

# RL78/L12

### **RENESAS MCU**

R01DS0157EJ0221 Rev.2.21 Feb 01, 2023

True low-power platform (62.5 μA/MHz, and 0.64 μA for operation with only RTC and LVD) for the LCD-based applications, with the on-chip LCD controller and driver, 8- to 32-Kbyte code flash memory, 1.6-V to 5.5-V operation, and 31 DMIPS at 24 MHz

## 1. OUTLINE

### 1.1 Features

## **Ultra-Low Power Technology**

- 1.6 V to 5.5 V operation from a single supply
- Stop (RAM retained): 0.23 μA, (LVD enabled): 0.31 μA
- Halt (RTC + LVD): 0.64 μA
- Supports snooze
- Operating: 62.5 μA/MHz
- LCD operating current (Capacitor split method): 0.12 μA
- LCD operating current (Internal voltage boost method):
   0.63 µA (VDD = 3.0 V)

### 16-bit RL78 CPU Core

- Delivers 31 DMIPS at maximum operating frequency of 24 MHz
- Instruction Execution: 86% of instructions can be executed in 1 to 2 clock cycles
- CISC Architecture (Harvard) with 3-stage pipeline
- Multiply Signed & Unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

#### **Code Flash Memory**

- Density: 8 KB to 32 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing
- Self-programming with flash shield window function

### **Data Flash Memory**

- Data flash with background operation
- Data flash size: 2 KB size
- Erase cycles: 1 Million (typ.)
- Erase/programming voltage: 1.8 V to 5.5 V

### RAM

- 1 KB and 1.5 KB size options
- Supports operands or instructions
- Back-up retention in all modes

### **High-speed On-chip Oscillator**

- 24 MHz with +/- 1% accuracy over voltage (1.8 V to 5.5 V) and temperature (-20°C to 85°C)
- Pre-configured settings: 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz & 1 MHz

# **Reset and Supply Management**

- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 14 setting options (Interrupt and/or reset function)

#### LCD Controller/Driver

- Up to 35 seg x 8 com or 39 seg x 4 com
- Supports capacitor split method, internal voltage boost method and resistance division method
- Supports waveform types A and B
- Supports LCD contrast adjustment (16 steps)
- Supports LCD blinking

### **Direct Memory Access (DMA) Controller**

- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

### **Multiple Communication Interfaces**

- Up to 1 × I<sup>2</sup>C multi-master
- Up to 2 × Simplified SPI (CSINote1) (7-, 8-bit)
- Up to 1 × UART (7-, 8-, 9-bit)
- $\bullet$  Up to  $1 \times LIN$

### **Extended-Function Timers**

- Multi-function 16-bit timers: Up to 8 channels
- Real-time clock (RTC): 1 channel (full calendar and alarm function with watch correction function)
- Interval Timer: 12-bit, 1 channel
- 15 kHz watchdog timer: 1 channel (window function)

### **Rich Analog**

- ullet ADC: Up to 10 channels, 10-bit resolution, 2.1  $\mu s$  conversion time
- Supports 1.6 V
- Internal reference voltage (1.45 V)
- On-chip temperature sensor

### Safety Features (IEC or UL 60730 compliance)

- Flash memory CRC calculation
- · RAM parity error check
- RAM write protection
- SFR write protection
- · Illegal memory access detection
- Clock frequency detection
- ADC self-test

### General Purpose I/O

- 5V tolerant, high-current (up to 20 mA per pin)
- Open-Drain, Internal Pull-up support

# **Operating Ambient Temperature**

- T<sub>A</sub>: -40 °C to +85 °C (A: Consumer applications)
- T<sub>A</sub>: -40 °C to +105 °C (G: Industrial applications)

## Package Type and Pin Count

From 7mm x 7mm to 12mm x 12mm QFP: 32, 44, 48, 52, 64

**Notes 1.** Although the CSI function is generally called SPI, it is also called CSI in this product, so it is referred to as such in this manual.

O ROM, RAM capacities

Flash ROM	Data flash	RAM			RL78/L12		
			32 pins	44 pins	48 pins	52 pins	64 pins
32 KB	2 KB	1.5 KB <sup>Note</sup>	R5F10RBC	R5F10RFC	R5F10RGC	R5F10RJC	R5F10RLC
16 KB	2 KB	1 KB <sup>Note</sup>	R5F10RBA	R5F10RFA	R5F10RGA	R5F10RJA	R5F10RLA
8KB	2 KB	1 KB <sup>Note</sup>	R5F10RB8	R5F10RF8	R5F10RG8	R5F10RJ8	-

Note In the case of the 1 KB, and 1.5 KB, this is 630 bytes when the self-programming function and data flash function is used.

Remark The functions mounted depend on the product. See 1.6 Outline of Functions.

## 1.2 List of Part Numbers

Figure 1-1. Part Number, Memory Size, and Package of RL78/L12
Part Number

Ordering Part Number R5F10RLCAxxxFB#10 Packaging specification: #U0, #00, #20 : Tray (HWQFN) #V0, #10, #30 : Tray (LFQFP, LQFP) #W0, #40 : Embossed Tape (HWQFN) #X0, #50 : Embossed Tape (LFQFP, LQFP) Package type: FP: LQFP, 0.80 mm pitch FA: LQFP, 0.65 mm pitch FB: LFQFP, 0.50 mm pitch NB: HWQFN, 0.40 mm pitch ROM number (Omitted with blank products) Fields of application: A : Consumer applications,  $T_A = -40$ °C to 85°C G : Industrial applications,  $T_A = -40$ °C to 105°C ROM capacity: 8 : 8 KB A : 16 KB C: 32 KB Pin count: B: 32-pin F 44-pin G: 48-pin J : 52-pin L : 64-pin RL78/L12 group Memory type: F: Flash memory Renesas MCU Renesas semiconductor product

Table 1-1. List of Ordering Part Numbers

(1/2)

Pin			Fields of	Ordering Part Number		
count	Package	Data flash	Application Note	Product Name	Packaging Specifications	RENESAS Code
32 pins		Mounted	Α	R5F10RB8AFP, R5F10RBAAFP, R5F10RBCAFP	#V0, #X0, #30	PLQP0032GB-A
	LQFP (7 × 7 mm,				#10, #50	PLQP0032GB-A PLQP0032GE-A
	0.8mm pitch)		G	R5F10RB8GFP, R5F10RBAGFP, R5F10RBCGFP	#V0, #X0, #30	PLQP0032GB-A
					#10, #50	PLQP0032GB-A PLQP0032GE-A
44 pins		Mounted	Α	R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP	#V0, #X0	PLQP0044GC-A
	LQFP (10 × 10 mm,				#10, #50	PLQP0044GC-A PLQP0044GC-D PLQP0044GE-A
	0.8mm pitch)				#30	PLQP0044GC-A PLQP0044GC-D
			G	R5F10RF8GFP, R5F10RFAGFP, R5F10RFCGFP	#V0, #X0	PLQP0044GC-A
					#10, #50	PLQP0044GC-A PLQP0044GC-D PLQP0044GE-A
					#30	PLQP0044GC-A PLQP0044GC-D
48 pins	48-pin plastic	Mounted	Α	R5F10RG8AFB, R5F10RGAAFB, R5F10RGCAFB	#V0, #X0	PLQP0048KF-A
	LFQFP (7 × 7 mm,				#10, #50	PLQP0048KB-B PLQP0048KL-A
	0.5mm pitch)				#30	PLQP0048KB-B
			G	R5F10RG8GFB, R5F10RGAGFB, R5F10RGCGFB	#V0, #X0	PLQP0048KF-A
					#10, #50	PLQP0048KB-B PLQP0048KL-A
					#30	PLQP0048KB-B
52 pins	52-pin plastic	Mounted	Α	R5F10RJ8AFA, R5F10RJAAFA, R5F10RJCAFA	#V0, #X0	PLQP0052JA-A
	LQFP (10 × 10				#10, #30, #50	PLQP0052JA-A PLQP0052JD-B
	mm, 0.65mm		G	R5F10RJ8GFA, R5F10RJAGFA, R5F10RJCGFA	#V0, #X0	PLQP0052JA-A
	pitch)				#10, #30, #50	PLQP0052JA-A PLQP0052JD-B

Note For the fields of application, refer to Figure 1-1 Part Number, Memory Size, and Package of RL78/L12.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

<R>

Table 1-1. List of Ordering Part Numbers

(2/2)

			Fields of	Ordering Part Number		
Pin count	Package	Data flash	Application	Product Name	Packaging Specifications	RENESAS Code
64 pins	64-pin plastic	Mounted	Α	R5F10RLAANB, R5F10RLCANB	#U0, #W0	PWQN0064LA-A
	HWQFN				#00, #20, #40	PWQN0064LB-A
	(8 × 8 mm, 0.4mm pitch)		G	R5F10RLAGNB, R5F10RLCGNB	#U0, #W0	PWQN0064LA-A
	,				#00, #20, #40	PWQN0064LB-A
	64-pin plastic	Mounted	Α	R5F10RLAAFB, R5F10RLCAFB	#V0, #X0	PLQP0064KF-A
	LFQFP (10 × 10 mm,				#10, #50	PLQP0064KB-C PLQP0064KL-A
	0.5mm pitch)				#30	PLQP0064KB-C
			G	R5F10RLAGFB, R5F10RLCGFB	#V0, #X0	PLQP0064KF-A
					#10, #50	PLQP0064KB-C PLQP0064KL-A
					#30	PLQP0064KB-C
	64-pin plastic	Mounted	Α	R5F10RLAAFA, R5F10RLCAFA	#V0, #X0	PLQP0064JA-A
	LQFP (12 × 12 mm,				#10, #30, #50	PLQP0064JA-A PLQP0064JB-A
	0.65mm pitch)		G	R5F10RLAGFA, R5F10RLCGFA	#V0, #X0	PLQP0064JA-A
					#10, #30, #50	PLQP0064JA-A PLQP0064JB-A

Note For the fields of application, refer to Figure 1-1 Part Number, Memory Size, and Package of RL78/L12.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

# 1.3 Pin Configuration (Top View)

# 1.3.1 32-pin products

<R>

<R>

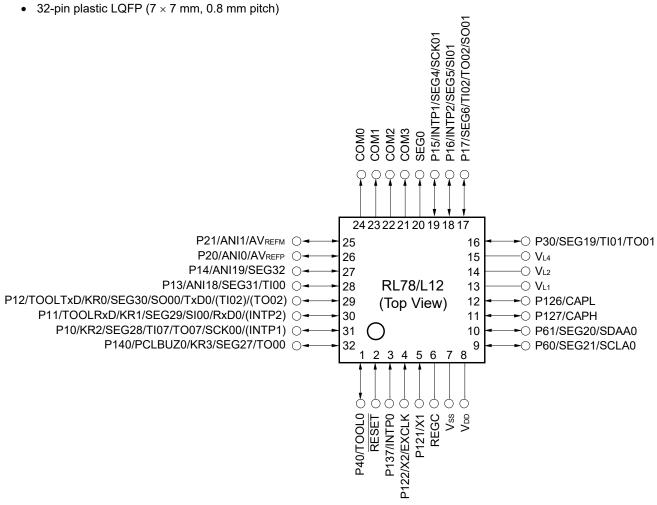


Table 1-2. Alternate function of 32-pin products

(1/2)

Pin No.	I/O	debug	Analog	НМІ			Timer		Communications Interface	
32LQFP	Digital port	Power supply, system, clock, d	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P40	TOOL0								
2		RESET								
3	P137			INTP0						
4	P122	X2/EXCLK								

<R>

Table 1-2. Alternate function of 32-pin products

(2/2)

Pin No.	I/O	- Bnqa	Analog	НМІ			Timer		Communications	Interface
32LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
5	P121	X1								
6		REGC								
7		V <sub>SS</sub>								
8		$V_{DD}$								
9	P60					SEG21				SCLA0
10	P61					SEG20				SDAA0
11	P127					CAPH				
12	P126					CAPL				
13						V <sub>L1</sub>				
14						$V_{L2}$				
15						$V_{L4}$				
16	P30					SEG19	TI01/TO01			
17	P17					SEG6	TI02/TO02		SO01	
18	P16			INTP2		SEG5			SI01	
19	P15			INTP1		SEG4			SCK01	
20						SEG0				
21						СОМЗ				
22						COM2				
23						COM1				
24						СОМО				
25	P21		ANI1/AV <sub>REFM</sub>							
26	P20		ANI0/AV <sub>REFP</sub>							
27	P14		ANI19			SEG32				
28	P13		ANI18			SEG31	TI00			
29	P12	TOOLTxD			KR0	SEG30	(TI02)/(TO02)		SO00/TxD0	
30	P11	TOOLRxD		(INTP2)	KR1	SEG29			SI00/RxD0	
31	P10			(INTP1)	KR2	SEG28	TI07/TO07		SCK00	
32	P140	PCLBUZ0			KR3	SEG27	TO00		_	

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

**2.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.3.2 44-pin products



<R>

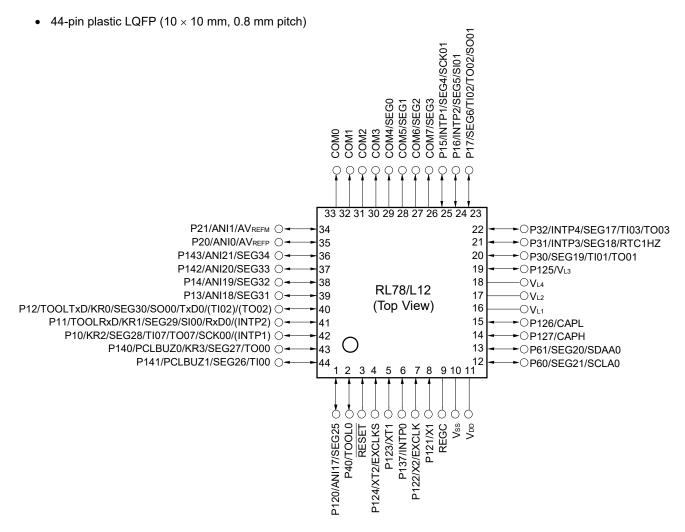


Table 1-3. Alternate function of 44-pin products

(1/3)

Pin No.	I/O	gndeb	Analog	НМІ		Timer		Communications Interface		
44LQFP	Digital port	Power supply, system, clock, o	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				
2	P40	TOOL0								
3		RESET								
4	P124	XT2/EXCLKS								
5	P123	XT1								

<R>

Table 1-3. Alternate function of 44-pin products

(2/3)

Pin No.	I/O	epnd	Analog	НМІ			Timer		Communicat Interface	tions
44LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
6	P137			INTP0						
7	P122	X2/EXCLK								
8	P121	X1								
9		REGC								
10		V <sub>SS</sub>								
11		V <sub>DD</sub>								
12	P60					SEG21				SCLA0
13	P61					SEG20				SDAA0
14	P127					САРН				
15	P126					CAPL				
16						V <sub>L1</sub>				
17						V <sub>L2</sub>				
18						V <sub>L4</sub>				
19	P125					V <sub>L3</sub>				
20	P30					SEG19	TI01/TO01			
21	P31			INTP3		SEG18		RTC1HZ		
22	P32			INTP4		SEG17	TI03/TO03			
23	P17					SEG6	TI02/TO02		SO01	
24	P16			INTP2		SEG5			SI01	
25	P15			INTP1		SEG4			SCK01	
26						COM7/SEG3				
27						COM6/SEG2				
28						COM5/SEG1				
29						COM4/SEG0				
30						СОМЗ				
31						COM2				
32						COM1				
33						СОМО				

<R>

			Table 1-3	. Alterna	te func	tion of 44-pin	products		(3/3)		
Pin No.	I/O	bnge	Analog	НМІ			Timer		Communicati Interface	ions	
44LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA	
34	P21		ANI1/AV <sub>REFM</sub>								
35	P20		ANI0/AV <sub>REFP</sub>								
36	P143		ANI21			SEG34					
37	P142		ANI20			SEG33					
38	P14		ANI19			SEG32					
39	P13		ANI18			SEG31					
40	P12	TOOLTxD			KR0	SEG30	(TI02)/(TO02)		SO00/TxD0		
41	P11	TOOLRxD		(INTP2)	KR1	SEG29			SI00/RxD0		
42	P10			(INTP1)	KR2	SEG28	TI07/TO07		SCK00		
43	P140	PCLBUZ0			KR3	SEG27	TO00				
44	P141	PCLBUZ1				SEG26	TI00				

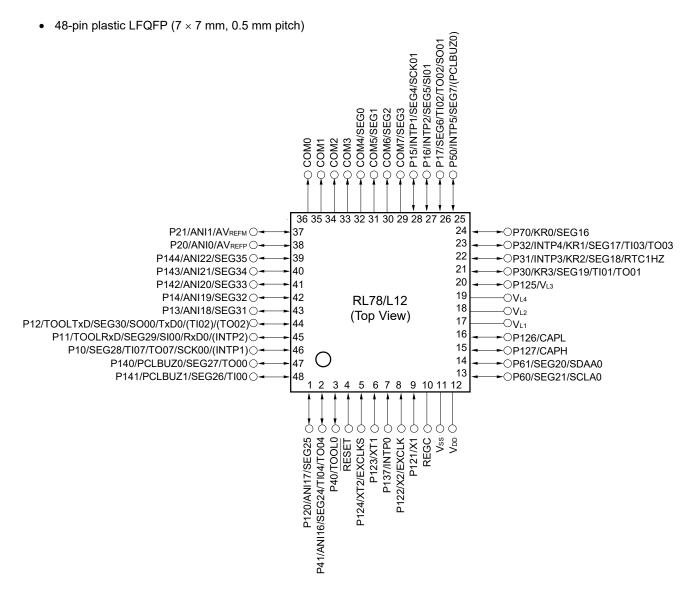
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.3.3 48-pin products





<R>

Table 1-4. Alternate function of 48-pin products

(1/3)

Pin No.	I/O	, debug	Analog	HMI		Timer		Communications Interface		
48LFQFP	Digital port	Power supply, system, clock,	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				
2	P41		ANI16			SEG24	TI04/TO04			
3	P40	TOOL0								

<R>

Table 1-4. Alternate function of 48-pin products

(2/3)

Pin No.	I/O	, debug	Analog	НМІ			Timer		Communications Interface	
48LFQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
4		RESET								
5	P124	XT2/EXCLKS								
6	P123	XT1								
7	P137			INTP0						
8	P122	X2/EXCLK								
9	P121	X1								
10		REGC								
11		V <sub>SS</sub>								
12		V <sub>DD</sub>								
13	P60					SEG21				SCLA0
14	P61					SEG20				SDAA0
15	P127					CAPH				
16	P126					CAPL				
17						V <sub>L1</sub>				
18						V <sub>L2</sub>				
19						V <sub>L4</sub>				
20	P125					V <sub>L3</sub>				
21	P30				KR3	SEG19	TI01/TO01			
22	P31			INTP3	KR2	SEG18		RTC1HZ		
23	P32			INTP4	KR1	SEG17	TI03/TO03			
24	P70				KR0	SEG16				
25	P50	(PCLBUZ0)		INTP5		SEG7				
26	P17					SEG6	TI02/TO02		SO01	
27	P16			INTP2		SEG5			SI01	
28	P15			INTP1		SEG4			SCK01	
29						COM7/SEG3				
30						COM6/SEG2				
31						COM5/SEG1				
32						COM4/SEG0				

<R>

Table 1-4. Alternate function of 48-pin products

(3/3)

Pin No.	I/O	бn.	Analog	НМІ			Timer		Communications Interface	
48LFQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
33						СОМ3				
34						COM2				
35						COM1				
36						СОМ0				
37	P21		ANI1/AV <sub>REFM</sub>							
38	P20		ANI0/AV <sub>REFP</sub>							
39	P144		ANI22			SEG35				
40	P143		ANI21			SEG34				
41	P142		ANI20			SEG33				
42	P14		ANI19			SEG32				
43	P13		ANI18			SEG31				
44	P12	TOOLTxD				SEG30	(TI02)/(TO02)		SO00/TxD0	
45	P11	TOOLRxD		(INTP2)		SEG29			SI00/RxD0	
46	P10			(INTP1)		SEG28	TI07/TO07		SCK00	
47	P140	PCLBUZ0				SEG27	TO00			
48	P141	PCLBUZ1				SEG26	TI00			

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.3.4 52-pin products

• 52-pin plastic LQFP (10 × 10 mm, 0.65 mm pitch)



<R>

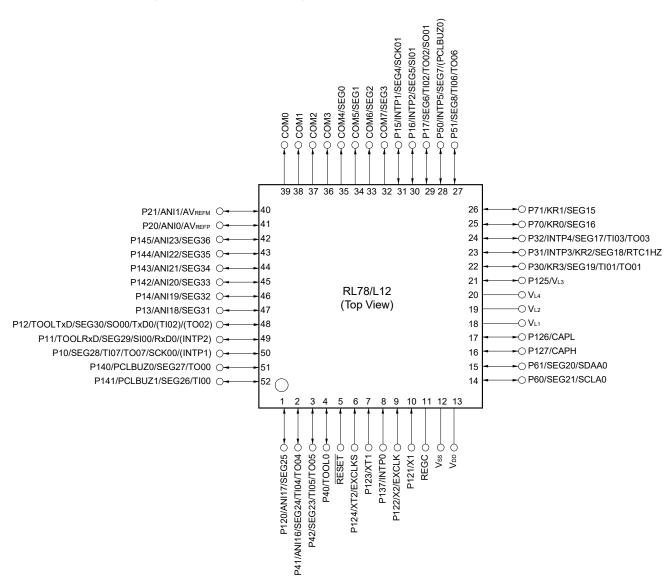


Table 1-5. Alternate function of 52-pin products

(1/3)

Pin No.	I/O	depnd	Analog	НМІ			Timer		Communications Interface	
52LQFP	Digital port	Power supply, system, clock, d	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				_
2	P41		ANI16			SEG24	TI04/TO04			

<R>

# Table 1-5. Alternate function of 52-pin products

(2/3)

Pin No.	I/O	<b>Bnq</b> e	Analog	НМІ			Timer		Communications Interface	;
52LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
3	P42					SEG23	TI05/TO05			
4	P40	TOOL0								
5		RESET								
6	P124	XT2/EXCLKS								
7	P123	XT1								
8	P137			INTP0						
9	P122	X2/EXCLK								
10	P121	X1								
11		REGC								
12		V <sub>SS</sub>								
13		$V_{DD}$								
14	P60					SEG21				SCLA0
15	P61					SEG20				SDAA0
16	P127					САРН				
17	P126					CAPL				
18						V <sub>L1</sub>				
19						$V_{L2}$				
20						V <sub>L4</sub>				
21	P125					V <sub>L3</sub>				
22	P30				KR3	SEG19	TI01/TO01			
23	P31			INTP3	KR2	SEG18		RTC1HZ		
24	P32			INTP4		SEG17	TI03/TO03			
25	P70				KR0	SEG16				
26	P71				KR1	SEG15				
27	P51					SEG8	TI06/TO06			
28	P50	(PCLBUZ0)		INTP5		SEG7				
29	P17					SEG6	TI02/TO02		SO01	
30	P16			INTP2		SEG5			SI01	

<R>

Table 1-5. Alternate function of 52-pin products

(3/3)

Pin No.	I/O	<b>Bnqa</b>	Analog	НМІ			Timer		Communications Interface	
52LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
31	P15			INTP1		SEG4			SCK01	
32						COM7/SEG3				
33						COM6/SEG2				
34						COM5/SEG1				
35						COM4/SEG0				
36						СОМЗ				
37						COM2				
38						COM1				
39						СОМ0				
40	P21		ANI1/AV <sub>REFM</sub>							
41	P20		ANI0/AV <sub>REFP</sub>							
42	P145		ANI23			SEG36				
43	P144		ANI22			SEG35				
44	P143		ANI21			SEG34				
45	P142		ANI20			SEG33				
46	P14		ANI19			SEG32				
47	P13		ANI18			SEG31				
48	P12	TOOLTxD				SEG30	(TI02)/(TO02)		SO00/TxD0	
49	P11	TOOLRxD		(INTP2)		SEG29			SI00/RxD0	
50	P10			(INTP1)		SEG28	TI07/TO07		SCK00	
51	P140	PCLBUZ0				SEG27	TO00			
52	P141	PCLBUZ1				SEG26	TI00			

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

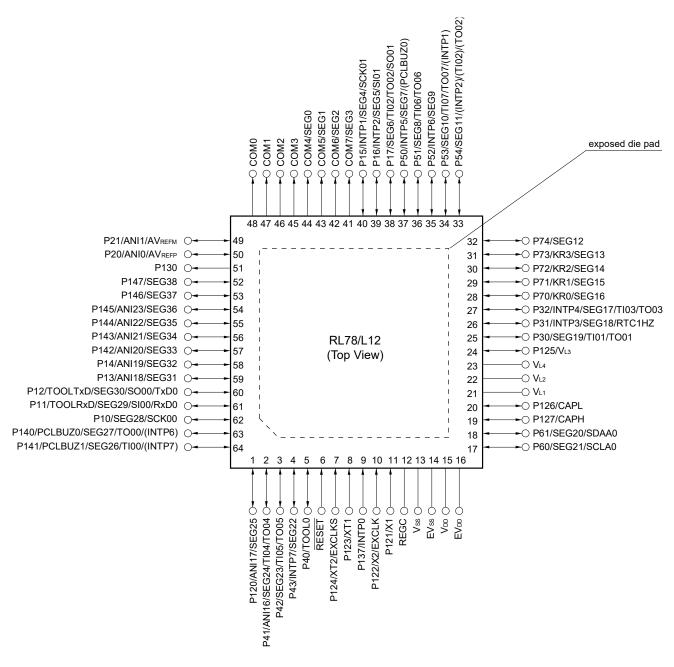
Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.3.5 64-pin products

• 64-pin plastic HWQFN (8 × 8 mm, 0.4 mm pitch)

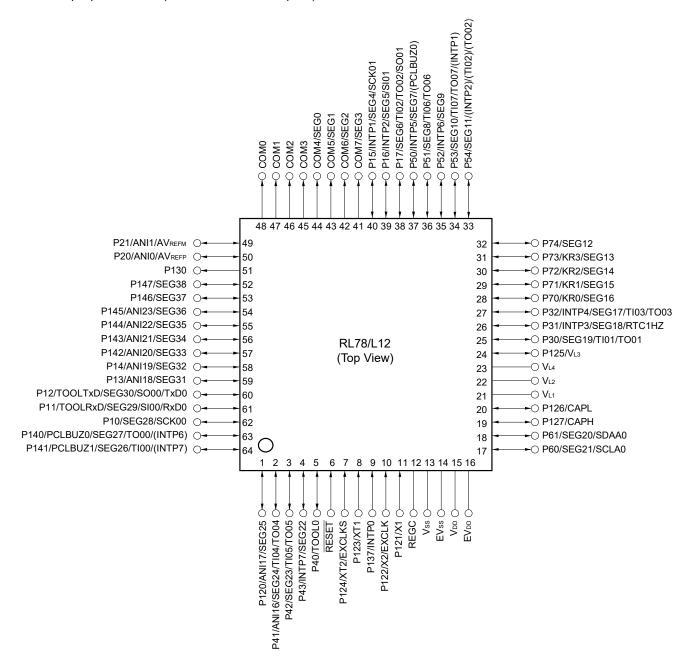
<R>



<R>

- 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch)
- 64-pin plastic LQFP (12 × 12 mm, 0.65 mm pitch)

<R>



<R>

Table 1-6. Alternate function of 64-pin products

(1/3)

Pin No.	I/O		Analog	НМІ			Timer		Communications I	nterface
64HWQFN, 64LFQFP, 64LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				
2	P41		ANI16			SEG24	TI04/TO04			
3	P42					SEG23	TI05/TO05			
4	P43			INTP7		SEG22				
5	P40	TOOL0								
6		RESET								
7	P124	XT2/EXCLKS								
8	P123	XT1								
9	P137			INTP0						
10	P122	X2/EXCLK								
11	P121	X1								
12		REGC								
13		V <sub>SS</sub>								
14		EV <sub>SS</sub>								
15		$V_{DD}$								
16		EV <sub>DD</sub>								
17	P60					SEG21				SCLA0
18	P61					SEG20				SDAA0
19	P127					CAPH				
20	P126					CAPL				
21						V <sub>L1</sub>				
22						V <sub>L2</sub>				
23						V <sub>L4</sub>				
24	P125					V <sub>L3</sub>				
25	P30					SEG19	TI01/TO01			
26	P31			INTP3		SEG18		RTC1HZ		
27	P32			INTP4		SEG17	TI03/TO03			
28	P70				KR0	SEG16				

<R>

Table 1-6. Alternate function of 64-pin products

(2/3)

Pin No.	I/O		Analog	НМІ			Timer		Communications I	nterface
64HWQFN, 64LFQFP, 64LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
29	P71				KR1	SEG15				
30	P72				KR2	SEG14				
31	P73				KR3	SEG13				
32	P74					SEG12				
33	P54			(INTP2)		SEG11	(TI02)/(TO02)			
34	P53			(INTP1)		SEG10	TI07/TO07			
35	P52			INTP6		SEG9				
36	P51					SEG8	TI06/TO06			
37	P50	(PCLBUZ0)		INTP5		SEG7				
38	P17					SEG6	TI02/TO02		SO01	
39	P16			INTP2		SEG5			SI01	
40	P15			INTP1		SEG4			SCK01	
41						COM7/SEG3				
42						COM6/SEG2				
43						COM5/SEG1				
44						COM4/SEG0				
45						СОМЗ				
46						COM2				
47						COM1				
48						СОМО				
49	P21		ANI1/AV <sub>REFM</sub>							
50	P20		ANI0/AV <sub>REFP</sub>							
51	P130									
52	P147					SEG38				
53	P146					SEG37				
54	P145		ANI23			SEG36				
55	P144		ANI22			SEG35				
56	P143		ANI21			SEG34				

<R>

Table 1-6. Alternate function of 64-pin products

(3/3)

Pin No.	I/O	_	Analog	НМІ			Timer		Communications I	nterface
64HWQFN, 64LFQFP, 64LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
57	P142		ANI20			SEG33				
58	P14		ANI19			SEG32				
59	P13		ANI18			SEG31				
60	P12	TOOLTxD				SEG30			SO00/TxD0	
61	P11	TOOLRxD				SEG29			SI00/RxD0	
62	P10					SEG28			SCK00	
63	P140	PCLBUZ0		(INTP6)		SEG27	TO00			
64	P141	PCLBUZ1		(INTP7)		SEG26	TI00			

- Cautions 1. Make EVss pin the same potential as Vss pin.
  - 2. Make VDD pin the same potential as EVDD pin.
  - 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).
- Remarks 1. For pin identification, see 1.4 Pin Identification.
  - 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V<sub>DD</sub> and EV<sub>DD</sub> pins and connect the V<sub>SS</sub> and EV<sub>SS</sub> pins to separate ground lines.
  - **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

## 1.4 Pin Identification

P20, P21:

P30 to P32:

P40 to P43:

P50 to P54:

Port 2

Port 3

Port 4

Port 5

<R>

ANI0, ANI1,		P130, P137:	Port 13
ANI16 to ANI23:	Analog Input	P140 to P147:	Port 14
AVREFM:	Analog Reference	PCLBUZ0, PCLBUZ1:	Programmable Clock
	Voltage Minus		Output/Buzzer Output
AVREFP:	Analog Reference	REGC:	Regulator Capacitance
	Voltage Plus	RESET:	Reset
CAPH, CAPL:	Capacitor for LCD	RTC1HZ:	Real-time Clock Correction Clock
COM0 to COM7,			(1 Hz) Output
EV <sub>DD</sub> :	Power Supply for Port	RxD0:	Receive Data
EVss:	Ground for Port	SCK00, SCK01,	
EXCLK:	External Clock Input	SCLA0:	Serial Clock Input/Output
	(Main System Clock)	SDAA0:	Serial Data Input/Output
EXCLKS:	External Clock Input	SEG0 to SEG38:	LCD Segment Output
	(Subsystem Clock)	SI00, SI01:	Serial Data Input
INTP0 to INTP7:	Interrupt Request From	SO00, SO01:	Serial Data Output
	Peripheral	TI00 to TI07:	Timer Input
KR0 to KR3:	Key Return	TO00 to TO07:	Timer Output
P10 to P17:	Port 1	TOOL0:	Data Input/Output for Tool

P60, P61:Port 6Vss:GroundP70 to P74:Port 7X1, X2:Crystal Oscillator (Main System Clock)P120 to P127:Port 12XT1, XT2:Crystal Oscillator (Subsystem Clock)

V<sub>L1</sub> to V<sub>L4</sub>:

TxD0:

V<sub>DD</sub>:

TOOLRxD, TOOLTxD:

Data Input/Output for External Device

Transmit Data

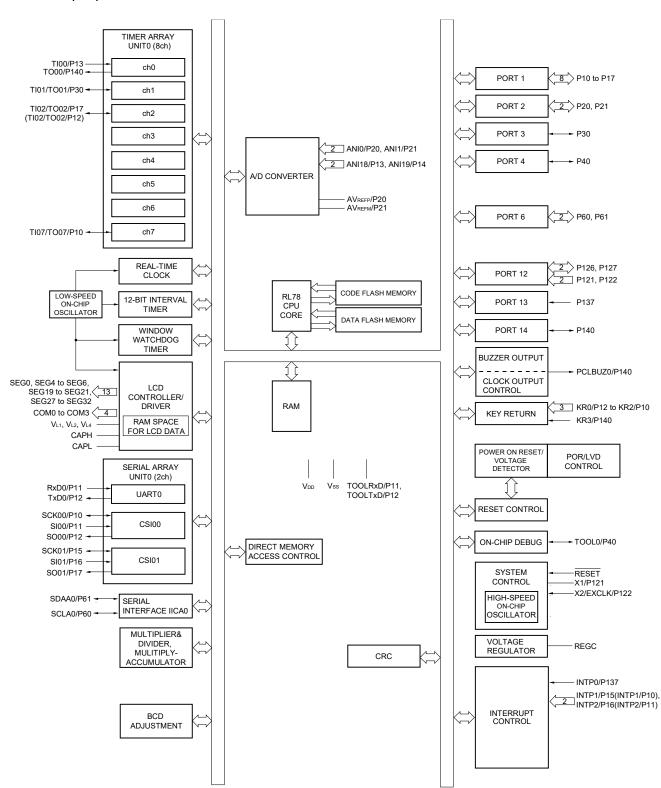
Power Supply

LCD Power Supply

# 1.5 Block Diagram

## 1.5.1 32-pin products

<R>

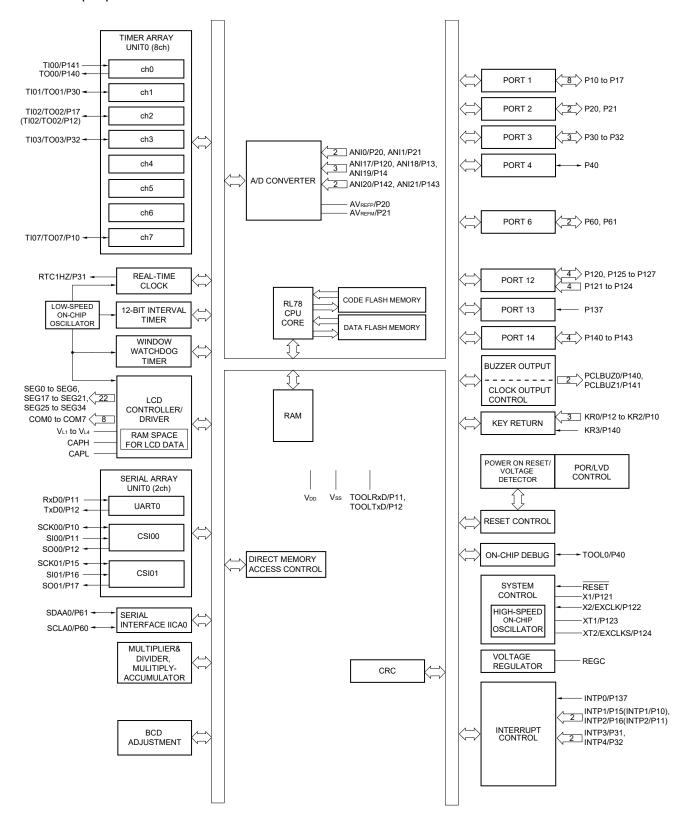


**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



# 1.5.2 44-pin products

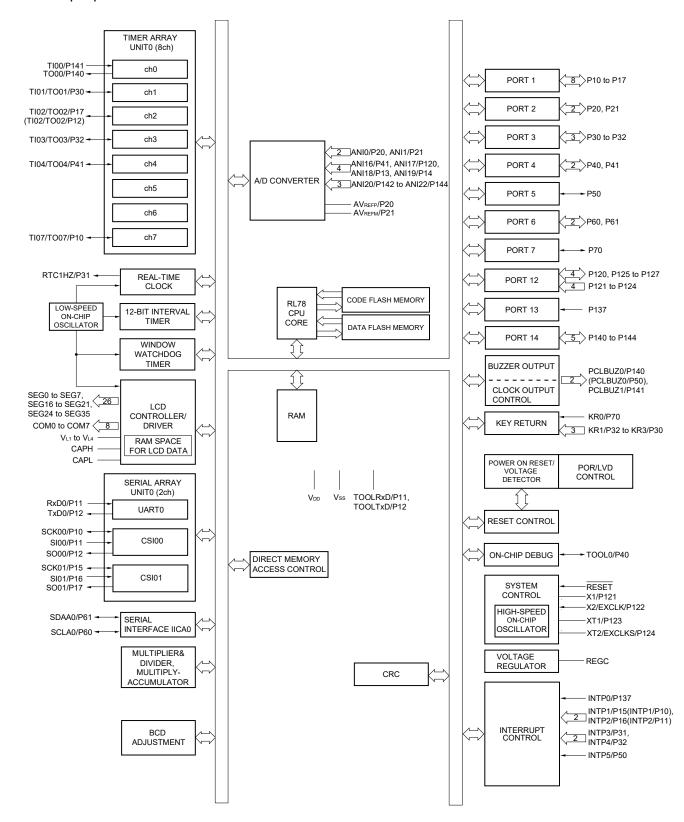




**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.5.3 48-pin products

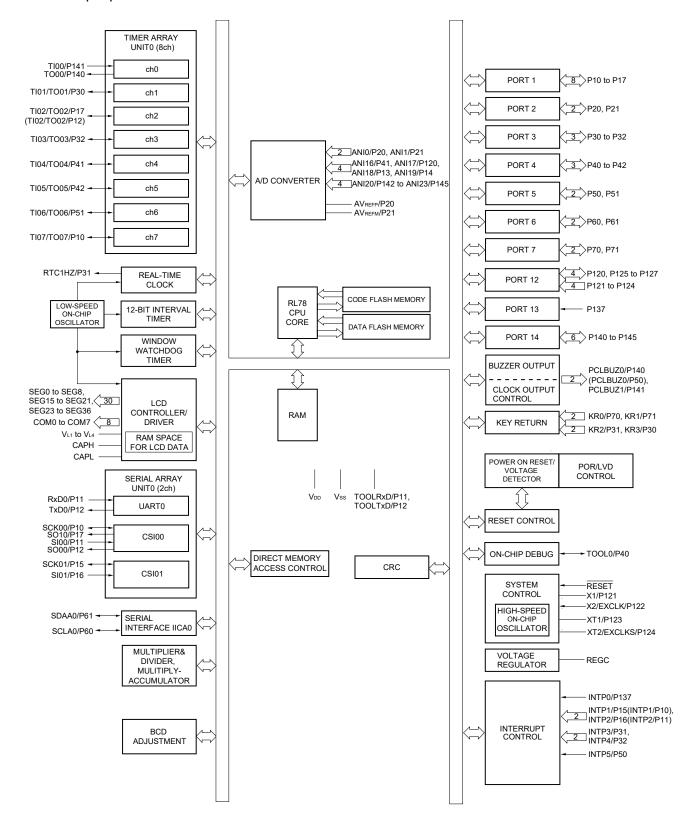




**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.5.4 52-pin products

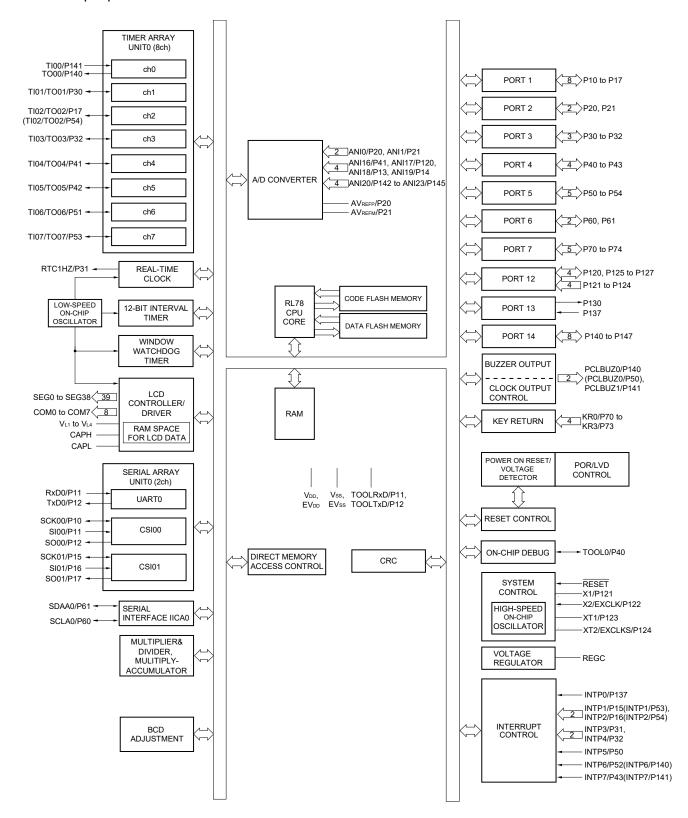




**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

# 1.5.5 64-pin products





**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

## 1.6 Outline of Functions

Caution This outline describes the functions at the time when Peripheral I/O redirection register (PIOR) is set to 00H.

(1/2)Item 32-pin 44-pin 48-pin 52-pin 64-pin R5F10RBx R5F10RFx R5F10RGx R5F10RJx R5F10RLx Code flash memory (KB) 8 to 32 8 to 32 8 to 32 8 to 32 16, 32 Data flash memory (KB) 2 2 2 2 2 1, 1.5 Note 1 1. 1.5 Note 1 1. 1.5 Note 1 1. 1.5 Note 1 1. 1.5<sup>Note 1</sup> RAM (KB) 1 MB Memory space X1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) Main High-speed system clock system HS (high-speed main) operation: 1 to 20 MHz ( $V_{DD}$  = 2.7 to 5.5 V), clock HS (high-speed main) operation: 1 to 16 MHz ( $V_{DD}$  = 2.4 to 5.5 V), LS (low-speed main) operation: 1 to 8 MHz (VDD = 1.8 to 5.5 V), LV (low-voltage main) operation: 1 to 4 MHz (VDD = 1.6 to 5.5 V) High-speed on-chip HS (high-speed main) operation: 1 to 24 MHz (VDD = 2.7 to 5.5 V), oscillator clock HS (high-speed main) operation: 1 to 16 MHz ( $V_{DD}$  = 2.4 to 5.5 V), LS (low-speed main) operation: 1 to 8 MHz ( $V_{DD} = 1.8$  to 5.5 V), LV (low-voltage main) operation: 1 to 4 MHz (VDD = 1.6 to 5.5 V) Subsystem clock XT1 (crystal) oscillation, external subsystem clock input (EXCLKS) 32.768 kHz (TYP.): VDD = 1.6 to 5.5 V Low-speed on-chip oscillator clock Internal oscillation 15 kHz (TYP.): VDD = 1.6 to 5.5 V 8 bits  $\times$  32 registers (8 bits  $\times$  8 registers  $\times$  4 banks) General-purpose register Minimum instruction execution time 0.04167  $\mu$ s (High-speed on-chip oscillator clock: fin = 24 MHz operation)  $0.05 \mu s$  (High-speed system clock:  $f_{MX} = 20 \text{ MHz operation}$ ) 30.5  $\mu$ s (Subsystem clock: fsub = 32.768 kHz operation) Instruction set • Data transfer (8/16 bits) • Adder and subtractor/logical operation (8/16 bits) • Multiplication (8 bits × 8 bits) • Rotate, barrel shift, and bit manipulation (Set, reset, test, and Boolean operation), etc Total number of I/O port pins and 28 40 44 48 58 pins dedicated to drive an LCD I/O Total 20 33 37 47 29 port CMOS I/O 15 22 26 30 39 CMOS input 3 5 5 5 5 CMOS output 1 2 2 2 2 N-ch open-drain I/O 2 (EV<sub>DD</sub> tolerance) Pins dedicated to drive an LCD 8 11 LCD controller/driver Internal voltage boosting method, capacitor split method, and external resistance division method are switchable 22 (18) Note 2 26 (22) Note 2 39 (35) Note 2 30 (26) Note 2 13 Segment signal output 4 (8) Note 2 Common signal output 4

**Notes 1.** In the case of the 1 KB, and 1.5 KB, this is 630 bytes when the self-programming function and data flash function is used.

2. The values in parentheses are the number of signal outputs when 8 com is used.

(2/2)

						(2/2			
	Item	32-pin	44-pin	48-pin	52-pin	64-pin			
		R5F10RBx	R5F10RFx	R5F10RGx	R5F10RJx	R5F10RLx			
Timer	16-bit timer	8 channels	8 channels	(with 1 channel r	remote control ou	tput function)			
,	Watchdog timer			1 channel					
1	Real-time clock (RTC)			1 channel					
	12-bit interval timer (IT)			1 channel					
	Timer output	4 channels (PWM outputs: 3 Note 1)	5 channels (PWM outputs: 4 Note 1)	6 channels (PWM outputs: 5 Note 1)	8 channels (PWN	∕l outputs: 7 <sup>Note 1</sup>			
1	RTC output	_	- 1  • 1 Hz (subsystem clock: fsub = 32.768 kHz)						
Clock output/b	uzzer output	1			2				
		(Main system • 256 Hz, 512 32.768 kHz	n clock: f <sub>MAIN</sub> = 20	MHz operation) .048 kHz, 4.096	kHz, 8.192 kHz,				
8/10-bit resolu	tion A/D converter	4 channels	7 channels	9 channels	10 channels	10 channels			
Serial interface	е	Simplified SPI (CSI): 2 channel/UART (LIN-bus supported): 1 channel							
I <sup>2</sup> C bus		1 channel 1 channel 1 channel 1 channel							
Multiplier and accumulator	divider/multiply-	<ul> <li>16 bits × 16 bits = 32 bits (Unsigned or signed)</li> <li>32 bits ÷ 32 bits = 32 bits (Unsigned)</li> <li>16 bits × 16 bits + 32 bits = 32 bits (Unsigned or signed)</li> </ul>							
DMA controlle	r	2 channels							
Vectored inter	rupt Internal	23	23	23	23	23			
sources	External	4	6	7	7	9			
Key interrupt	1		·	4					
Reset		<ul><li>Internal reset</li><li>Internal reset</li><li>Internal reset</li><li>Internal reset</li></ul>	SET pin by watchdog tim by power-on-res by voltage detec by illegal instruc by RAM parity e by illegal-memo	set ctor tion execution <sup>No</sup> rror	ote 2				
Power-on-rese	et circuit	Power-on-rese     Power-down-rese	et: 1.51 ±0.04 reset: 1.50 ±0.04						
Voltage detect	or	• Rising edge : 1.67 V to 4.06 V (14 stages) • Falling edge : 1.63 V to 3.98 V (14 stages)							
On-chip debug	function	Provided							
Power supply	voltage	V <sub>DD</sub> = 1.6 to 5.5	V						
Operating amb	pient temperature	T <sub>A</sub> = -40 to +85	5 °C						

**Notes 1.** The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves).

The illegal instruction is generated when instruction code FFH is executed.Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

# 2. ELECTRICAL SPECIFICATIONS (A, G: TA = -40 to +85°C)

This chapter describes the electrical specifications for the products "A: Consumer applications ( $T_A = -40$  to  $+85^{\circ}$ C)" and "G: Industrial applications (with  $T_A = -40$  to  $+85^{\circ}$ C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. With products not provided with an EV<sub>DD</sub>, or EVss pin, replace EV<sub>DD</sub> with V<sub>DD</sub>, or replace EVss with Vss.

# 2.1 Absolute Maximum Ratings

## Absolute Maximum Ratings (TA = 25°C)

(1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V <sub>DD</sub>	V <sub>DD</sub> = EV <sub>DD</sub>	-0.5 to +6.5	٧
	EV <sub>DD</sub>	V <sub>DD</sub> = EV <sub>DD</sub>	-0.5 to +6.5	V
	EVss		-0.5 to +0.3	٧
REGC pin input voltage	Virego	REGC	$-0.3 \text{ to } +2.8$ and $-0.3 \text{ to V}_{DD} + 0.3^{\text{Note 1}}$	٧
Input voltage	VI1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	-0.3 to EV <sub>DD</sub> +0.3 and $-0.3$ to V <sub>DD</sub> + $0.3$ <sup>Note 2</sup>	٧
	V <sub>12</sub>	P60, P61 (N-ch open-drain)	-0.3 to EV <sub>DD</sub> +0.3 and $-0.3$ to V <sub>DD</sub> + $0.3$ <sup>Note 2</sup>	٧
	Vı3	P20, P21, P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 2</sup>	٧
Output voltage	Vo <sub>1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	-0.3 to EV <sub>DD</sub> + $0.3$ and $-0.3$ to V <sub>DD</sub> + $0.3$ <sup>Note 2</sup>	<b>V</b>
	V <sub>O2</sub>	P20, P21	-0.3 to V <sub>DD</sub> + 0.3 Note 2	V
Analog input voltage	V <sub>Al1</sub>	ANI16 to ANI23	-0.3 to EV <sub>DD</sub> + 0.3 and -0.3 to AV <sub>REF</sub> (+) + 0.3 Notes 2, 3	V
	V <sub>Al2</sub>	ANIO, ANI1	-0.3 to V <sub>DD</sub> + 0.3 and -0.3 to AV <sub>REF</sub> (+) + 0.3 Notes 2, 3	٧

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
  - 2. Must be 6.5 V or lower.
  - **3.** Do not exceed  $AV_{REF(+)} + 0.3 V$  in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
  - **2.** AV<sub>REF(+)</sub>: + side reference voltage of the A/D converter.
  - 3. Vss: Reference voltage

## Absolute Maximum Ratings ( $T_A = 25^{\circ}C$ )

(2/3)

Parameter	Symbols		Conditions	Ratings	Unit
LCD voltage	V <sub>L1</sub>	V <sub>L1</sub> voltage <sup>Note 1</sup>		–0.3 to +2.8 and –0.3 to V <sub>L4</sub> + 0.3	٧
	V <sub>L2</sub>	V <sub>L2</sub> voltage <sup>Note 1</sup>		-0.3 to V <sub>L4</sub> + 0.3 Note 2	V
	V <sub>L3</sub>	V <sub>L3</sub> voltage <sup>Note 1</sup>		-0.3 to V <sub>L4</sub> + 0.3 Note 2	V
	V <sub>L4</sub>	V <sub>L4</sub> voltage <sup>Note 1</sup>		-0.3 to +6.5	V
	VLCAP	CAPL, CAPH vol	tage <sup>Note 1</sup>	$-0.3$ to $V_{L4} + 0.3^{\text{Note 2}}$	V
	VLOUT	COM0 to COM7, SEG0 to	External resistance division method	$-0.3$ to $V_{DD}$ + $0.3^{\text{Note 2}}$	٧
		SEG38,	Capacitor split method	-0.3 to V <sub>DD</sub> + 0.3 Note 2	
		output voltage	Internal voltage boosting method	-0.3 to V <sub>L4</sub> + 0.3 Note 2	

- Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the VL1, VL2, VL3, and V<sub>L4</sub> pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47  $\mu$  F  $\pm$  30%) and connect a capacitor (0.47  $\mu$  F  $\pm$  30%) between the CAPL and CAPH pins.
  - 2. Must be 6.5 V or lower.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Vss: Reference voltage

# Absolute Maximum Ratings (TA = 25°C)

(3/3)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147	-40	mA
		Total of all pins –170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	<del>-</del> 70	mA
			P15 to P17, P30 to P32, P50 to P54, P70 to P74, P125 to P127	-100	mA
	<b>І</b> он2	Per pin	P20, P21	-0.5	mA
		Total of all pins		-1	mA
Output current, low	lo <sub>L1</sub>	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	40	mA
		Total of all pins 170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	70	mA
			P15 to P17, P30 to P32, P50 to P54, P60, P61, P70 to P74, P125 to P127	100	mA
	lo <sub>L2</sub>	Per pin	P20, P21	1	mA
		Total of all pins		2	mA
Operating ambient	TA	In normal operati	ion mode	-40 to +85	°C
temperature		In flash memory	programming mode		
Storage temperature	T <sub>stg</sub>			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

## 2.2 Oscillator Characteristics

## 2.2.1 X1, XT1 oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation frequency (fx) <sup>Note</sup>	Ceramic resonator/ crystal resonator	$2.7~V \leq V_{DD} \leq 5.5~V$	1.0		20.0	MHz
		$2.4~V \leq V_{DD} \leq 2.7~V$	1.0		16.0	MHz
		$1.8~V \leq V_{DD} < 2.7~V$	1.0		8.0	MHz
		1.6 V ≤ V <sub>DD</sub> <1.8 V	1.0		4.0	MHz
XT1 clock oscillation frequency (fxt) <sup>Note</sup>	Crystal resonator		32	32.768	35	kHz

**Note** Indicates only permissible oscillator frequency ranges. Refer to **2.4 AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

# 2.2.2 On-chip oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency Notes 1, 2	fін			1		24	MHz
High-speed on-chip oscillator		−20 to +85°C	$1.8~V \leq V_{DD} \leq 5.5~V$	-1		+1	%
clock frequency accuracy			$1.6 \text{ V} \le \text{V}_{DD} \le 1.8 \text{ V}$	-5		+5	%
		-40 to −20°C	$1.8~V \leq V_{DD} \leq 5.5~V$	-1.5		+1.5	%
			$1.6 \text{ V} \le \text{V}_{DD} \le 1.8 \text{ V}$	-5.5		+5.5	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

**Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.

This indicates the oscillator characteristics only. Refer to 2.4 AC Characteristics for instruction execution time.

## 2.3 DC Characteristics

## 2.3.1 Pin characteristics

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

(1/5)

Items	Symbol		Conditions			TYP.	MAX.	Unit
Output current, high <sup>Note 1</sup>	Іон1	Per pin for P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147					-10.0 Note 2	mA
		Total of P10 to P14, P40 to P43, P120, P130, P140 to P147	$4.0~V \leq EV_{DD} \leq 5.5~V$			-40.0	mA	
			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}$			-8.0	mA	
		(When duty = 70% Note 3)		1.8 V ≤ EV <sub>DD</sub> < 2.7 V			-4.0	mA
				1.6 V ≤ EV <sub>DD</sub> < 1.8 V			-2.0	mA
		Total of P15 to P17, P30 to P32,		$4.0~V \leq EV_{DD} \leq 5.5~V$			-60.0	mA
		,	P70 to P74, P125 to P127	$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}$			-15.0	mA
		(When duty	= 70% Note 3)	1.8 V ≤ EV <sub>DD</sub> < 2.7 V			-8.0	mA
				1.6 V ≤ EV <sub>DD</sub> < 1.8 V			-4.0	mA
		Total of all pins (When duty = 70% <sup>Note 3</sup> )					-100.0	mA
	lон2	P20, P21	Per pin				-0.1	mA
			Total of all pins	$1.6~V \leq V_{DD} \leq 5.5~V$			-0.2	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the V<sub>DD</sub> and EV<sub>DD</sub> pins to an output pin.
  - 2. Do not exceed the total current value.
  - **3.** Specification under conditions where the duty factor  $\leq 70\%$ .

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = (IoH × 0.7)/(n × 0.01)

<Example> Where n = 80% and IoH = -40.0 mA

Total output current of pins =  $(-40.0 \times 0.7)/(80 \times 0.01) \approx -35.0$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

### Caution P10, P12, P15, and P17 do not output high level in N-ch open-drain mode.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

(2/5)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Output current, low <sup>Note 1</sup>	loL1	Per pin for P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147					20.0 Note 2	mA
		Per pin for P60, P61					15.0 Note 2	mA
		Total of P10 to P14, P40 to P43,	$4.0~V \leq EV_{DD} \leq 5.5~V$			70.0	mA	
		P120, P130, P140 to P147 (When duty = 70% Note 3)		$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 4.0 \text{ V}$			15.0	mA
				$1.8 \text{ V} \leq \text{EV}_{\text{DD}} \leq 2.7 \text{ V}$			9.0	mA
				1.6 V ≤ EV <sub>DD</sub> < 1.8 V			4.5	mA
		Total of P15 to P17, P30 to P32, P50 to P54, P60, P61, P70 to P74, P125 to P127 (When duty = 70% Note 3)		$4.0~V \leq EV_{DD} \leq 5.5~V$			80.0	mA
				$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 4.0 \text{ V}$			35.0	mA
				$1.8 \text{ V} \leq \text{EV}_{\text{DD}} \leq 2.7 \text{ V}$			20.0	mA
		,	, - ,	$1.6 \text{ V} \le \text{EV}_{DD} < 1.8 \text{ V}$			10.0	mA
		Total of all pins (When duty = 70% <sup>Note 3</sup> )					150.0	mA
	lol2	P20, P21	Per pin				0.4	mA
			Total of all pins	$1.6~V \leq V_{DD} \leq 5.5~V$			0.8	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the V<sub>DD</sub> and EV<sub>DD</sub> pins to an output pin.
  - 2. Do not exceed the total current value.
  - **3.** Specification under conditions where the duty factor  $\leq 70\%$ .

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (IoH × 0.7)/(n × 0.01)
- <Example> Where n = 80% and IoL = 70.0 mA

Total output current of pins =  $(70.0 \times 0.7)/(80 \times 0.01) \approx 61.25$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(3/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V <sub>IH1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	Normal input buffer	0.8EVDD		EV <sub>DD</sub>	V
	V <sub>IH2</sub>	P10, P11, P15, P16	TTL input buffer $4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$	2.2		EV <sub>DD</sub>	V
			TTL input buffer 3.3 V ≤ EV <sub>DD</sub> < 4.0 V	2.0		EV <sub>DD</sub>	V
<del>                                     </del>			TTL input buffer 1.6 V ≤ EV <sub>DD</sub> < 3.3 V	1.50		EV <sub>DD</sub>	V
	V <sub>IH3</sub>	P20, P21	0.7V <sub>DD</sub>		V <sub>DD</sub>	V	
	V <sub>IH4</sub>	P60, P61	0.7EV <sub>DD</sub>		EV <sub>DD</sub>	V	
	V <sub>IH5</sub>	P121 to P124, P137, EXCLK, EXCLK	0.8V <sub>DD</sub>		V <sub>DD</sub>	V	
Input voltage, low	VIL1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	Normal input buffer	0		0.2EV <sub>DD</sub>	V
	V <sub>IL2</sub>	P10, P11, P15, P16	TTL input buffer 4.0 V ≤ EV <sub>DD</sub> ≤ 5.5 V	0		0.8	V
			TTL input buffer 3.3 V ≤ EV <sub>DD</sub> < 4.0 V	0		0.5	V
V			TTL input buffer 1.6 V ≤ EV <sub>DD</sub> < 3.3 V	0		0.32	V
	V <sub>IL3</sub>	P20, P21	0		0.3V <sub>DD</sub>	V	
	V <sub>IL4</sub>	P60, P61		0		0.3EV <sub>DD</sub>	V
V <sub>IL5</sub> P121 to P124, P137, EXCLK, EX		P121 to P124, P137, EXCLK, EXCLK	S, RESET	0		0.2V <sub>DD</sub>	V

Caution The maximum value of VIH of P10, P12, P15, P17 is EVDD, even in the N-ch open-drain mode.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(4/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	V <sub>OH1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V},$ $I_{\text{OH1}} = -10 \text{ mA}$	EV <sub>DD</sub> -1.5			V
		P125 to P127, P130, P140 to P147	$4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V},$ $I_{\text{OH1}} = -3.0 \text{ mA}$	EV <sub>DD</sub> -0.7			٧
			$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V},$ $I_{\text{OH1}} = -2.0 \text{ mA}$	EV <sub>DD</sub> -0.6			٧
			$1.8 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ Iон1 = $-1.5 \text{ mA}$	EV <sub>DD</sub> -0.5			V
			$1.6 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ Iон1 = $-1.0 \text{ mA}$	EV <sub>DD</sub> -0.5			V
	V <sub>OH2</sub>	P20, P21	1.6 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V, I <sub>OH2</sub> = -100 $\mu$ A	V <sub>DD</sub> -0.5			V
Output voltage, low	V <sub>OL1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$4.0~\text{V} \leq \text{EV}_{\text{DD}} \leq 5.5~\text{V},$ $I_{\text{OL1}} = 20~\text{mA}$			1.3	V
		P125 to P127, P130, P140 to P147	$4.0~V \leq EV_{DD} \leq 5.5~V,$ $I_{OL1} = 8.5~mA$			0.7	V
			$2.7~\textrm{V} \leq \textrm{EV}_\textrm{DD} \leq 5.5~\textrm{V},$ $\textrm{I}_\textrm{OL1} = 3.0~\textrm{mA}$			0.6	٧
			$2.7~V \leq EV_{DD} \leq 5.5~V,$ $I_{OL1} = 1.5~mA$			0.4	٧
			$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL1}} = 0.6 \text{ mA}$			0.4	V
			$1.6 \text{ V} \le \text{EV}_{DD} < 5.5 \text{ V},$ $I_{OL1} = 0.3 \text{ mA}$			0.4	V
	V <sub>OL2</sub>	P20, P21	1.6 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V, I <sub>OL2</sub> = 400 $\mu$ A			0.4	V
	V <sub>OL3</sub>	P60, P61	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL3}} = 15.0 \text{ mA}$			2.0	٧
			$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ Iol3 = 5.0  mA			0.4	V
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL3}} = 3.0 \text{ mA}$			0.4	V
			$1.8 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OL3} = 2.0 \text{ mA}$			0.4	V
			$1.6 \text{ V} \le \text{EV}_{DD} < 5.5 \text{ V},$ $I_{OL3} = 1.0 \text{ mA}$			0.4	V

Caution P10, P12, P15, P17 do not output high level in N-ch open-drain mode.

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(5/5)

Items	Symbol	Condition	ons		MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ішн	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	V <sub>I</sub> = EV <sub>DD</sub>	)			1	μΑ
	ILIH2	P20, P21, P137, RESET	$V_{I} = V_{DD}$				1	μΑ
	Ілінз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	V <sub>I</sub> = V <sub>DD</sub>	In input port or external clock input			1	μΑ
				In resonator connection			10	μΑ
Input leakage current, low	ILIL1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147					-1	μΑ
	I <sub>LIL2</sub>	P20, P21, P137, RESET	Vı = Vss				-1	μA
	Ілігз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	V <sub>I</sub> = V <sub>SS</sub>	In input port or external clock input			-1	μΑ
				In resonator connection			-10	μΑ
On-chip pll-up	R <sub>U1</sub>	Vı = EVss	SEGxx p	ort				
resistance			2.4 V ≤	EV <sub>DD</sub> = V <sub>DD</sub> ≤ 5.5 V	10	20	100	kΩ
				EV <sub>DD</sub> = V <sub>DD</sub> < 2.4 V	10	30	100	kΩ
	Ru2			er than above or P60, P61, and	10	20	100	kΩ

**Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

## 2.3.2 Supply current characteristics

## (Ta = -40 to +85°C, 1.6 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

(1/3)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit		
Supply	I <sub>DD1</sub>	Operating	HS (high-speed	f <sub>IH</sub> = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA		
current		mode	main) mode <sup>Note 5</sup>		operation	V <sub>DD</sub> = 3.0 V		1.5		mA		
Note 1					Normal	V <sub>DD</sub> = 5.0 V		3.3	5.0	mA		
					operation	V <sub>DD</sub> = 3.0 V		3.3	5.0	mA		
				f <sub>IH</sub> = 16 MHz <sup>Note 3</sup>	Normal	V <sub>DD</sub> = 5.0 V		2.5	3.7	mA		
					operation	V <sub>DD</sub> = 3.0 V		2.5	3.7	mA		
			LS (low-speed	f <sub>IH</sub> = 8 MHz <sup>Note 3</sup>	Normal	V <sub>DD</sub> = 3.0 V		1.2	1.8	mA		
			main) mode <sup>Note 5</sup>		operation	V <sub>DD</sub> = 2.0 V		1.2	1.8	mA		
			LV (low-	f <sub>IH</sub> = 4 MHz <sup>Note 3</sup>	Normal	V <sub>DD</sub> = 3.0 V		1.2	1.7	mA		
			voltage main) mode <sup>Note 5</sup>		operation	V <sub>DD</sub> = 2.0 V		1.2	1.7	mA		
			HS (high-speed	f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> ,	Normal	Square wave input		2.8	4.4	mA		
			main) mode <sup>Note 5</sup>	V <sub>DD</sub> = 5.0 V	operation	Resonator connection		3.0	4.6	mA		
				f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> ,	Normal	Square wave input		2.8	4.4	mA		
				V <sub>DD</sub> = 3.0 V	operation	Resonator connection		3.0	4.6	mA		
				· '	Normal	Square wave input		1.8	2.6	mA		
					V <sub>DD</sub> = 5.0 V	operation	Resonator connection		1.8	2.6	mA	
				f <sub>MX</sub> = 10 MHz <sup>Note 2</sup> ,	Normal	Square wave input		1.8	2.6	mA		
						V <sub>DD</sub> = 3.0 V	operation	Resonator connection		1.8	2.6	mA
			LS (low-speed	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	Normal	Square wave input		1.1	1.7	mA		
			main) mode <sup>Note 5</sup>	V <sub>DD</sub> = 3.0 V	operation	Resonator connection		1.1	1.7	mA		
				f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	Normal	Square wave input		1.1	1.7	mA		
				V <sub>DD</sub> = 2.0 V	operation	Resonator connection		1.1	1.7	mA		
			Subsystem	fsub = 32.768 kHz <sup>Note 4</sup>	Normal	Square wave input		3.5	4.9	μΑ		
			clock operation	T <sub>A</sub> = -40°C	operation	Resonator connection		3.6	5.0	μΑ		
				fsub = 32.768 kHz <sup>Note 4</sup>	Normal	Square wave input		3.6	4.9	μΑ		
				T <sub>A</sub> = +25°C	operation	Resonator connection		3.7	5.0	μA		
				fsub = 32.768 kHz <sup>Note 4</sup>	Normal	Square wave input		3.7	5.5	μΑ		
				T <sub>A</sub> = +50°C	operation	Resonator connection		3.8	5.6	μΑ		
				fsub = 32.768 kHz <sup>Note 4</sup>	Normal	Square wave input		3.8	6.3	μΑ		
				T <sub>A</sub> = +70°C operation		Resonator connection		3.9	6.4	μΑ		
				fsuB = 32.768 kHz <sup>Note 4</sup>		Square wave input		4.1	7.7	μΑ		
				T <sub>A</sub> = +85°C	operation	Resonator connection		4.2	7.8	μΑ		

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Total current flowing into V<sub>DD</sub> and EV<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub>, EV<sub>DD</sub> or Vss, EVss. The following points apply in the HS (high-speed main), LS (low-speed main), and LV (low-voltage main) modes.
  - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
  - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

- 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- 3. When high-speed system clock and subsystem clock are stopped.
- 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation).
- 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz}$  to 24 MHz

 $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V@1 MHz}$  to 16 MHz

LS (low-speed main) mode:  $1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}@1 \text{ MHz}$  to 8 MHz LV (low-voltage main) mode:  $1.6 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}@1 \text{ MHz}$  to 4 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

<R>

## (Ta = -40 to +85°C, 1.6 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

(2/3)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub>	HALT	HS (high-speed	f <sub>IH</sub> = 24 MHz Note 4	V <sub>DD</sub> = 5.0 V		0.44	1.28	mA
current Note 1	Note 2	mode	main) mode Note 6		V <sub>DD</sub> = 3.0 V		0.44	1.28	mA
				f <sub>IH</sub> = 16 MHz Note 4	V <sub>DD</sub> = 5.0 V		0.40	1.00	mA
					V <sub>DD</sub> = 3.0 V		0.40	1.00	mA
			LS (low-speed	f <sub>IH</sub> = 8 MHz Note 4	V <sub>DD</sub> = 3.0 V		260	530	μA
			main) mode Note 6		V <sub>DD</sub> = 2.0 V		260	530	μA
			LV (low-voltage	f <sub>IH</sub> = 4 MHz Note 4	V <sub>DD</sub> = 3.0 V		420	640	μA
			main) mode Note 6		V <sub>DD</sub> = 2.0 V		420	640	μA
			HS (high-speed	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		0.28	1.00	mA
			main) mode Note 6	V <sub>DD</sub> = 5.0 V	Resonator connection		0.45	1.17	mA
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		0.28	1.00	mA
				V <sub>DD</sub> = 3.0 V	Resonator connection		0.45	1.17	mA
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		0.19	0.60	mA
				V <sub>DD</sub> = 5.0 V	Resonator connection		0.26	0.67	mA
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		0.19	0.60	mA
				V <sub>DD</sub> = 3.0 V	Resonator connection		0.26	0.67	mA
			LS (low-speed	f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		95	330	μA
			main) mode Note 6	V <sub>DD</sub> = 3.0 V	Resonator connection		145	380	μA
				f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		95	330	μA
				V <sub>DD</sub> = 2.0 V	Resonator connection		145	380	μA
			Subsystem	fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.31	0.57	μA
			clock operation	T <sub>A</sub> = -40°C	Resonator connection		0.50	0.76	μA
				fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.37	0.57	μA
				T <sub>A</sub> = +25°C	Resonator connection		0.56	0.76	μA
				fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.46	1.17	μA
				T <sub>A</sub> = +50°C	Resonator connection		0.65	1.36	μA
				fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.57	1.97	μA
				T <sub>A</sub> = +70°C	Resonator connection		0.76	2.16	μA
		f <sub>SUB</sub> = 32.768 kHz <sup>N</sup>		fsub = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.85	3.37	μΑ
				T <sub>A</sub> = +85°C	Resonator connection		1.04	3.56	μΑ
	I <sub>DD3</sub>	STOP Note 7	T <sub>A</sub> = -40°C				0.17	0.50	μА
		mode Note 7	T <sub>A</sub> = +25°C				0.23	0.50	μА
			T <sub>A</sub> = +50°C				0.32	1.10	μΑ
			T <sub>A</sub> = +70°C				0.43	1.90	μА
			T <sub>A</sub> = +85°C				0.71	3.30	μΑ

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Total current flowing into V<sub>DD</sub> and EV<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub>, EV<sub>DD</sub> or Vss, EVss. The following points apply in the HS (high-speed main), LS (low-speed main), and LV (low-voltage main) modes.
  - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
  - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- 4. When high-speed system clock and subsystem clock are stopped.
- **5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1).
- 6. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @ 1 \text{ MHz}$  to 24 MHz

 $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V@1 MHz to 16 MHz}$ 

LS (low-speed main) mode: 1.8 V  $\leq$  Vpd  $\leq$  5.5 V@1 MHz to 8 MHz

LV (low-voltage main) mode:  $1.6 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @ 1 \text{ MHz to 4 MHz}$ 

- 7. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C

(3/3)

Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on- chip oscillator operating current	<sub>FIL</sub> Note 1					0.20		μΑ
RTC operating current	IRTC Notes 1, 2, 3	fmain is stopped				0.08		μА
12-bit interval timer current	I <sub>IT</sub> Notes 1, 2, 4					0.08		μА
Watchdog timer operating current	WDT   Notes 1, 2, 5	fı∟ = 15 kHz				0.24		μΑ
A/D converter	IADC	When conversion		$AV_{REFP} = V_{DD} = 5.0 V$		1.3	1.7	mA
operating current	Notes 1, 6	at maximum speed	Low voltage mo	de, $AV_{REFP} = V_{DD} = 3.0 \text{ V}$		0.5	0.7	mA
A/D converter reference voltage current	ADREF Note 1					75.0		μA
Temperature sensor operating current	I <sub>TMPS</sub> Note 1				75.0		μΑ	
LVD operating current	ILVD Notes 1, 7					0.08		μА
Self- programming operating current	FSP Notes 1, 9					2.50	12.20	mA
BGO operating current	I <sub>BGO</sub>					2.00	12.20	mA
LCD operating current	ILCD1 Notes 11, 12	External resistance	division method	V <sub>DD</sub> = EV <sub>DD</sub> = 5.0 V V <sub>L4</sub> = 5.0 V		0.04	0.20	μА
	I <sub>LCD2</sub> Note 11	Internal voltage boo	osting method	$V_{DD} = EV_{DD} = 5.0 \text{ V}$ $V_{L4} = 5.1 \text{ V (VLCD} = 12\text{H)}$		1.12	3.70	μА
				$V_{DD} = EV_{DD} = 3.0 \text{ V}$ $V_{L4} = 3.0 \text{ V} \text{ (VLCD} = 04\text{H)}$		0.63	2.20	μΑ
	I <sub>LCD3</sub> Note 11	Capacitor split metl	nod		0.12	0.50	μА	
SNOOZE	I <sub>SNOZ</sub> Note 1	ADC operation	C operation The mode is performed Note 10				0.60	mA
operating current			The A/D conversion operations are performed, Low voltage mode, AVREFP = VDD = 3.0 V			1.20	1.44	mA
	I	Simplified SPI (CSI				0.70	0.84	mA

(Notes and Remarks are listed on the next page.)

#### Notes 1. Current flowing to VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
- 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer is in operation.
- **6.** Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
- 8. Current flowing only during data flash rewrite.
- 9. Current flowing only during self programming.
- 10. For shift time to the SNOOZE mod.
- 11. Current flowing only to the LCD controller/driver. The supply current value of the RL78 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1 or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel.

The TYP. value and MAX. value are following conditions.

- When fsuB is selected for system clock, LCD clock = 128 Hz (LCDC0 = 07H)
- 4-Time-Slice, 1/3 Bias Method
- **12.** Not including the current that flows through the external divider resistor when the external resistance division method is used.

#### Remarks 1. fil: Low-speed on-chip oscillator clock frequency

- 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- 3. fclk: CPU/peripheral hardware clock frequency
- 4. Temperature condition of the TYP. value is TA = 25°C

## 2.4 AC Characteristics

## 2.4.1 Basic operation

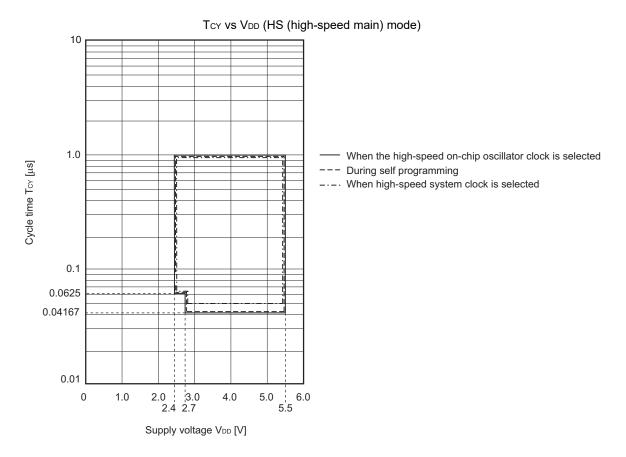
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \leq \text{EV}_{DD} = \text{V}_{DD} \leq 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

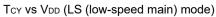
Items	Symbol				MIN.	TYP.	MAX.	Unit	
Instruction cycle (minimum	Tcy	Main system	HS (high-		$2.7V \le V_{DD} \le 5.5V$	0.04167		1	μS
instruction execution time)		clock (fmain) operation	main) mo	ode	$2.4 \text{ V} \le \text{V}_{DD} \le 2.7 \text{ V}$	0.0625		1	μS
		ороганоп	LV (low v main) mo		$1.6V\!\leq\!V_{DD}\!\leq\!5.5V$	0.25		1	μs
			LS (low-s main) mo		$1.8V \le V_{DD} \le 5.5V$	0.125		1	μs
		Subsystem clo	ock (fsuв)		$1.8V \le V_{DD} \le 5.5V$	28.5	30.5	31.3	μs
		In the self	HS (high-		$2.7V\!\leq\!V_{DD}\!\leq\!5.5V$	0.04167		1	μS
		programming mode	main) mo	ode	$2.4 \text{ V} \le \text{V}_{DD} \le 2.7 \text{ V}$	0.0625		1	μS
			LV (low v main) mo		$1.8V \le V_{DD} \le 5.5V$	0.25		1	μS
			LS (low-s main) mo		$1.8V \le V_{DD} \le 5.5V$	0.125		1	μs
External main system clock	fex	$2.7 \text{ V} \leq V_{DD} \leq 3$	5.5 V			1.0		20.0	MHz
frequency		$2.4 \text{ V} \leq \text{V}_{DD} < 2.4 \text{ V}$				1.0		16.0	MHz
		$1.8 \text{ V} \le \text{V}_{DD} < 2.4 \text{ V}$ $1.6 \text{ V} \le \text{V}_{DD} < 1.8 \text{ V}$			1.0		8.0	MHz	
		1.6 V ≤ V <sub>DD</sub> <	1.8 V			1.0		4.0	MHz
	fexs	27 V < Vpp < 5.5 V				32		35	kHz
External main system clock input high-level width, low-level width	texh, texl	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$				24			ns
riigii level widai, lew level widai		2.4 V ≤ V <sub>DD</sub> < 2.7 V				30			ns
		$1.8 \text{ V} \leq \text{V}_{DD} < 3$		60			ns		
		$1.6 \text{ V} \leq \text{V}_{DD} <$	1.8 V			120			ns
	texhs, texhs					13.7			μS
TI00 to TI07 input high-level width, low-level width	tтін, tтіL					1/fмск+10			ns
TO00 to TO07 output frequency	fто	HS (high-spee	ed 4	1.0 V ≤	$EV_{DD} \le 5.5 V$			16	MHz
		main) mode	2	2.7 V ≤	EV <sub>DD</sub> < 4.0 V			8	MHz
			2	2.4 V ≤	EV <sub>DD</sub> < 2.7 V			4	MHz
		LS (low-speed mode	d main) 1	1.8 V ≤	EV <sub>DD</sub> ≤ 5.5 V			4	MHz
		LV (low voltag main) mode	je 1	1.6 V ≤	$EV_{DD} \le 5.5 V$			2	MHz
PCLBUZ0, PCLBUZ1 output	<b>f</b> PCL	HS (high-spee	ed 4	1.0 V ≤	EV <sub>DD</sub> ≤ 5.5 V			16	MHz
frequency		main) mode	2	2.7 V ≤	EV <sub>DD</sub> < 4.0 V			8	MHz
			2	2.4 V ≤	EV <sub>DD</sub> < 2.7 V			4	MHz
		LS (low-speed mode	Ť	1.8 V ≤	EV <sub>DD</sub> ≤ 5.5 V			4	MHz
		LV (low-voltage 1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V				4	MHz		
		main) mode 1.6 V ≤ EV <sub>DD</sub> < 1.8 V				2	MHz		
Interrupt input high-level width,	tinth,	INTP0			$V_{DD} \le 5.5 \text{ V}$	1			μS
low-level width	<b>t</b> intl	INTP1 to INTP			$EV_{DD} \le 5.5 V$	1			μS
Key interrupt input low-level width	<b>t</b> kr	KR0 to KR3 1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V		250			ns		
		1.6 V ≤ EV <sub>DD</sub> < 1.8 V		1			μS		
RESET low-level width	<b>t</b> RSL				10			μS	

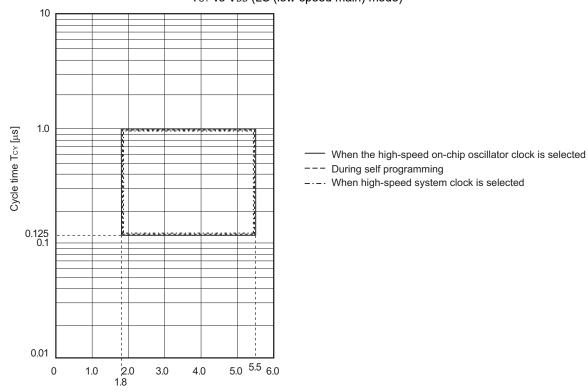
Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

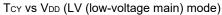
#### Minimum Instruction Execution Time during Main System Clock Operation

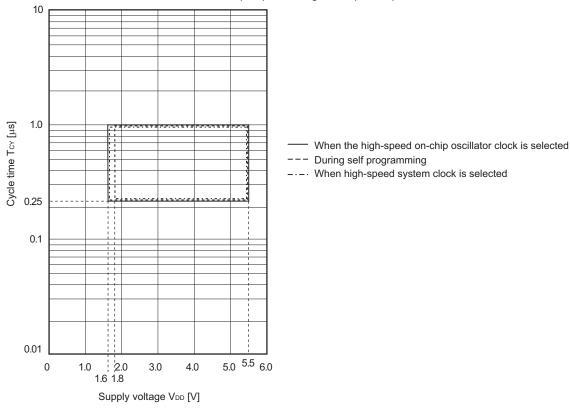




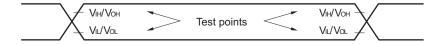


Supply voltage VDD [V]

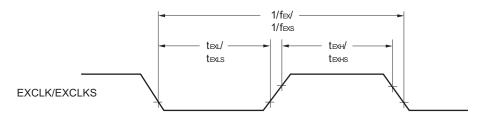




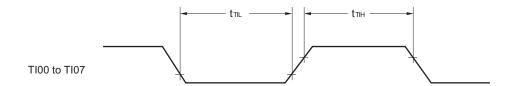
## **AC Timing Test Points**

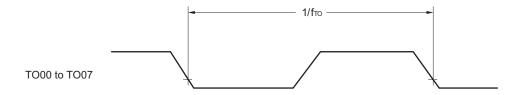


#### **External System Clock Timing**

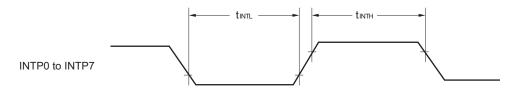


## **TI/TO Timing**

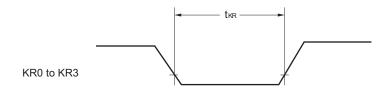




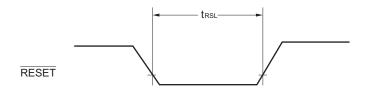
## **Interrupt Request Input Timing**



## **Key Interrupt Input Timing**

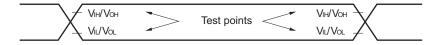


## **RESET** Input Timing



## 2.5 Peripheral Functions Characteristics

#### **AC Timing Test Points**



#### 2.5.1 Serial array unit

#### (1) During communication at same potential (UART mode)

(T<sub>A</sub> = -40 to +85°C, 1.6 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

Parameter	Symbol		Conditions		HS (high-speed main) Mode		/-speed Mode		-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate Note 1		2.4 \	$V \leq EV_{DD} = V_{DD} \leq 5.5 \text{ V}$		fмск/6		fмск/6		fмск/6	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		4.0		1.3		0.6	Mbps
		1.8 \	$1.8 \text{ V} \leq \text{EV}_{DD} = \text{V}_{DD} \leq 5.5 \text{ V}$				fмск/6		fмск/6	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2				1.3		0.6	Mbps
		1.6 \	$1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}$						fмск/6	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2						0.6	Mbps

#### Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

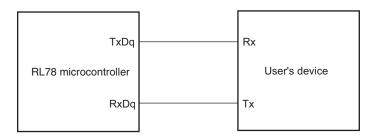
HS (high-speed main) mode: 24 MHz (2.7 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

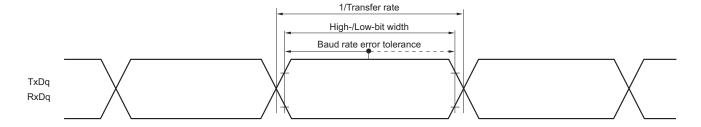
LS (low-speed main) mode: 8 MHz (1.8 V  $\leq$  VDD  $\leq$  5.5 V) LV (low-voltage main) mode: 4 MHz (1.6 V  $\leq$  VDD  $\leq$  5.5 V)

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

#### **UART** mode connection diagram (during communication at same potential)



#### UART mode bit width (during communication at same potential) (reference)



**Remarks 1.** q: UART number (q = 0), g: PIM and POM number (g = 1)

2. fmck: Serial array unit operation clock frequency
(Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

# (2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	(	Conditions	, ,	h-speed Mode	,	/-speed Mode	,	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	2.7 V ≤ EV	/ <sub>DD</sub> ≤ 5.5 V	167 Note 1		500 Note 1		1000 Note 1		ns
		2.4 V ≤ EV	$V_{DD} \leq 5.5 \text{ V}$	250 Note 1		500 Note 1		1000 Note 1		ns
		1.8 V ≤ EV	$f_{\text{DD}} \leq 5.5 \text{ V}$			500 Note 1		1000 Note 1		ns
		1.6 V ≤ EV	$V_{DD} \leq 5.5 \text{ V}$					1000 Note 1		ns
SCKp high-/low-level width	tкн1, tкL1	$4.0~V \leq EV_{DD} \leq 5.5~V$		tксү1/2 - 12		tkcy1/2 - 50		tксү1/2 - 50		ns
		2.7 V ≤ EV	'DD ≤ 5.5 V	tксү1/2 - 18		tkcy1/2 - 50		tксү1/2 - 50		ns
		2.4 V ≤ EV	<b>/</b> DD ≤ <b>5.5 V</b>	tkcy1/2 - 38		tkcy1/2 - 50		tксү1/2 - 50		ns
		1.8 V ≤ EV	$l_{DD} \leq 5.5 \text{ V}$			tkcy1/2 - 50		tkcy1/2 - 50		ns
		1.6 V ≤ EV	$\prime_{\text{DD}} \leq 5.5 \text{ V}$					tксү1/2 - 100		ns
SIp setup time (to SCKp↑)	tsık1	2.7 V ≤ EV	$V_{DD} \leq 5.5 \text{ V}$	44		110		110		ns
Note 2		2.4 V ≤ EV	/ <sub>DD</sub> ≤ 5.5 V	75		110		110		ns
		1.8 V ≤ EV	<sup>1</sup> / <sub>DD</sub> ≤ 5.5 V			110		110		ns
		1.6 V ≤ EV	/ <sub>DD</sub> ≤ 5.5 V					220		ns
SIp hold time (from SCKp↑)	<b>t</b> ksıı	2.4 V ≤ EV	$2.4~V \leq EV_{DD} \leq 5.5~V$			19		19		ns
Note 3		$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$				19		19		
		$1.6~V \leq EV_{DD} \leq 5.5~V$						19		
Delay time from SCKp↓ to	<b>t</b> kso1		$2.4~V \le EV_{DD} \le 5.5~V$		25		25		25	ns
SOp output Note 4		Note 5	$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$				25		25	
			$1.6~V \le EV_{DD} \le 5.5~V$						25	

Notes 1. For CSI00, set a cycle of 2/fмск or longer. For CSI01, set a cycle of 4/fмск or longer.

- **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp $\downarrow$ " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

(Remarks are listed on the next page.)

- **Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM numbers (g = 1)
  - 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00, 01))

# (3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Cond	litions	HS (high main)		LS (low main)			-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time <sup>Note 5</sup>	t <sub>KCY2</sub>	$4.0~V \le EV_{DD} \le 5.5~V$	20 MHz < fмск	8/fмск						ns
			f <sub>MCK</sub> ≤ 20 MHz	6/fмск		6/fмск		6/fмск		ns
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$	16 MHz < fмск	8/fмск						ns
			fмск ≤ 16 MHz	6/ƒмск		6/fмск		6/ƒмск		ns
		$2.4~V \le EV_{DD} \le 5.5~V$		6/fмск and 500		6/ƒмск		6/fмск		ns
		1.8 V ≤ EV <sub>DD</sub> < 2.4 V				6/fмск		6/ƒмск		ns
		1.6 V ≤ EV <sub>DD</sub> < 1.8 V						6/ƒмск		ns
SCKp high-/low-level width	tкн2, tкL2	$4.0~\text{V} \leq \text{EV}_{\text{DD}} \leq 5.5~\text{V}$		tксү2/2 - 7		tксү2/2 -7		tксү2/2 - 7		ns
		2.7 V ≤ EV <sub>DD</sub> < 4.0 V		tксу2/2 - 8		tксү2/2 -8		tксү2/2 -8		ns
		2.4 V ≤ EV <sub>DD</sub> < 2.7 V		tксу2/2 - 18		tксү2/2 - 18		tксү2/2 - 18		ns
		1.8 V ≤ EV <sub>DD</sub> < 2.4 V				tксү2/2 - 18		tксу2/2 - 18		ns
		1.6 V ≤ EV <sub>DD</sub> < 1.8 V						tkcy2/2 -66		ns
SIp setup time (to SCKp↑) <sup>Note 1</sup>	tsıк2	$2.7~\text{V} \leq \text{EV}_{\text{DD}} \leq 5.5~\text{V}$		1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		2.4 V ≤ EV <sub>DD</sub> < 2.7 V		1/fмск + 30		1/fмск + 30		1/fмск + 30		
		1.8 V ≤ EV <sub>DD</sub> < 2.4 V				1/fмск + 30		1/fмск + 30		ns
		1.6 V ≤ EV <sub>DD</sub> < 1.8 V						1/fмск + 40		ns
SIp hold time (from SCKp↑) <sup>Note 2</sup>	t <sub>KSI2</sub>	$2.4~\text{V} \leq \text{EV}_{\text{DD}} \leq 5.5~\text{V}$		1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
		1.8 V ≤ EV <sub>DD</sub> < 2.4 V				1/fмск + 31		1/fмск + 31		ns
		1.6 V ≤ EV <sub>DD</sub> < 1.8 V						1/fмск + 250		ns

(Notes, Caution, and Remarks are listed on the next page.)

# (3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

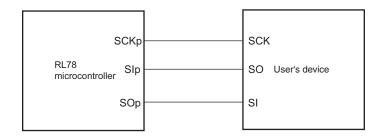
Parameter	Symbol	Cc	onditions	HS (high- speed main) Mode	LS (low- speed main) Mode	LV (low- voltage main) Mode	Unit	Para meter	Symbol	Conditions
Delay time from SCKp↓ to SOp	<b>t</b> ks02	C = 30 pF Note 4	$4.0~V \leq EV_{DD} \leq 5.5~V$		2/fмск + 44		2/fмск + 110		2/fмск + 110	ns
output Note 3			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}$		2/fмск + 44		2/fмск + 110		2/fмск + 110	ns
			2.4 V ≤ EV <sub>DD</sub> < 2.7 V		2/fмск + 75		2/fмск + 110		2/fмск + 110	ns
			1.8 V ≤ EV <sub>DD</sub> < 2.4 V				2/fмск + 110		2/fмск + 110	ns
			1.6 V ≤ EV <sub>DD</sub> < 1.8 V						2/fмск + 220	ns

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SCKp and SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

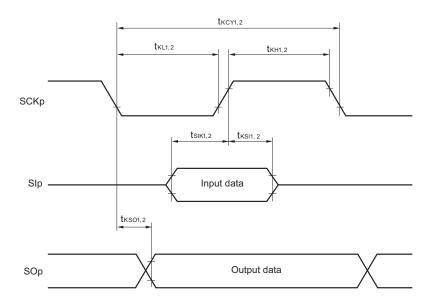
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- Remarks 1. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM number (g = 1)
  - 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

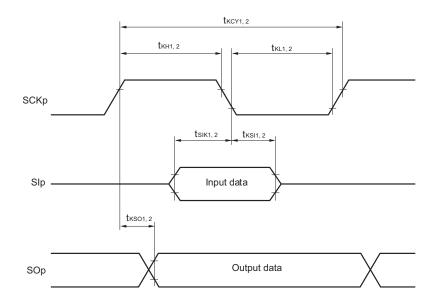
#### Simplified SPI (CSI) mode connection diagram (during communication at same potential)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remarks 1.** p: CSI number (p = 00, 01)

2. m: Unit number, n: Channel number (mn = 00, 01)

## (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) ( $T_A = -40$ to +85°C, 1.8 V $\leq$ EV<sub>DD</sub> = $V_{DD} \leq$ 5.5 V, $V_{SS} = EV_{SS} = 0$ V)

(1/2)

Parameter	Symbol		Conditions		HS (high main) I	•	LS (low-speed main) Mode		LV (low-voltage main) Mode		Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		Reception	4.0 V ≤ EV 2.7 V ≤ V <sub>b</sub>	,		fmck/6 Note 1		fMCK/6 Note 1		fMCK/6 Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$			4.0		1.3		0.6	Mbps
			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$			fmck/6 Note 1		fMCK/6 Note 1		fMCK/6 Note 1	bps
				Theoretical value of the maximum transfer rate f <sub>MCK</sub> = f <sub>CLK</sub> Note 3		4.0		1.3		0.6	Mbps
			2.4 V ≤ EV 1.6 V ≤ V <sub>b</sub>	,		fmck/6 Note 1		fMCK/6 Note 1		fmck/6 Note 1	bps
				Theoretical value of the maximum transfer rate f <sub>MCK</sub> = f <sub>CLK</sub> Note 3		4.0		1.3		0.6	Mbps
			$1.8 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$					fmck/6 Notes 1, 2		fMCK/6 Notes 1, 2	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3					1.3		0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. Use it with  $EV_{DD} \ge V_b$ .

3. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 24 MHz ( $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$ )

16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

LS (low-speed main) mode: 8 MHz (1.8 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V) LV (low-voltage main) mode: 4 MHz (1.6 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (Vod tolerance (32-pin to 52-pin products)/EVod tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For Vih and Vil, see the DC characteristics with TTL input buffer selected.

Remarks 1. Vb[V]: Communication line voltage

- **2.** q: UART number (q = 0), g: PIM and POM number (g = 1)
- 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)

# (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = V_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EVss} = 0 \text{ V} )$

(2/2)

Parameter	Symbol		Con	ditions	` `	h-speed Mode	,	v-speed Mode	,	-voltage Mode	Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		Transmission		$EV_{DD} \le 5.5 \text{ V},$ $V_b \le 4.0 \text{ V}$		Note 1		Note 1		Note 1	bps
				Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 1.4 \text{ k}\Omega,$ $V_b = 2.7 \text{ V}$		2.8 <sup>Note 2</sup>		2.8 <sup>Note 2</sup>		2.8 <sup>Note 2</sup>	Mbps
				7 V ≤ EV <sub>DD</sub> < 4.0 V, 3 V ≤ V <sub>b</sub> ≤ 2.7 V		Note 3		Note 3		Note 3	bps
			Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$ $V_b = 2.3 \text{ V}$		1.2 <sup>Note 4</sup>		1.2 <sup>Note 4</sup>		1.2 <sup>Note 4</sup>	Mbps	
				EV <sub>DD</sub> < 3.3 V, V <sub>b</sub> ≤ 2.0 V		Note 6		Note 6		Note 6	bps
				Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 5.5 k $\Omega$ $V_b$ = 1.6 V		0.43 <sup>Note 7</sup>		0.43 <sup>Note 7</sup>		0.43 <sup>Note 7</sup>	Mbps
				EV <sub>DD</sub> < 3.3 V, V <sub>b</sub> ≤ 2.0 V				Notes 5, 6		Notes 5, 6	bps
				Theoretical value of the maximum transfer rate $C_b$ = 50 pF, $R_b$ = 5.5 k $\Omega$ , $V_b$ = 1.6 V				0.43 <sup>Note 7</sup>		0.43 <sup>Note 7</sup>	Mbps

**Notes 1.** The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V  $\leq$  EV<sub>DD</sub>  $\leq$  5.5 V and 2.7 V  $\leq$  V<sub>b</sub>  $\leq$  4.0 V

$$\label{eq:maximum transfer rate} \begin{aligned} & \frac{1}{\{-C_b \times R_b \times ln\ (1-\frac{2.2}{V_b})\} \times 3} \ [bps] \end{aligned}$$

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **2.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.

3. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V  $\leq$  EV<sub>DD</sub> < 4.0 V and 2.3 V  $\leq$  V<sub>b</sub>  $\leq$  2.7 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{2.0}{V_b})}\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **4.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.
- 5. Use it with  $EV_{DD} \ge V_b$ .
- **6.** The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V  $\leq$  EV<sub>DD</sub> < 3.3 V and 1.6 V  $\leq$  V<sub>b</sub>  $\leq$  2.0 V

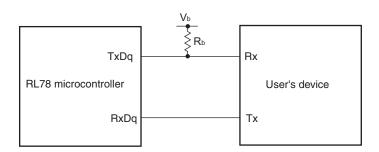
Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times ln \ (1 - \frac{1.5}{V_b})\} \times 3} [bps]$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{1.5}{V_b})}\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

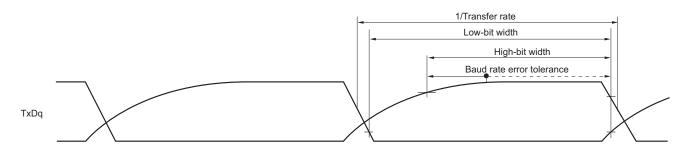
- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **7.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 6 above to calculate the maximum transfer rate under conditions of the customer.

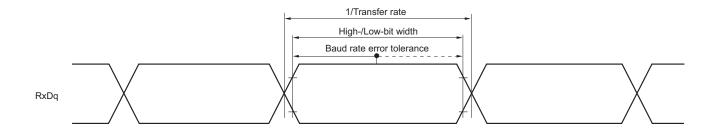
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (Vpd tolerance (32-pin to 52-pin products)/EVpd tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For Vih and Vil, see the DC characteristics with TTL input buffer selected.

#### **UART** mode connection diagram (during communication at different potential)



#### UART mode bit width (during communication at different potential) (reference)





- **Remarks 1.**  $R_b[\Omega]$ : Communication line (TxDq) pull-up resistance,
  - $C_b[F]: \ Communication \ line \ (TxDq) \ load \ capacitance, \ V_b[V]: \ Communication \ line \ voltage$
  - 2. q: UART number (q = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

# (5) Communication at different potential (2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

(TA = -40 to +85°C, 2.7 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

Parameter	Symbol	Conditions		speed	high- main) ode	,	/-speed Mode	LV (low- voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 2/fclk	$\begin{split} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V &\leq V_b \leq 4.0 \ V, \\ C_b &= 20 \ pF, \ R_b = 1.4 \ k\Omega \end{split}$	200 Note 1		1150 Note 1		1150 Note 1		ns
			$\begin{split} 2.7 \ V &\leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 20 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	300 Note 1		1150 Note 1		1150 Note 1		ns
SCKp high-level width	<b>t</b> кн1	4.0 V ≤ EV <sub>DD</sub>	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$			tkcy1/2		tkcy1/2		ns
		C₀ = 20 pF, R	$R_b = 1.4 \text{ k}\Omega$	- 50		- 50		- 50		
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		tксү1/2 - 120		tксү1/2 - 120		tксү1/2 - 120		ns
SCKp low-level width	t <sub>KL1</sub>		$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			tксү1/2 - 50		tксү1/2 - 50		ns
		2.7 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R	$< 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $R_b = 2.7 \text{ k}Ω$	tксү1/2 - 10		tксү1/2 - 50		tксү1/2 - 50		ns
SIp setup time (to SCKp↑) Note 2	tsıĸ1	4.0 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R	58		479		479		ns	
			$< 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$	121		479		479		ns
SIp hold time (from SCKp↑) Note 2	t <sub>KSI1</sub>	4.0 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R	10		10		10		ns	
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$ $C_{\text{b}} = 20 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}\Omega$		10		10		10		ns
Delay time from SCKp↓ to SOp output Note 2	tkso1		$\leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_{b} \leq 4.0 \text{ V},$		60		60		60	ns
		2.7 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R		130		130		130	ns	
SIp setup time (to SCKp↓) Note 3	tsıĸı	$4.0 \text{ V} \leq \text{EV}_{DD}$ $C_b = 20 \text{ pF}, \text{ R}$	$\leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_b \leq 4.0 \text{ V},$ $R_b = 1.4 \text{ k}\Omega$	23		110		110		ns
		2.7 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R	$< 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $R_b = 2.7 \text{ k}\Omega$	33		110		110		ns
SIp hold time (from SCKp↓) Note 3	t <sub>KSI1</sub>	-	$\leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_{b} \leq 4.0 \text{ V},$	10		10		10		ns
		2.7 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R	$< 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $R_b = 2.7 \text{ k}Ω$	10		10		10		ns
Delay time from SCKp↑ to SOp output Note 3	tkso1	4.0 V ≤ EV <sub>DD</sub> C <sub>b</sub> = 20 pF, R		10		10		10	ns	
			$< 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$		10		10		10	ns

(Notes, Caution and Remarks are listed on the next page.)

- Notes 1. For CSI00, set a cycle of 2/fмcκ or longer. For CSI01, set a cycle of 4/fмcκ or longer.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
  - 3. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R<sub>b</sub>[ $\Omega$ ]:Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub>[F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmcx: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)

# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (1/3)

(T<sub>A</sub> = -40 to +85°C, 1.8 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

Parameter	Symbol	Conditions			high- main) ode	,	/-speed Mode	LV (low- voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fclk	$\begin{aligned} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V &\leq V_b \leq 4.0 \ V, \\ C_b &= 30 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned}$	300		1150		1150		ns
			$2.7 \ V \le EV_{DD} < 4.0 \ V,$ $2.3 \ V \le V_b \le 2.7 \ V,$ $C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega$	500		1150		1150		ns
			$2.4 \ V \le EV_{DD} < 3.3 \ V,$ $1.6 \ V \le V_b \le 2.0 \ V,$ $C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega$	1150		1150		1150		ns
			$\begin{aligned} 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{aligned}$			1150		1150		ns
SCKp high-level width	tкн1	4.0 V ≤ EV <sub>DD</sub> ≤ 5 C <sub>b</sub> = 30 pF, R <sub>b</sub> =	5.5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V, = 1.4 kΩ	tксү1/2 - 75		tkcy1/2 - 75		tксү1/2 - 75		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4$ $C_b = 30 \text{ pF}, R_b = 4$	4.0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	tксү1/2 - 170		tkcy1/2 - 170		tксү1/2 - 170		ns
		$2.4 \text{ V} \le \text{EV}_{DD} < 3$ $C_b = 30 \text{ pF}, R_b = 3$	3.3 V, 1.6 V $\leq$ V <sub>b</sub> $\leq$ 2.0 V, = 5.5 kΩ	tксү1/2 - 458		tkcy1/2 - 458		tkcy1/2 - 458		ns
		$1.8 \text{ V} \le \text{EV}_{DD} < 3$ $C_b = 30 \text{ pF}, R_b = 3$	$3.3~V,~1.6~V \le V_b \le 2.0~V^{\text{Note}},$ = $5.5~k\Omega$			tkcy1/2 - 458		tkcy1/2 - 458		ns
SCKp low-level width	t <sub>KL1</sub>	$4.0 \text{ V} \leq \text{EV}_{DD} \leq 5$ $C_b = 30 \text{ pF}, R_b = 5$	$5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ = $1.4 \text{ k}\Omega$	tkcy1/2 - 12		tkcy1/2 - 50		tkcy1/2 - 50		ns
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}\Omega$			tkcy1/2 - 50		tkcy1/2 - 50		ns
			$2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_b \le 2.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			tkcy1/2 - 50		tkcy1/2 - 50		ns
		$1.8 \text{ V} \le \text{EV}_{DD} < 3$ $C_b = 30 \text{ pF}, R_b = 3$	$3.3~V,1.6~V \le V_b \le 2.0~V^{\text{Note}},$ = $5.5~k\Omega$			tkcy1/2 - 50		tксү1/2 - 50		ns

Note Use it with  $EV_{DD} \ge V_b$ .

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/3)

(T<sub>A</sub> = -40 to +85°C, 1.8 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

Parameter	Symbol	Conditions	speed	high- I main) ode	speed	(low- l main) ode	voltage	(low- e main) ode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) Note 1	tsıĸı	$ \begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array} $	81		479		479		ns
		$ \begin{array}{l} 2.7 \; V \leq EV_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $	177		479		479		ns
		$ \begin{array}{l} 2.4 \; V \leq EV_{DD} < 3.3 \; V, \; 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} $	479		479		479		ns
		$ \begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array} $			479		479		ns
SIp hold time (from SCKp↑) Note 1	tksi1	$ \begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array} $	19		19		19		ns
		$ \begin{array}{l} 2.7 \; V \leq EV_{DD} < 4.0 \; V,  2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $	19		19		19		ns
		$ \begin{array}{l} 2.4 \; V \leq EV_{DD} < 3.3 \; V, \; 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} $	19		19		19		ns
		$ \begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array} $			19		19		ns
Delay time from SCKp↓ to SOp output Note 1	tkso1	$ \begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array} $		100		100		100	ns
		$ \begin{array}{c} 2.7 \; V \leq EV_{DD} < 4.0 \; V,  2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $		195		195		195	ns
		$ \begin{array}{c} 2.4 \; V \leq EV_{DD} < 4.0 \; V,  2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $		483		483		483	ns
		$\begin{split} 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$				483		483	ns
SIp setup time (to SCKp↓) Note 2	tsıĸı	$ \begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array} $	44		110		110		ns
		$ 2.7 \text{ V} \leq \text{EV}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \leq \text{V}_b \leq 2.7 \text{ V}, \\ C_b = 30 \text{ pF},  R_b = 2.7 \text{ k}\Omega $	44		110		110		ns
		$ \begin{array}{c} 2.4 \; V \leq EV_{DD} < 4.0 \; V,  2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $	110		110		110		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$			110		110		ns

Notes

- 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
- 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. Use it with EVDD ≥ Vb.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VH and VL, see the DC characteristics with TTL input buffer selected.

(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (3/3)

(T<sub>A</sub> = -40 to +85°C, 1.8 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

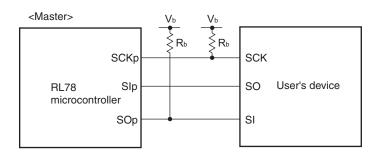
Parameter	Symbol	Conditions	HS (high- speed main)			(low-   main)		(low- e main)	Unit
				ode	Mode		_	ode	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp hold time (from SCKp↓) Note 2	tksi1	$ \begin{aligned} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b &= 30 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned} $	19		19		19		ns
		$ \begin{array}{l} 2.7 \; V \leq EV_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $	19		19		19		ns
		$ \begin{array}{l} 2.4 \; V \leq EV_{DD} < 3.3 \; V, \; 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} $	19		19		19		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$			19		19		ns
Delay time from SCKp↑ to SOp output Note 2	tkso1	$ \begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array} $		25		25		25	ns
		$ \begin{array}{l} 2.7 \; V \leq EV_{DD} < 4.0 \; V,  2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $		25		25		25	ns
		$ \begin{array}{l} 2.4 \; V \leq EV_{DD} < 3.3 \; V, \; 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} $		25		25		25	ns
		$\begin{split} 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{split}$				25		25	ns

#### **Notes**

- 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
- 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. Use it with  $EV_{DD} \ge V_b$ .

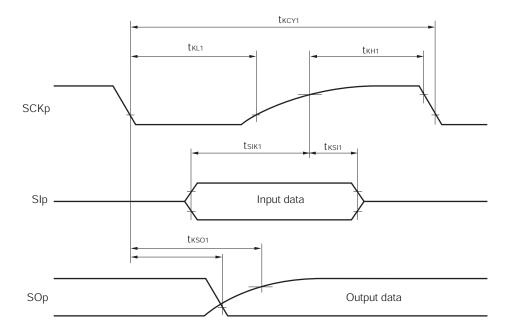
Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

#### Simplified SPI (CSI) mode connection diagram (during communication at different potential)

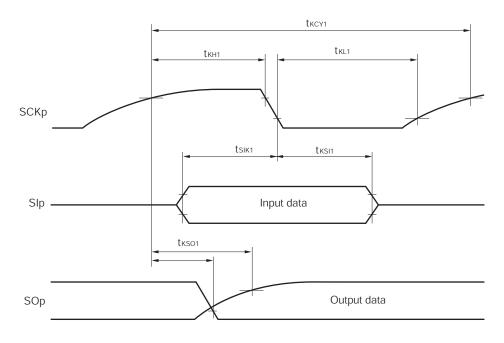


- **Remarks 1.** R<sub>b</sub>[Ω]:Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub>[F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency
    (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)

Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

# (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

(1/2)

$(T_A = -40 \text{ to } +85)$	°C, 1.8 \	$/ \le EV_{DD} = V_{DD} \le 5$ .	5 V, Vss = EVss = 0	<u>V)</u>						(1/2)
Parameter	Symbol	Con	ditions	speed	high- main) ode	,	/-speed mode	"	low- e main) ode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 1	tkcy2	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	<b>12/f</b> мск						ns
		$2.7~V \leq V_b \leq 4.0~V$	$8 \text{ MHz} < f_{MCK} \le 20 \text{ MHz}$	10/fмск						ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	8/fмск		16/fмск				ns
			fмck ≤ 4 MHz	6/fмск		10/fмск		10/fмск		ns
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	<b>16/f</b> мск						ns
		$2.3~V \leq V_b \leq 2.7~V$	16 MHz < f <sub>MCK</sub> ≤ 20 MHz	<b>14/f</b> мск						ns
			8 MHz < fмck ≤ 16 MHz	<b>12/f</b> мск						ns
			4 MHz < fMCK ≤ 8 MHz	8/fмск		16/fмск				ns
			fмcκ ≤ 4 MHz	6/fмск		10/fмск		<b>10/f</b> мск		ns
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	36/fмск						ns
		$1.6 \text{ V} \leq \text{V}_b \leq 2.0 \text{ V}$	$16 \text{ MHz} < \text{fmck} \le 20 \text{ MHz}$	32/fмск						ns
			8 MHz < fмck ≤ 16 MHz	<b>26/f</b> мск						ns
			4 MHz < fMCK ≤ 8 MHz	<b>16/f</b> мск		16/fмск				ns
			fмcк≤4 MHz	10/fмск		10/fмск		<b>10/f</b> мск		ns
		1.8 V ≤ EV <sub>DD</sub> < 3.3 V,	4 MHz < fMCK ≤ 8 MHz			16/fмск				ns
	$1.6~V \le V_b \le 2.0~V^{\text{Note 2}}$		fмcк≤4 MHz			10/fмск		<b>10/f</b> мск		ns
SCKp high-/low-level width	tkH2, tkL2	$4.0 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$	$V_{c}, 2.7 \text{ V} \le V_{b} \le 4.0 \text{ V}$	tkcy2/2 - 12		tkcy2/2 - 50		tkcy2/2 - 50		ns
		2.7 V ≤ EV <sub>DD</sub> < 4.0 V	tkcy2/2 - 18		txcy2/2 - 50		tkcy2/2 - 50		ns	
		2.4 V ≤ EV <sub>DD</sub> < 3.3 V	tkcy2/2 - 50		tkcy2/2 - 50		tkcy2/2 - 50		ns	
		$\begin{array}{c} 1.8 \ V \leq EV_{DD} < 3.3 \ V \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{Not} \end{array}$			txcy2/2 - 50		tkcy2/2 - 50		ns	
SIp setup time (to SCKp↑) Note 3	tsık2	4.0 V ≤ EV <sub>DD</sub> < 5.5 V	$V_{1}, 2.7 \text{ V} \le V_{b} \le 4.0 \text{ V}$	1/f <sub>MCK</sub> + 20		1/fmck + 30		1/fmck + 30		ns
		2.7 V ≤ EV <sub>DD</sub> < 4.0 V	$V_{1}, 2.3 \text{ V} \le V_{b} \le 2.7 \text{ V}$	1/f <sub>MCK</sub> + 20		1/fmck + 30		1/f <sub>MCK</sub> + 30		ns
		2.4 V ≤ EV <sub>DD</sub> < 3.3 V	$V_{1}, 1.6 \text{ V} \le V_{b} \le 2.0 \text{ V}$	1/f <sub>MCK</sub> + 30		1/f <sub>MCK</sub> + 30		1/f <sub>MCK</sub> + 30		ns
		$\begin{array}{c} 1.8 \ V \leq EV_{DD} < 3.3 \ V \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{Not} \end{array}$				1/fmck+ 30		1/fmck + 30		ns
SIp hold time (from SCKp <sup>↑</sup> ) Note 4	t <sub>KSI2</sub>	4.0 V ≤ EV <sub>DD</sub> < 5.5 V	$V, 2.7 \text{ V} \le V_b \le 4.0 \text{ V}$	1/f <sub>MCK</sub> + 31		1/f <sub>MCK</sub> + 31		1/f <sub>MCK</sub> + 31		ns
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$				1/f <sub>MCK</sub> + 31		1/f <sub>MCK</sub> + 31		ns
		$2.4 \text{ V} \le \text{EV}_{DD} \le 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$				1/f <sub>MCK</sub> + 31		1/f <sub>MCK</sub> + 31		ns
		$\begin{array}{c} 1.8 \ V \leq EV_{DD} < 3.3 \ V \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{Not} \end{array}$	·			1/f <sub>MCK</sub> + 31		1/f <sub>MCK</sub> + 31		ns

(Notes, Caution and Remarks are listed on the next page.)

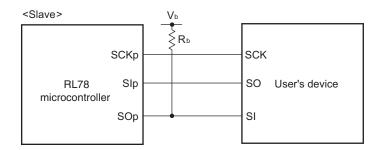
## (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

(T <sub>A</sub> = -40 to +85°	C, 1.8 V ≤	$EV_{DD} = V_{DD} \le 5.5 \text{ V, Vss} = EV_{SS} = 0$	V)						(2/2)
Parameter	Symbol	Conditions		HS (high- speed main) mode		v-speed mode	voltage	low- e main) ode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Delay time from SCKp↓ to SOp output Note 5	tkso2	$ \begin{aligned} 4.0 \ V &\leq EV_{DD} \leq 5.5 \ V,  2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b &= 30 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned} $		2/fмск + 120		2/fмск + 573		2/fмск + 573	ns
				2/fмск + 214		2/fмск + 573		2/fмск + 573	ns
				2/fмск + 573		2/fмск + 573		2/fмск + 573	ns
		$\begin{split} 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$				2/fмск + 573		2/fмск + 573	ns

- Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
  - 2. Use it with  $EV_{DD} \ge V_b$ .
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

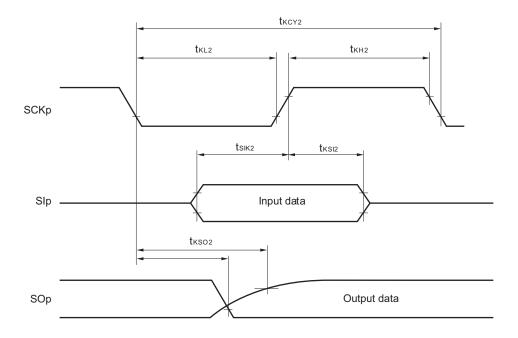
Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

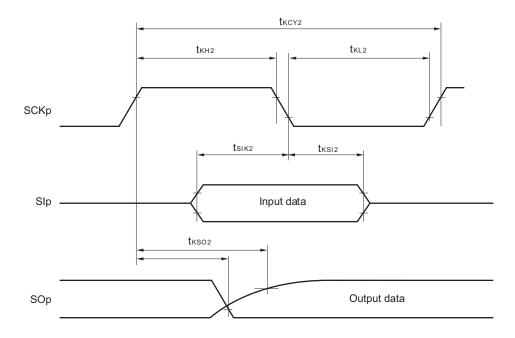


- **Remarks 1.**  $R_b[\Omega]$ :Communication line (SOp) pull-up resistance,  $C_b[F]$ : Communication line (SOp) load capacitance,  $V_b[V]$ : Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency
    (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

## 2.5.2 Serial interface IICA

## (1) I<sup>2</sup>C standard mode

(Ta = -40 to +85°C, 1.6 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

Parameter	Symbol	(	Conditions	speed	high- I main) ode	LS (low-speed main) Mode		LV (low- voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	Standard	$2.7~V \leq EV_{DD} \leq 5.5~V$	0	100	0	100	0	100	kHz
		mode: fclk≥ 1 MHz	2.4 V ≤ EV <sub>DD</sub> ≤ 5.5 V	0	100	0	100	0	100	
		TOLK = T WIT 12	1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V			0	100	0	100	
			1.6 V ≤ EV <sub>DD</sub> ≤ 5.5 V					0	100	
Setup time of restart condition	tsu:sta	2.7 V ≤ EV <sub>DD</sub> s	≤ 5.5 V	4.7		4.7		4.7		μS
		2.4 V ≤ EV <sub>DD</sub> s	≤ 5.5 V	4.7		4.7		4.7		
		1.8 V ≤ EV <sub>DD</sub> s	≤ 5.5 V			4.7		4.7		
		1.6 V ≤ EV <sub>DD</sub> :	≤ 5.5 V					4.7		
Hold time Note 1	thd:sta	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V		4.0		4.0		4.0		μS
		2.4 V ≤ EV <sub>DD</sub> s	$2.4~V \le EV_{DD} \le 5.5~V$			4.0		4.0		
		1.8 V ≤ EV <sub>DD</sub> s	≤ 5.5 V			4.0		4.0		
		1.6 V ≤ EV <sub>DD</sub> ≤ 5.5 V						4.0		
Hold time when SCLA0 = "L"	tLOW	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V		4.7		4.7		4.7		μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5 V		4.7		4.7		4.7		
		1.8 V ≤ EV <sub>DD</sub> s	≤ 5.5 V			4.7		4.7		
		1.6 V ≤ EV <sub>DD</sub> :	≤ 5.5 V					4.7		
Hold time when SCLA0 = "H"	<b>t</b> HIGH	$2.7~V \leq EV_{DD} \leq 5.5~V$		4.0		4.0		4.0		μS
		$2.4~V \leq EV_{DD} \leq 5.5~V$		4.0		4.0		4.0		
		$1.8 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$				4.0		4.0		
		$1.6 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$						4.0		
Data setup time (reception)	tsu:dat	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V		250		250		250		ns
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5 V		250		250		250		
		1.8 V ≤ EV <sub>DD</sub> s	≤ 5.5 V			250		250		
		1.6 V ≤ EV <sub>DD</sub> s	≤ 5.5 V					250		
Data hold time (transmission)Note 2	thd:dat	2.7 V ≤ EV <sub>DD</sub> :	≤ 5.5 V	0	3.45	0	3.45	0	3.45	μS
		2.4 V ≤ EV <sub>DD</sub> s	≤ 5.5 V	0	3.45	0	3.45	0	3.45	
		1.8 V ≤ EV <sub>DD</sub> :	≤ 5.5 V			0	3.45	0	3.45	
		1.6 V ≤ EV <sub>DD</sub> :	≤ 5.5 V					0	3.45	
Setup time of stop condition	tsu:sto	2.7 V ≤ EV <sub>DD</sub> s	≤ 5.5 V	4.0		4.0		4.0		μS
		2.4 V ≤ EV <sub>DD</sub> :	≤ 5.5 V	4.0		4.0		4.0		
		1.8 V ≤ EV <sub>DD</sub> :	≤ 5.5 V			4.0		4.0		
		1.6 V ≤ EV <sub>DD</sub> :					4.0			
Bus-free time	<b>t</b> BUF	2.7 V ≤ EV <sub>DD</sub> s	≤ 5.5 V	4.7		4.7		4.7		μS
		2.4 V ≤ EV <sub>DD</sub> :	≤ 5.5 V	4.7		4.7		4.7		
		1.8 V ≤ EV <sub>DD</sub> :	≤ 5.5 V			4.7		4.7		
		1.6 V ≤ EV <sub>DD</sub> :	≤ 5.5 V					4.7		

(Notes and Remark are listed on the next page.)

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
  - 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

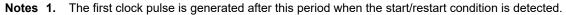
**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode:  $C_b = 400 \text{ pF}, R_b = 2.7 \text{ k}\Omega$ 

#### (2) I2C fast mode

#### (Ta = -40 to +85°C, 1.6 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol	(	Conditions			LS (low-speed main) Mode		LV (low- voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	Fast mode:	$2.7~V \leq EV_{DD} \leq 5.5~V$	0	400	0	400	0	400	kHz
		fc∟k≥ 3.5 MHz	$2.4~V \leq EV_{DD} \leq 5.5~V$	0	400	0	400	0	400	
		IVII IZ	$1.8 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$			0	400	0	400	
Setup time of restart condition	tsu:sta	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		0.6		0.6		0.6		μS
		$2.4~V \leq EV_{DD} \leq 5.5~V$		0.6		0.6		0.6		
		1.8 V ≤ EV <sub>DD</sub>	≤ 5.5 V			0.6		0.6		
Hold time Note 1	thd:STA	2.7 V ≤ EV <sub>DD</sub>	$2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$			0.6		0.6		μS
		2.4 V ≤ EV <sub>DD</sub>	≤ 5.5 V	0.6		0.6		0.6		
		1.8 V ≤ EV <sub>DD</sub>	1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V			0.6		0.6		
Hold time when SCLA0 = "L"	tLOW	2.7 V ≤ EV <sub>DD</sub>	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V			1.3		1.3		μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5 V 1		1.3		1.3		1.3		
		1.8 V ≤ EV <sub>DD</sub>	1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V			1.3		1.3		
Hold time when SCLA0 = "H"	tніgн	2.7 V ≤ EV <sub>DD</sub>	≤ 5.5 V	0.6		0.6		0.6		μS
		$2.4~V \leq EV_{DD} \leq 5.5~V$		0.6		0.6		0.6		
		1.8 V ≤ EV <sub>DD</sub>	≤ 5.5 V			0.6		0.6		
Data setup time (reception)	tsu:dat	2.7 V ≤ EV <sub>DD</sub>	≤ 5.5 V	100		100		100		ns
		2.4 V ≤ EV <sub>DD</sub>	≤ 5.5 V	100		100		100		
		1.8 V ≤ EV <sub>DD</sub>	≤ 5.5 V			100		100		
Data hold time (transmission)Note 2	thd:dat	$2.7 \text{ V} \leq \text{EV}_{\text{DD}}$	≤ 5.5 V	0	0.9	0	0.9	0	0.9	μS
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}}$	≤ 5.5 V	0	0.9	0	0.9	0	0.9	
		1.8 V ≤ EV <sub>DD</sub>	≤ 5.5 V			0	0.9	0	0.9	
Setup time of stop condition	tsu:sto	$2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$		0.6		0.6		0.6		μS
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		0.6		0.6		0.6		
		1.8 V ≤ EV <sub>DD</sub> ≤ 5.5 V				0.6		0.6		
Bus-free time	t <sub>BUF</sub>	$2.7 \text{ V} \leq \text{EV}_{\text{DD}}$	≤ 5.5 V	1.3		1.3		1.3		μS
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}}$	≤ 5.5 V	1.3		1.3		1.3		
		1.8 V ≤ EV <sub>DD</sub>	≤ 5.5 V			1.3		1.3		



2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode:  $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$ 



#### (3) I<sup>2</sup>C fast mode plus

# (Ta = -40 to +85°C, 1.6 V $\leq$ EVDD = VDD $\leq$ 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol	bol Conditions			h-speed Mode		/-speed Mode	`	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode plus: fcLk ≥ 10 MHz	.			_		_		kHz
Setup time of restart condition	tsu:sta	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V			_		_	_	μS
Hold time <sup>Note 1</sup>	thd:STA	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5$	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V				-	_	-	μS
Hold time when SCLA0 = "L"	tLOW	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V			_		_		μS
Hold time when SCLA0 = "H"	<b>t</b> HIGH	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V			_	-	_	-	μS
Data setup time (reception)	tsu:dat	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	50		_	_	_	_	μS
Data hold time (transmission) <sup>Note 2</sup>	thd:dat	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0	0.45	_	_	_	_	μS
Setup time of stop condition	tsu:sto	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5 V			_	_	_	_	μs
Bus-free time	<b>t</b> BUF	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.5		_	-	_	-	μS

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

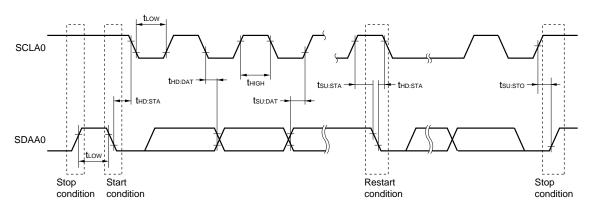
2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

Caution The values in the above table are applied even when bit 2 (PIOR2) in the peripheral I/O redirection register (PIOR) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.

**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode plus:  $C_b = 120 \text{ pF}, R_b = 1.1 \text{ k}\Omega$ 

#### IICA serial transfer timing





# 2.6 Analog Characteristics

#### 2.6.1 A/D converter characteristics

#### Classification of A/D converter characteristics

	Reference Voltage							
Input channel	Reference voltage (+) = AV <sub>REFP</sub> Reference voltage (-) = AV <sub>REFM</sub>	Reference voltage (+) = V <sub>DD</sub> Reference voltage (-) = Vss	Reference voltage (+) = V <sub>BGR</sub> Reference voltage (-) = AV <sub>REFM</sub>					
ANIO, ANI1	_	Refer to 2.6.1 (3).	Refer to <b>2.6.1 (4)</b> .					
ANI16 to ANI23	Refer to 2.6.1 (2).							
Internal reference voltage Temperature sensor output voltage	Refer to <b>2.6.1 (1)</b> .		-					

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : internal reference voltage, and temperature sensor output voltage

(TA = -40 to +85°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, 1.6 V  $\leq$  AV<sub>REFP</sub>  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V, Reference voltage (+) = AV<sub>REFP</sub>, Reference voltage (-) = AV<sub>REFM</sub> = 0 V)

Parameter	Symbol	Condit	tions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$		1.2	±3.5	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.6~V \leq V_{DD} \leq 5.5~V^{\text{Note 4}}$		1.2	±7.0	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.375		39	μS
		Target pin: Internal reference	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.5625		39	μs
		voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
		, , ,					
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	10-bit resolution	1.8 V ≤ AV <sub>REFP</sub> ≤ 5.5 V			±0.25	%FSR
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.6~V \leq AV_{REFP} \leq 5.5~V^{\text{Note 4}}$			$\pm 0.50$	%FSR
Full-scale errorNotes 1, 2	E <sub>FS</sub>	10-bit resolution	$1.8~V \leq AV_{REFP} \leq 5.5~V$			±0.25	%FSR
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.6~V \leq AV_{REFP} \leq 5.5~V^{\text{Note 4}}$			±0.50	%FSR
Integral linearity	ILE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±2.5	LSB
error <sup>Note 1</sup>		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.6~V \leq V_{DD} \leq 5.5~V^{\text{Note 4}}$			±5.0	LSB
Differential linearity	DLE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±1.5	LSB
error <sup>Note 1</sup>		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.6~V \leq V_{DD} \leq 5.5~V^{\text{Note 4}}$			±2.0	LSB
Analog input voltage	Vain	Internal reference voltage (2.4 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V, HS (high-		V <sub>BGR</sub> Note 5		V	
	VBGR	Temperature sensor output vo $(2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},  HS (high-$		V <sub>TMPS25</sub> Note 5		V	

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When AVREFP < VDD. the MAX, values are as follows.

Overall error: Add  $\pm 1.0$  LSB to the MAX. value when AVREFP = VDD.

Zero-scale error/Full-scale error: Add  $\pm 0.05\%$  FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Integral linearity error/Differential linearity error: Add  $\pm 0.5$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

- **4.** Values when the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).
- 5. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.



# (2) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : ANI16 to ANI23

(TA = -40 to +85°C, 1.6 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, 1.6 V  $\leq$  AV<sub>REFP</sub>  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V, Reference voltage (+) = AV<sub>REFP</sub>, Reference voltage (-) = AV<sub>REFM</sub> = 0 V)

Parameter	Symbol	Condit	ions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution	$1.8~V \leq AV_{REFP} \leq 5.5~V$		1.2	±5.0	LSB
		$AV_{REFP} = EV_{DD} = V_{DD}^{\text{Note 3}}$	$1.6~V \leq AV_{REFP} \leq 5.5~V$ Note 4		1.2	±8.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
		AV <sub>REFP</sub> = EV <sub>DD</sub> = V <sub>DD</sub> Note 3	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \leq V_{DD} \leq 5.5~V$	17		39	μS
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μS
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	10-bit resolution	$1.8~V \leq AV_{REFP} \leq 5.5~V$			±0.35	%FSR
			$1.6~V \le AV_{REFP} \le 5.5~V$ Note 4			±0.60	%FSR
Full-scale errorNotes 1, 2	E <sub>FS</sub>		$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.35	%FSR
		$AV_{REFP} = EV_{DD} = V_{DD}^{\text{Note 3}}$	$1.6~V \le AV_{REFP} \le 5.5~V$ Note 4			±0.60	%FSR
Integral linearity errorNote 1	ILE	10-bit resolution	1.8 V ≤ AV <sub>REFP</sub> ≤ 5.5 V			±3.5	LSB
		$AV_{REFP} = EV_{DD} = V_{DD}^{\text{Note 3}}$	$1.6~V \le AV_{REFP} \le 5.5~V$ Note 4			±6.0	LSB
Differential linearity error	DLE	10-bit resolution	1.8 V ≤ AV <sub>REFP</sub> ≤ 5.5 V			±2.0	LSB
Note 1		$AV_{REFP} = EV_{DD} = V_{DD}^{\text{Note 3}}$	$1.6~V \le AV_{REFP} \le 5.5~V$ Note 4			±2.5	LSB
Analog input voltage	Vain			0		AV <sub>REFP</sub> and EV <sub>DD</sub>	V

#### Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When AVREFP < EVDD = VDD, the MAX. values are as follows.

Overall error: Add  $\pm 4.0$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Zero-scale error/Full-scale error: Add  $\pm 0.20\%$ FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Integral linearity error/Differential linearity error: Add  $\pm 2.0$  LSB to the MAX. value when AVREFP = VDD.

**4.** When the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).

(3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>SS</sub> (ADREFM = 0), target pin : ANI0, ANI1, ANI16 to ANI23, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{V}_{DD}, \text{ Reference voltage (-)} = \text{V}_{SS})$ 

Parameter	Symbol	Conditio	ns	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$		1.2	±7.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μS
			$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μS
			$1.8~V \leq V_{DD} \leq 5.5~V$	17		39	μS
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μS
		10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.375		39	μS
		Target pin: Internal	$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μS
		reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±0.85	%FSR
Full-scale errorNotes 1, 2	Ers	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$\begin{array}{c} 1.6 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V} \\ \text{Note 3} \end{array}$			±0.85	%FSR
Integral linearity errorNote 1	ILE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±4.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±6.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±2.5	LSB
Analog input voltage	VAIN	ANI0, ANI1		0		V <sub>DD</sub>	V
		ANI16 to ANI23	0		EV <sub>DD</sub>	V	
		Internal reference voltage (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (high		V <sub>BGR</sub> Note 4		V	
		Temperature sensor output (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (hig	•		V <sub>TMPS25</sub> Note 4		V

**Notes 1.** Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- **3.** When the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).
- 4. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : ANI0, ANI16 to ANI23

(TA = -40 to  $+85^{\circ}$ C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, Vss = EVss = 0 V, Reference voltage (+) = V<sub>BGR</sub> Note 3, Reference voltage (-) = AV<sub>REFM</sub> Note 4 = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Cond	MIN.	TYP.	MAX.	Unit	
Resolution	RES				8		bit
Conversion time	tconv	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity errorNote 1	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	Vain			0		V <sub>BGR</sub> Note 3	V

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - 3. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.
  - **4.** When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add  $\pm 0.35\%$  FSR to the MAX. value when reference voltage (–) = AVREFM.

Integral linearity error: Add ±0.5 LSB to the MAX. value when reference voltage (-) = AVREFM.

Differential linearity error: Add  $\pm 0.2$  LSB to the MAX. value when reference voltage (–) = AVREFM.

# 2.6.2 Temperature sensor/internal reference voltage characteristics

(TA = -40 to +85°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, Vss = EVss = 0 V) (HS (high-speed main) mode)

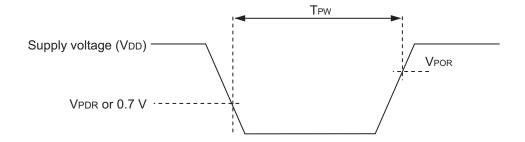
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V <sub>TMPS25</sub>	Setting ADS register = 80H, T <sub>A</sub> = +25°C		1.05		V
Internal reference voltage	V <sub>BGR</sub>	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μS

# 2.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	The power supply voltage is rising.	1.47	1.51	1.55	V
	V <sub>PDR</sub>	The power supply voltage is falling.	1.46	1.50	1.54	V
Minimum pulse width <sup>Note</sup>	Tpw		300			μs

Note Minimum time required for a POR reset when VDD exceeds below VPDR. This is also the minimum time required for a POR reset from when VDD exceeds below 0.7 V to when VDD exceeds VPDR while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



# 2.6.4 LVD circuit characteristics

(Ta = -40 to +85°C, V<sub>PDR</sub>  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	V <sub>LVD0</sub>	Power supply rise time	3.98	4.06	4.14	V
voltage			Power supply fall time	3.90	3.98	4.06	V
		V <sub>LVD1</sub>	Power supply rise time	3.68	3.75	3.82	V
			Power supply fall time	3.60	3.67	3.74	V
		V <sub>LVD2</sub>	Power supply rise time	3.07	3.13	3.19	V
			Power supply fall time	3.00	3.06	3.12	V
		V <sub>LVD3</sub>	Power supply rise time	2.96	3.02	3.08	V
			Power supply fall time	2.90	2.96	3.02	V
		V <sub>LVD4</sub>	Power supply rise time	2.86	2.92	2.97	V
			Power supply fall time	2.80	2.86	2.91	V
		V <sub>LVD5</sub>	Power supply rise time	2.76	2.81	2.87	V
			Power supply fall time	2.70	2.75	2.81	V
		V <sub>LVD6</sub>	Power supply rise time	2.66	2.71	2.76	V
			Power supply fall time	2.60	2.65	2.70	V
		V <sub>LVD7</sub>	Power supply rise time	2.56	2.61	2.66	V
			Power supply fall time	2.50	2.55	2.60	V
		V <sub>LVD8</sub>	Power supply rise time	2.45	2.50	2.55	V
			Power supply fall time	2.40	2.45	2.50	V
		V <sub>LVD9</sub>	Power supply rise time	2.05	2.09	2.13	V
			Power supply fall time	2.00	2.04	2.08	V
		V <sub>LVD10</sub>	Power supply rise time	1.94	1.98	2.02	V
			Power supply fall time	1.90	1.94	1.98	V
		V <sub>LVD11</sub>	Power supply rise time	1.84	1.88	1.91	V
			Power supply fall time	1.80	1.84	1.87	V
		V <sub>LVD12</sub>	Power supply rise time	1.74	1.77	1.81	V
			Power supply fall time	1.70	1.73	1.77	V
		V <sub>LVD13</sub>	Power supply rise time	1.64	1.67	1.70	V
			Power supply fall time	1.60	1.63	1.66	V
Minimum pu	ulse width	tLW		300			μS
Detection de	elay time	<b>t</b> LD				300	μS

# LVD Detection Voltage of Interrupt & Reset Mode

(Ta = -40 to +85°C, VpDr  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

Parameter	Symbol		Cond	litions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	V <sub>LVDA0</sub>	VPOC2,	V <sub>POC1</sub> , V <sub>POC0</sub> = 0, 0, 0	falling reset voltage	1.60	1.63	1.66	V
mode	V <sub>LVDA1</sub>		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.74	1.77	1.81	V
				Falling interrupt voltage	1.70	1.73	1.77	V
	V <sub>LVDA2</sub>		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.84	1.88	1.91	V
				Falling interrupt voltage	1.80	1.84	1.87	V
	V <sub>L</sub> VDA3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	V <sub>LVDB1</sub>	VPOC2,	V <sub>POC1</sub> , V <sub>POC0</sub> = 0, 0, 1	falling reset voltage	1.80	1.84	1.87	V
	V <sub>LVDB2</sub>		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.02	V
				Falling interrupt voltage	1.90	1.94	1.98	V
	V <sub>LVDB3</sub>		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V
	VLVDB4			Falling interrupt voltage	2.00	2.04	2.08	V
			LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	V
				Falling interrupt voltage	3.00	3.06	3.12	V
	V <sub>LVDC0</sub>	V <sub>POC2</sub> ,	VPOC1, VPOC0 = 0, 1, 0	falling reset voltage	2.40	2.45	2.50	V
	V <sub>LVDC1</sub>		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.66	V
				Falling interrupt voltage	2.50	2.55	2.60	V
	V <sub>LVDC2</sub>		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.76	V
				Falling interrupt voltage	2.60	2.65	2.70	V
	V <sub>L</sub> VDC3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.68	3.75	3.82	V
				Falling interrupt voltage	3.60	3.67	3.74	V
	V <sub>L</sub> VDD0	VPOC2,	VPOC1, VPOC0 = 0, 1, 1	falling reset voltage	2.70	2.75	2.81	V
	V <sub>LVDD1</sub>		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
	VLVDD2			Falling interrupt voltage	2.80	2.86	2.91	<b>V</b>
			LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.08	V
				Falling interrupt voltage	2.90	2.96	3.02	V
	V <sub>LVDD3</sub>		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.98	4.06	4.14	V
	_			Falling interrupt voltage	3.90	3.98	4.06	V

# 2.6.5 Supply voltage rise time

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V<sub>DD</sub> reaches the operating voltage range shown in 2.4 AC Characteristics.

# 2.7 LCD Characteristics

# 2.7.1 Resistance division method

#### (1) Static display mode

(Ta = -40 to +85°C, VL4 (MIN.)  $\leq$  VDD  $\leq$  5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.0		$V_{DD}$	V

# (2) 1/2 bias method, 1/4 bias method

(TA = -40 to +85°C, VL4 (MIN.)  $\leq$  VDD  $\leq$  5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.7		V <sub>DD</sub>	V

#### (3) 1/3 bias method

(TA = -40 to +85°C, VL4 (MIN.)  $\leq$  VDD  $\leq$  5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.5		V <sub>DD</sub>	V

# 2.7.2 Internal voltage boosting method

# (1) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$ 

Parameter	Symbol	Cond	litions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V <sub>L1</sub>	C1 to C4 <sup>Note 1</sup>	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 μF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	VL2	C1 to C4 <sup>Note 1</sup> =	: 0.47 μF	2 V <sub>L1</sub> - 0.1	2 VL1	2 V <sub>L1</sub>	V
Tripler output voltage	V <sub>L4</sub>	C1 to C4 <sup>Note 1</sup> = 0.47 $\mu$ F		3 V <sub>L1</sub> - 0.15	3 VL1	3 V <sub>L1</sub>	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait timeNote 3	tvwait2	C1 to C4 <sup>Note 1</sup> =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between V<sub>L1</sub> and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between V<sub>L4</sub> and GND
- $C1 = C2 = C3 = C4 = 0.47 \mu F \pm 30\%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

#### (2) 1/4 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Cor	iditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V <sub>L1</sub> Note 4	C1 to C5 <sup>Note 1</sup>	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 μF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	V <sub>L2</sub>	C1 to C5 <sup>Note 1</sup> =	0.47 μF	2 V <sub>L1</sub> – 0.08	2 V <sub>L1</sub>	2 VL1	V
Tripler output voltage	V <sub>L3</sub>	C1 to C5 <sup>Note 1</sup> =	0.47 μF	3 V <sub>L1</sub> – 0.12	3 V <sub>L1</sub>	3 VL1	V
Quadruply output voltage	V <sub>L4</sub> Note 4	C1 to C5 <sup>Note 1</sup> =	0.47 μF	4 V <sub>L1</sub> – 0.16	4 V <sub>L1</sub>	4 V <sub>L1</sub>	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait timeNote 3	tvwait2	C1 to C5 <sup>Note 1</sup> =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL3 and GND
- C5: A capacitor connected between  $V_{L4}$  and GND
- $C1 = C2 = C3 = C4 = C5 = 0.47 \mu F \pm 30\%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** V<sub>L4</sub> must be 5.5 V or lower.

#### 2.7.3 Capacitor split method

#### 1/3 bias method

(Ta = -40 to +85°C, 2.2 V  $\leq$  VDD  $\leq$  5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V <sub>L4</sub> voltage	V <sub>L4</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 2</sup>		V <sub>DD</sub>		V
V <sub>L2</sub> voltage	V <sub>L2</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 2</sup>	2/3 V <sub>L4</sub> - 0.1	2/3 V <sub>L4</sub>	2/3 V <sub>L4</sub> + 0.1	V
V <sub>L1</sub> voltage	V <sub>L1</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 2</sup>	1/3 V <sub>L4</sub> - 0.1	1/3 V <sub>L4</sub>	1/3 V <sub>L4</sub> + 0.1	V
Capacitor split wait timeNote 1	tvwait		100			ms

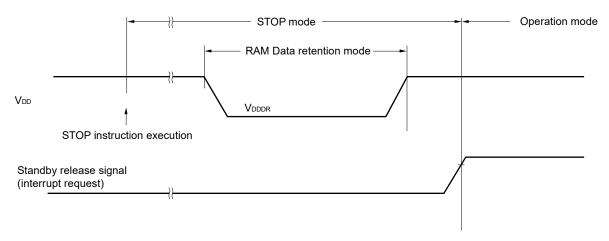
- Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).
  - 2. This is a capacitor that is connected between voltage pins used to drive the LCD.
    - C1: A capacitor connected between CAPH and CAPL
    - C2: A capacitor connected between V<sub>L1</sub> and GND
    - C3: A capacitor connected between VL2 and GND
    - C4: A capacitor connected between VL4 and GND
    - C1 = C2 = C3 = C4 = 0.47  $\mu$ F±30%

#### 2.8 RAM Data Retention Characteristics

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 <sup>Note</sup>		5.5	٧

**Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



# 2.9 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	1		24	MHz
Number of code flash rewrites Note 1, 2, 3	Cerwr	Retained for 20 years T <sub>A</sub> = 85°C	1,000			Times
Number of data flash rewrites		Retained for 1 year T <sub>A</sub> = 25°C		1,000,000		
		Retained for 5 years T <sub>A</sub> = 85°C	100,000			
		Retained for 20 years T <sub>A</sub> = 85°C	10,000			

- **Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite.

  The retaining years are until next rewrite after the rewrite.
  - 2. When using flash memory programmer and Renesas Electronics self programming library
  - 3. This characteristic indicates the flash memory characteristic and based on Renesas Electronics reliability test.

**Remark** When updating data multiple times, use the flash memory as one for updating data.

# 2.10 Dedicated Flash Memory Programmer Communication (UART)

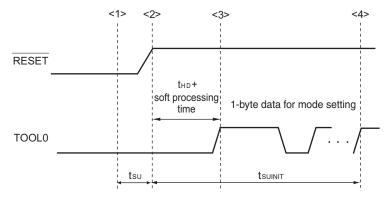
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115,200		1,000,000	bps

# 2.11 Timing Specifications for Switching Flash Memory Programming Modes

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

**Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after a reset is released during this period.

 $tsu: \quad \mbox{ Time to release the external reset after the TOOL0 pin is set to the low level }$ 

thd: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

# 3. ELECTRICAL SPECIFICATIONS (G: $T_A = -40 \text{ to } +105^{\circ}\text{C}$ )

This chapter describes the electrical specifications for the products "G: Industrial applications ( $T_A = -40$  to +105°C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. With products not provided with an EVDD or EVss pin, replace EVDD with VDD, or replace EVss with Vss
  - 3. For derating with  $T_A = +85$  to +105°C, contact our Sales Division or the vender's sales division. Derating means the specified reduction in an operating parameter to improve reliability.

There are following differences between the products "G: Industrial applications ( $T_A = -40 \text{ to } +105^{\circ}\text{C}$ )" and the products "A: Consumer applications, and G: Industrial applications ( $T_A = -40 \text{ to } +85^{\circ}\text{C}$ )".

Parameter	Арр	lication
	A: Consumer applications, G: Industrial applications (with T <sub>A</sub> = -40 to +85°C)	G: Industrial applications
Operating ambient temperature	T <sub>A</sub> = -40 to +85°C	T <sub>A</sub> = -40 to +105°C
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:
Operating voltage range	$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V@1 MHz to } 32 \text{ MHz}$	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 32 \text{ MHz}$
	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V@1 MHz}$ to 16 MHz	$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 16 \text{ MHz}$
	LS (low-speed main) mode:	
	$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V@1 MHz to } 8 \text{ MHz}$	
	LV (low-voltage main) mode:	
	1.6 V ≤ V <sub>DD</sub> ≤ 5.5 V@1 MHz to 4 MHz	
High-speed on-chip oscillator clock	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V:	$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$ :
accuracy	±1.0%@ T <sub>A</sub> = -20 to +85°C	±2.0%@ T <sub>A</sub> = +85 to +105°C
	±1.5%@ T <sub>A</sub> = -40 to -20°C	±1.0%@ T <sub>A</sub> = -20 to +85°C
	$1.6 \text{ V} \le \text{V}_{DD} < 1.8 \text{ V}$ :	±1.5%@ T <sub>A</sub> = -40 to -20°C
	±5.0%@ T <sub>A</sub> = -20 to +85°C	
	±5.5%@ T <sub>A</sub> = -40 to -20°C	
Serial array unit	UART	UART
	CSI00: fclk/2 (supporting 16 Mbps), fclk/4	CSI00: fcLK/4
	CSI01	CSI01
	Simplified I <sup>2</sup> C communication	Simplified I <sup>2</sup> C communication
IICA	Normal mode	Normal mode
	Fast mode	Fast mode
	Fast mode plus	
Voltage detector	Rise detection voltage: 1.67 V to 4.06 V	Rise detection voltage: 2.61 V to 4.06 V
	(14 levels)	(8 levels)
	Fall detection voltage: 1.63 V to 3.98 V	Fall detection voltage: 2.55 V to 3.98 V
	(14 levels)	(8 levels)

**Remark** The electrical characteristics of the products G: Industrial applications (T<sub>A</sub> = -40 to +105°C) are different from those of the products "A: Consumer applications, and G: Industrial applications (only with T<sub>A</sub> = -40 to +85°C)". For details, refer to **3.1** to **3.11**.

# 3.1 Absolute Maximum Ratings

## Absolute Maximum Ratings (TA = 25°C)

(1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V <sub>DD</sub>	V <sub>DD</sub> = EV <sub>DD</sub>	-0.5 to +6.5	V
	EV <sub>DD</sub>	V <sub>DD</sub> = EV <sub>DD</sub>	-0.5 to +6.5	V
	EVss		-0.5 to +0.3	V
REGC pin input voltage	Virego	REGC	-0.3 to +2.8 and -0.3 to V <sub>DD</sub> + 0.3 <sup>Note 1</sup>	>
Input voltage	Vıı	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	-0.3 to EV <sub>DD</sub> + 0.3 and -0.3 to V <sub>DD</sub> + 0.3 <sup>Note 2</sup>	٧
	Vı2	P60, P61 (N-ch open-drain)	-0.3 to EV <sub>DD</sub> + 0.3 and -0.3 to V <sub>DD</sub> + 0.3 <sup>Note 2</sup>	V
	Vıз	P20, P21, P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 2</sup>	V
Output voltage	Vo <sub>1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	-0.3 to EV <sub>DD</sub> + 0.3 and $-0.3$ to V <sub>DD</sub> + 0.3 Note 2	٧
	V <sub>O2</sub>	P20, P21	-0.3 to V <sub>DD</sub> + 0.3 Note 2	V
Analog input voltage	Val1	ANI16 to ANI23	-0.3 to EV <sub>DD</sub> + $0.3$ and $-0.3$ to AV <sub>REF</sub> (+) + $0.3$ <sup>Notes 2, 3</sup>	V
	V <sub>Al2</sub>	ANIO, ANI1	-0.3 to V <sub>DD</sub> + 0.3 and $-0.3$ to AV <sub>REF</sub> (+) + $0.3$ <sup>Notes 2, 3</sup>	V

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
  - 2. Must be 6.5 V or lower.
  - 3. Do not exceed AVREF(+) + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
  - 2. AVREF (+): + side reference voltage of the A/D converter.
  - 3. Vss: Reference voltage

# Absolute Maximum Ratings (TA = 25°C)

(2/3)

Parameter	Symbols		Conditions	Ratings	Unit
LCD voltage	voltage V <sub>L1</sub> V <sub>L1</sub> voltage <sup>Note 1</sup>				V
VL2		V <sub>L2</sub> voltage <sup>Note 1</sup>		-0.3 to V <sub>L4</sub> + 0.3 Note 2	V
	V <sub>L</sub> 3	V <sub>L3</sub> voltage <sup>Note 1</sup>		-0.3 to V <sub>L4</sub> + 0.3 Note 2	V
	V <sub>L4</sub>	V <sub>L4</sub> voltage <sup>Note 1</sup>		-0.3 to +6.5	V
	VLCAP	CAPL, CAPH vol	tage <sup>Note 1</sup>	-0.3 to V <sub>L4</sub> + $0.3$ Note 2	V
	VLOUT	,	External resistance division method	-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 2</sup>	V
	SEG38,	Capacitor split method	-0.3 to V <sub>DD</sub> + 0.3 Note 2		
		output voltage	Internal voltage boosting method	$-0.3$ to $V_{L4} + 0.3^{\text{Note 2}}$	

- Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the V<sub>L1</sub>, V<sub>L2</sub>, V<sub>L3</sub>, and V<sub>L4</sub> pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to V<sub>SS</sub> via a capacitor (0.47  $\mu$  F  $\pm$  30%) and connect a capacitor (0.47  $\mu$  F  $\pm$  30%) between the CAPL and CAPH pins.
  - 2. Must be 6.5 V or lower.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Vss: Reference voltage

# Absolute Maximum Ratings (TA = 25°C)

(3/3)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147	-40	mA
		Total of all pins –170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	<del>-</del> 70	mA
			P15 to P17, P30 to P32, P50 to P54, P70 to P74, P125 to P127	-100	mA
	Іон2	Per pin	P20, P21	-0.5	mA
		Total of all pins		-1	mA
Output current, low	lo <sub>L1</sub>	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	40	mA
		Total of all pins 170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	70	mA
			P15 to P17, P30 to P32, P50 to P54, P60, P61, P70 to P74, P125 to P127	100	mA
	lo <sub>L2</sub>	Per pin	P20, P21	1	mA
		Total of all pins		2	mA
Operating ambient	TA	In normal operation	on mode	-40 to +105	°C
temperature		In flash memory p	programming mode		
Storage temperature	Tstg			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

#### 3.2 Oscillator Characteristics

#### 3.2.1 X1, XT1 oscillator characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/	$2.7~V \leq V_{DD} \leq 5.5~V$	1.0		20.0	MHz
frequency (fx) <sup>Note</sup>	crystal resonator	$2.4~\textrm{V} \leq \textrm{V}_\textrm{DD} < 2.7~\textrm{V}$	1.0		16.0	MHz
XT1 clock oscillation frequency (fxt) <sup>Note</sup>	Crystal resonator		32	32.768	35	kHz

**Note** Indicates only permissible oscillator frequency ranges. Refer to **3.4 AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

# 3.2.2 On-chip oscillator characteristics

(Ta = -40 to +105°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, Vss = EVss = 0 V)

Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency Notes 1, 2	fін			1		24	MHz
High-speed on-chip oscillator		−20 to +85°C	$2.4~V \le V_{DD} \le 5.5~V$	-1		+1	%
clock frequency accuracy		−40 to −20°C	$2.4~V \leq V_{DD} \leq 5.5~V$	-1.5		+1.5	%
		+85 to +105°C	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	-2.0		+2.0	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

- **Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.
  - 2. This indicates the oscillator characteristics only. Refer to 3.4 AC Characteristics for instruction execution time.

#### 3.3 DC Characteristics

#### 3.3.1 Pin characteristics

## $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

(1/5)

Items	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Output current, high <sup>Note 1</sup>	Іон1	Per pin for P10 to P17 P70 to P74, P120, P1					-3.0 Note 2	mA
		Total of P10 to P14, F	240 to P43, P120,	$4.0~V \leq EV_{DD} \leq 5.5~V$			-30.0	mA
		P130, P140 to P147	e 3 \	$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$			-8.0	mA
		(When duty = 70% Note 3)  Total of P15 to P17, P30 to P32,	( )	$2.4 \text{ V} \le \text{EV}_{DD} \le 2.7 \text{ V}$			-4.0	mA
			<sup>2</sup> 30 to P32,	$4.0~V \leq EV_{DD} \leq 5.5~V$			-30.0	mA
		P50 to P54, P70 to P7	•	$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$			-15.0	mA
		(When duty = 70% Not	)	$2.4 \text{ V} \leq \text{EV}_{DD} \leq 2.7 \text{ V}$			-8.0	mA
		Total of all pins (When duty = 70%Note)	otal of all pins  When duty = 70% <sup>Note 3</sup> )				-60.0	mA
	<b>І</b> он2	P20, P21 Per pin					-0.1	mA
			Total of all pins	$2.4~V \leq V_{DD} \leq 5.5~V$			-0.2	mA

- **Notes 1.** Value of current at which the device operation is guaranteed even if the current flows from the V<sub>DD</sub> and EV<sub>DD</sub> pins to an output pin.
  - 2. Do not exceed the total current value.
  - **3.** Specification under conditions where the duty factor  $\leq 70\%$ .

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (IoH × 0.7)/(n × 0.01)
- <Example> Where n = 80% and IOH = -30.0 mA

Total output current of pins =  $(-30.0 \times 0.7)/(80 \times 0.01) \approx -26.25$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

#### Caution P10, P12, P15, and P17 do not output high level in N-ch open-drain mode.

# $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

(2/5)

Items	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Output current, low <sup>Note 1</sup>	lo <sub>L1</sub>		10 to P17, P30 to P32, P40 P120, P125 to P127, P130				8.5 Note 2	mA
		Per pin for P6	60, P61				15.0 Note 2	mA
		Total of P10 t	to P14, P40 to P43, P120,	$4.0~V \leq EV_{DD} \leq 5.5~V$			40.0	mA
		P130, P140 t		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$			15.0	mA
		(When duty = 70% Note 3)	$2.4 \text{ V} \leq \text{EV}_{DD} \leq 2.7 \text{ V}$			9.0	mA	
		Total of P15 t	to P17, P30 to P32, P50	$4.0~V \leq EV_{DD} \leq 5.5~V$			40.0	mA
		to P54, P60, P125 to P127	P61, P70 to P74,	$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$			35.0	mA
		(When duty =		2,4 V ≤ EV <sub>DD</sub> < 2.7 V			20.0	mA
		Total of all pir (When duty =					80.0	mA
	lo <sub>L2</sub>	P20, P21	Per pin				0.4	mA
			Total of all pins	$2.4~V \leq V_{DD} \leq 5.5~V$			0.8	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the V<sub>DD</sub> and EV<sub>DD</sub> pins to an output pin.
  - 2. Do not exceed the total current value.
  - **3.** Specification under conditions where the duty factor  $\leq 70\%$ .

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = (IoL × 0.7)/(n × 0.01)

<Example> Where n = 80% and IoL = 40.0 mA

Total output current of pins =  $(40.0 \times 0.7)/(80 \times 0.01) \cong 35.0 \text{ mA}$ 

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

(3/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1 P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147  VIH2 P10, P11, P15, P16  VIH3 P20, P21  VIH4 P60, P61  VIH5 P121 to P124, P137, EXCLK, EXCLK P10 to P54, P70 to P74, P120, P125 to P127, P140 to P147  VIL2 P10, P11, P15, P16  VIL2 P10, P11, P15, P16	Normal input buffer	0.8EV <sub>DD</sub>		EV <sub>DD</sub>	V	
	V <sub>IH2</sub>	P10, P11, P15, P16	TTL input buffer $4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$	2.2		EV <sub>DD</sub>	V
			TTL input buffer $3.3 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}$	2.0		EV <sub>DD</sub>	V
			TTL input buffer $2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V}$	1.50		EV <sub>DD</sub>	V
	V <sub>IH3</sub>	P20, P21		0.7V <sub>DD</sub>		V <sub>DD</sub>	V
	V <sub>IH4</sub> P60, P61		0.7EV <sub>DD</sub>		EV <sub>DD</sub>	V	
	V <sub>IH5</sub>	P121 to P124, P137, EXCLK, EXCLKS	S, RESET	0.8V <sub>DD</sub>		EVDD \\ EVDD \\ EVDD \\ VDD \\ VDD \\ VDD \\ 0.2EVDD \\ 0.32 \\ 0.3VDD \\	V
Input voltage, low	V <sub>IL1</sub>	P50 to P54, P70 to P74, P120,	Normal input buffer	0		0.2EV <sub>DD</sub>	V
	V <sub>IL2</sub>	P10, P11, P15, P16	TTL input buffer 4.0 V ≤ EV <sub>DD</sub> ≤ 5.5 V	0		0.8	V
			TTL input buffer $3.3 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}$	0		0.5	V
			TTL input buffer $2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}$	0		0.32	V
	V <sub>IL3</sub>	P20, P21	0		0.3V <sub>DD</sub>	V	
	V <sub>IL4</sub>	P60, P61		0		0.3EV <sub>DD</sub>	V
	VIL5	P121 to P124, P137, EXCLK, EXCLKS	RESET	0		0.2V <sub>DD</sub>	V

Caution The maximum value of VIH of pins P10, P12, P15, and P17 is EVDD, even in the N-ch open-drain mode.

(4/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	V <sub>OH1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OH1}} = -3.0 \text{ mA}$	EV <sub>DD</sub> – 0.7			V
		P125 to P127, P130, P140 to P147	$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OH1}} = -2.0 \text{ mA}$	EV <sub>DD</sub> – 0.6			V
			$2.4 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ Iон1 = $-1.5 \text{ mA}$	EV <sub>DD</sub> – 0.5			V
	V <sub>OH2</sub>	P20, P21	$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH2} = -100 \ \mu \text{ A}$	V <sub>DD</sub> - 0.5			V
Output voltage,	V <sub>OL1</sub>	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL1}} = 8.5 \text{ mA}$			0.7	V
		P125 to P127, P130, P140 to P147	$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL1}} = 3.0 \text{ mA}$			0.6	V
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL1}} = 1.5 \text{ mA}$			0.4	V
			$2.4~V \leq EV_{DD} \leq 5.5~V,$ $I_{OL1} = 0.6~mA$			0.4	V
	V <sub>OL2</sub>	P20, P21	$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $\text{I}_{OL2} = 400 \ \mu \text{ A}$			0.4	V
	Vol3	P60, P61	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL3}} = 15.0 \text{ mA}$			2.0	V
			$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL3}} = 5.0 \text{ mA}$			0.4	V
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL3}} = 3.0 \text{ mA}$			0.4	V
			$2.4 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ $I_{\text{OL3}} = 2.0 \text{ mA}$			0.4	V

Caution P10, P12, P15, and P17 do not output high level in N-ch open-drain mode.

(5/5)

Items	Symbol	Conditio	ns		MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ішнт	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	VI = EVDD				1	μA
	ILIH2	P20, P21, P137, RESET	$V_{I} = V_{DD}$				1	μΑ
	Ішнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	V <sub>I</sub> = V <sub>DD</sub>	In input port or external clock input			1	μΑ
				In resonator connection			10	μА
Input leakage current, low	ILIL1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	Vı = EVss				-1	μA
	I <sub>LIL2</sub>	P20, P21, P137, RESET	Vı = Vss				-1	μA
	Ішз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = VSS	In input port or external clock input			-1	μΑ
				In resonator connection			-10	μА
On-chip pll-up	R <sub>U1</sub>	V <sub>I</sub> = EV <sub>SS</sub>	SEGxx po	SEGxx port				
resistance			2.4 V ≤	$2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}$		20	100	kΩ
	Ru2			r than above r P60, P61, and	10	20	100	kΩ

# 3.3.2 Supply current characteristics

# (Ta = -40 to +105°C, 2.4 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

(1/3)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD1</sub>	Operating	HS (high-	f <sub>IH</sub> = 24 MHz Note 3	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current		mode	speed main) mode Note 5		operation	V <sub>DD</sub> = 3.0 V		1.5		mA
Note 1			mode		Normal	V <sub>DD</sub> = 5.0 V		3.3	5.3	mA
					operation	V <sub>DD</sub> = 3.0 V		3.3	5.3	mA
				f <sub>IH</sub> = 16 MHz Note 3	Normal	V <sub>DD</sub> = 5.0 V		2.5	3.9	mA
					operation	V <sub>DD</sub> = 3.0 V		2.5	3.9	mA
			HS (high-	f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> ,	Normal	Square wave input		2.8	4.7	mA
			speed main) mode Note 5	V <sub>DD</sub> = 5.0 V	operation	Resonator connection		3.0	4.8	mA
			mode	f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> ,	Normal	Square wave input		2.8	4.7	mA
				V <sub>DD</sub> = 3.0 V	operation	Resonator connection		3.0	4.8	mA
				f <sub>MX</sub> = 10 MHz <sup>Note 2</sup> ,	Normal	Square wave input		1.8	2.8	mA
				V <sub>DD</sub> = 5.0 V	operation	Resonator connection		1.8	2.8	mA
	1 1 1		$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$	Nomal	Square wave input		1.8	2.8	mA	
			V <sub>DD</sub> = 3.0 V	operation	Resonator connection		1.8	2.8	mA	
		Subsystem	fsuB = 32.768 kHz	Nomal	Square wave input		3.5	4.9	μA	
			clock operation	Note 4 T <sub>A</sub> = -40°C	operation	Resonator connection		3.6	5.0	μΑ
				fsuB = 32.768 kHz	Normal	Square wave input		3.6	4.9	μA
				Note 4	operation	Resonator connection		3.7	5.0	μA
				T <sub>A</sub> = +25°C						•
				fsub = 32.768 kHz	Normal	Square wave input		3.7	5.5	μΑ
				Note 4 T <sub>A</sub> = +50°C	operation	Resonator connection		3.8	5.6	μΑ
				fsub = 32.768 kHz	Normal	Square wave input		3.8	6.3	μA
				Note 4 T <sub>A</sub> = +70°C	operation	Resonator connection		3.9	6.4	μА
				fsuB = 32.768 kHz	Normal	Square wave input		4.1	7.7	μA
			Note 4	operation	Resonator connection		4.2	7.8	μA	
			T <sub>A</sub> = +85°C						•	
		fs			Square wave input		6.4	19.7	μА	
				Note 4 T <sub>A</sub> = +105°C	operation	Resonator connection		6.5	19.8	μΑ

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Total current flowing into V<sub>DD</sub> and EV<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub>, EV<sub>DD</sub> or Vss, EVss. The following points apply in the HS (high-speed main) mode.
  - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
  - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

- 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- 3. When high-speed system clock and subsystem clock are stopped.
- **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation).
- **5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @ 1 \text{ MHz}$  to 24 MHz  $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @ 1 \text{ MHz}$  to 16 MHz

Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

- 2. fin: High-speed on-chip oscillator clock frequency
- 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

<R>

# (Ta = -40 to +105°C, 2.4 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

(2/3)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub>	HALT	HS (high-	fiH = 24 MHz Note 4	V <sub>DD</sub> = 5.0 V		0.44	2.3	mA
current Note 1	IDD2 Note 2 HALT mode HS (high- speed main) mode Note 6  HS (high- speed main) mode Note 6  Subsystem clock operation  IDD3 STOP modeNote 7 TA = -40°C TA = +25°C		V <sub>DD</sub> = 3.0 V		0.44	2.3	mA		
Note 1			speed main) mode Note 6  HS (high-speed main) mode Note 6  Subsystem clock operation  TA = -40°C  TA = +25°C	fiH = 16 MHz Note 4	V <sub>DD</sub> = 5.0 V		0.40	1.7	mA
					V <sub>DD</sub> = 3.0 V		0.40	1.7	mA
			, σ	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		0.28	1.9	mA
			mode Note 6	V <sub>DD</sub> = 5.0 V	Resonator connection		0.45	2.0	mA
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		0.28	1.9	mA
				V <sub>DD</sub> = 3.0 V	Resonator connection		0.45	2.0	mA
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		0.19	1.02	mA
				V <sub>DD</sub> = 5.0 V	Resonator connection		0.26	1.10	mA
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		0.19	1.02	mA
				V <sub>DD</sub> = 3.0 V	Resonator connection		0.26	1.10	mA
			,	fsuB = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.31	0.57	μΑ
		T <sub>A</sub> = -40°C	Resonator connection		0.50	0.76	μΑ		
		fsuB = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.37	0.57	μΑ		
				T <sub>A</sub> = +25°C	Resonator connection		0.56	0.76	μА
			ı	fsuB = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.46	1.17	μΑ
				T <sub>A</sub> = +50°C	Resonator connection		0.65	1.36	μА
				fsuB = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.57	1.97	μА
				T <sub>A</sub> = +70°C	Resonator connection		0.76	2.16	μА
				f <sub>SUB</sub> = 32.768 kHz <sup>Note 5</sup>	Square wave input		0.85	3.37	μА
				T <sub>A</sub> = +85°C	Resonator connection		1.04	3.56	μА
				fsuB = 32.768 kHz <sup>Note 5</sup>	Square wave input		3.04	15.37	μΑ
				T <sub>A</sub> = +105°C	Resonator connection		3.23	15.56	μΑ
	IDD3	-	T <sub>A</sub> = -40°C				0.17	0.50	μΑ
	$\begin{tabular}{ll} mode^{Note  7} & $T_A = +25^\circ C$ \\ \hline $T_A = +50^\circ C$ \\ \hline $T_A = +70^\circ C$ \\ \hline $T_A = +85^\circ C$ \\ \hline \end{tabular}$				0.23	0.50	μΑ		
		T <sub>A</sub> = +50°C				0.32	1.10	μΑ	
			T <sub>A</sub> = +70°C				0.43	1.90	μΑ
		T <sub>A</sub> = +85°C	-85°C			0.71	3.30	μΑ	
			T <sub>A</sub> = +105°C				2.90	15.30	μΑ

(Notes and Remarks are listed on the next page.)





- **Notes 1.** Total current flowing into V<sub>DD</sub> and EV<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub>, EV<sub>DD</sub> or Vss, EVss. The following points apply in the HS (high-speed main) mode.
  - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
  - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC

In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- 4. When high-speed system clock and subsystem clock are stopped.
- **5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1).
- **6.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode: 2.7 V ≤ V<sub>DD</sub> ≤ 5.5 V@1 MHz to 24 MHz

 $2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V@1 MHz}$  to 16 MHz

- 7. Regarding the value for current operate the subsystem clock in STOP mode, refer to that in HALT mode.
- **Remarks 1.** f<sub>MX</sub>: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C

(3/3)

•			*	<u> </u>				
Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on- chip oscillator operating current	<sub>FIL</sub> Note 1					0.20		μΑ
RTC operating current	IRTC Notes 1, 2, 3	fmain is stopped				0.08		μΑ
12-bit interval timer current	l <sub>IT</sub> Notes 1, 2, 4					0.08		μΑ
Watchdog timer operating current	I <sub>WDT</sub> Notes 1, 2, 5	fı∟ = 15 kHz				0.24		μΑ
A/D converter	IADC	When conversion		$AV_{REFP} = V_{DD} = 5.0 V$		1.3	1.7	mA
operating current	Notes 1, 6	at maximum speed	Low voltage mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 3.0 V			0.5	0.7	mA
A/D converter reference voltage current	ladref Note 1				75.0		μΑ	
Temperature sensor operating current	ITMPS Note 1				75.0		μΑ	
LVD operating current	ILVD Notes 1, 7				0.08		μΑ	
Self- programming operating current	FSP Notes 1, 9					2.50	12.20	mA
BGO operating current	BGO Notes 1, 8					2.50	12.20	mA
LCD operating current	ILCD1 Notes 11, 12	External resistance	division method	V <sub>DD</sub> = EV <sub>DD</sub> = 5.0 V V <sub>L4</sub> = 5.0 V		0.04	0.20	μА
	ILCD2	Internal voltage boo	osting method	$V_{DD} = EV_{DD} = 5.0 \text{ V}$ $V_{L4} = 5.1 \text{ V (VLCD} = 12\text{H)}$		1.12	3.70	μA
				$V_{DD} = EV_{DD} = 3.0 \text{ V}$		0.63	2.20	μΑ
			V <sub>L4</sub> = 3.0 V (VLCD = 04H)					
	ILCD3 Note 11	Capacitor split met	thod $V_{DD} = EV_{DD} = 3.0 \text{ V}$ $V_{L4} = 3.0 \text{ V}$			0.12	0.50	μΑ
SNOOZE	I <sub>SNOZ</sub> Note 1	ADC operation	The mode is performed Note 10			0.50	1.10	mA
operating current			The A/D conversion performed, Low votes 3.0 V		1.20	2.04	mA	
		Simplified SPI (CSI				0.70	1.54	mA
	×							

(Notes and Remarks are listed on the next page.)

#### Notes 1. Current flowing to VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
- 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer is in operation.
- **6.** Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
- 8. Current flowing only during data flash rewrite.
- 9. Current flowing only during self programming.
- 10. For shift time to the SNOOZE mode.
- 11. Current flowing only to the LCD controller/driver. The supply current value of the RL78 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1 or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel.

The TYP. value and MAX. value are following conditions.

- When fsuB is selected for system clock, LCD clock = 128 Hz (LCDC0 = 07H)
- 4-Time-Slice, 1/3 Bias Method
- **12.** Not including the current that flows through the external divider resistor when the external resistance division method is used.

#### Remarks 1. fil: Low-speed on-chip oscillator clock frequency

- 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- 3. fclk: CPU/peripheral hardware clock frequency
- 4. Temperature condition of the TYP. value is TA = 25°C

# 3.4 AC Characteristics

# 3.4.1 Basic operation

(Ta = -40 to +105°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, Vss = EVss = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Tcy	Main	HS (high-speed	$2.7 \text{ V} \le V_{DD} \le 5.5 \text{ V}$	0.04167		1	μS
instruction execution time)		system clock (f <sub>MAIN</sub> ) operation	main) mode	2.4 V ≤ V <sub>DD</sub> < 2.7 V	0.0625		1	μs
		Subsystem of operation	clock (fsub)	$2.4 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	28.5	30.5	31.3	μS
		In the self	HS (high-speed	$2.7~V \le V_{DD} \le 5.5~V$	0.04167		1	μS
		programming mode	main) mode	$2.4 \text{ V} \le \text{V}_{DD} \le 2.7 \text{ V}$	0.0625		1	μS
External system clock frequency	fex	2.7 V ≤ V <sub>DD</sub> ≤	5.5 V		1.0		20.0	MHz
		$2.4 \text{ V} \leq \text{V}_{DD} \leq$	2.7 V		1.0		16.0	MHz
	fexs				32		35	kHz
External system clock input high-	texh, texl	2.7 V ≤ V <sub>DD</sub> ≤	5.5 V		24			ns
level width, low-level width		2.4 V ≤ V <sub>DD</sub> < 2.7 V			30			ns
	texhs, texhs				13.7			μS
TI00 to TI07 input high-level width, low-level width	tтін, tтіL				1/fмск+10			ns
TO00 to TO07 output frequency	fто	HS (high-spe	ed 4.0 V	$\leq$ EV <sub>DD</sub> $\leq$ 5.5 V			16	MHz
		main) mode	2.7 V	≤ EV <sub>DD</sub> < 4.0 V			8	MHz
			2.4 V	≤ EV <sub>DD</sub> < 2.7 V			4	MHz
PCLBUZ0, PCLBUZ1 output	<b>f</b> PCL	HS (high-spe	ed 4.0 V	$\leq$ EV <sub>DD</sub> $\leq$ 5.5 V			16	MHz
frequency		main) mode	2.7 V	≤ EV <sub>DD</sub> < 4.0 V			8	MHz
			2.4 V	≤ EV <sub>DD</sub> < 2.7 V			4	MHz
Interrupt input high-level width,	tinth,	INTP0	2.4 V	$\leq V_{DD} \leq 5.5 \text{ V}$	1			μS
low-level width	<b>t</b> intl	INTP1 to INT	P7 2.4 V	$\leq$ EV <sub>DD</sub> $\leq$ 5.5 V	1			μS
Key interrupt input low-level width	<b>t</b> kr	KR0 to KR3	2.4 V	$\leq$ EV <sub>DD</sub> $\leq$ 5.5 V	250			ns
RESET low-level width	trsl				10			μS

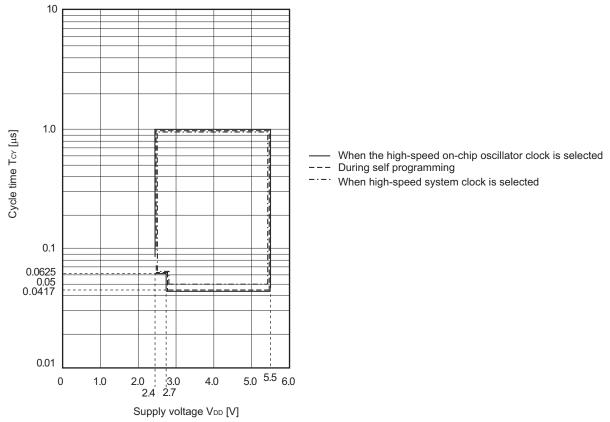
Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n).

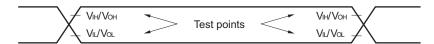
n: Channel number (n = 0 to 7))

# Minimum Instruction Execution Time during Main System Clock Operation

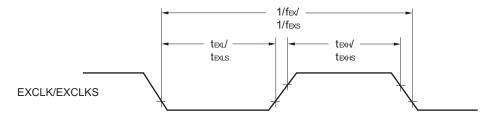
Tcy vs VDD (HS (high-speed main) mode)



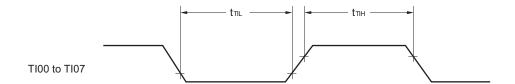
# **AC Timing Test Points**

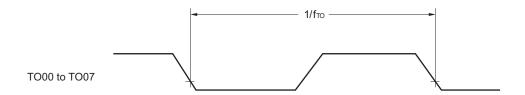


# **External System Clock Timing**

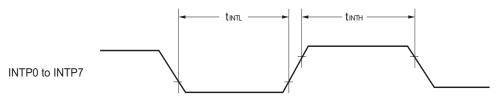


# **TI/TO Timing**

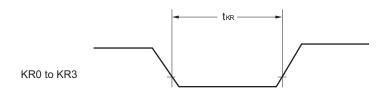




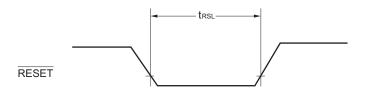
# **Interrupt Request Input Timing**



# **Key Interrupt Input Timing**

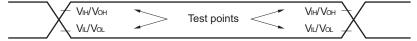


# **RESET** Input Timing



### 3.5 Peripheral Functions Characteristics

#### **AC Timing Test Points**



# 3.5.1 Serial array unit

#### (1) During communication at same potential (UART mode)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
Transfer rate Note 1				fмск/12	bps
		Theoretical value of the maximum transfer rate f <sub>MCK</sub> = f <sub>CLK</sub> Note 2		2.0	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

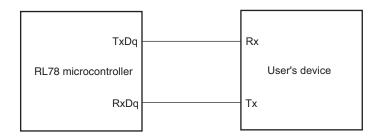
HS (high-speed main) mode:

24 MHz (2.7 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

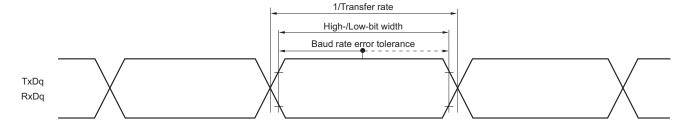
16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

### **UART** mode connection diagram (during communication at same potential)



# UART mode bit width (during communication at same potential) (reference)



**Remarks 1.** q: UART number (q = 0), g: PIM and POM number (g = 1)

2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

# (2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions		HS (high-speed main) Mode		Unit
				MIN.	MAX.	
SCKp cycle time tkcY1		$2.7~V \leq EV_{DD} \leq 5.5~V$		334 Note 1		ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$		500 Note 1		ns
SCKp high-/low-level width	<b>t</b> кн1,	$4.0~V \leq EV_{DD} \leq 5.5~V$		tkcy1/2 - 24		ns
	<b>t</b> KL1	$2.7~V \leq EV_{DD} \leq 5.5~V$		tkcy1/2 - 36		ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$		tkcy1/2 - 76		ns
SIp setup time (to SCKp↑) Note 2 tsik1		$2.7~\text{V} \leq \text{EV}_{\text{DD}} \leq 5.5~\text{V}$		66		ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$		113		ns
SIp hold time (from SCKp↑) Note 3	t <sub>KSI1</sub>	$2.4~V \leq EV_{DD} \leq 5.5~V$		38		ns
Delay time from SCKp↓ to SOp output Note 4	tkso1	C = 30 pF Note 5	$2.4~V \leq EV_{DD} \leq 5.5~V$		50	ns

#### Notes 1. Set a cycle of 4/fmck or longer.

- 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. C is the load capacitance of the SCKp and SOp output lines.

# Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

**Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM numbers (g = 1)

2. fmcκ: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

## (3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

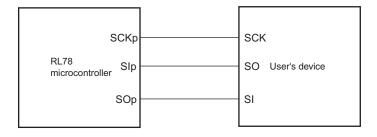
Parameter	Symbol	Cond	ditions	HS (high-spee	d main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time Note 5	tkcy2	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$	20 MHz < f <sub>MCK</sub>	16/fмск		ns
			fмcк ≤ 20 MHz	12/fмск		ns
		2.7 V ≤ EV <sub>DD</sub> < 4.0 V	16 MHz < f <sub>MCK</sub>	16/fмск		ns
			fмcк ≤ 16 MHz	12/fмск		ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$	2.4 V ≤ EV <sub>DD</sub> ≤ 5.5 V			ns
SCKp high-/low-level	t <sub>KH2</sub> ,	$4.0~V \leq EV_{DD} \leq 5.5~V$		tксү2/2 – 14		ns
width	t <sub>KL2</sub>	$2.7 \text{ V} \leq \text{EV}_{DD} \leq 4.0 \text{ V}$		tксү2/2 – 16		ns
		$2.4 \text{ V} \leq \text{EV}_{DD} < 2.7 \text{ V}$		tkcy2/2 - 36		ns
SIp setup time	tsik2	$2.7~V \leq EV_{DD} \leq 5.5~V$		1/f <sub>MCK</sub> + 40		ns
(to SCKp↑) Note 1		$2.4 \text{ V} \leq \text{EV}_{DD} < 2.7 \text{ V}$		1/fмск + 60		ns
SIp hold time (from SCKp↑) Note 2	tksi2	$2.4~V \leq EV_{DD} \leq 5.5~V$		1/fмск + 62		ns
Delay time from SCKp↓	tkso2	C = 30 pF Note 4	$4.0~V \le EV_{DD} \le 5.5~V$		2/fmck + 66	ns
to SOp output Note 3			$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$		2/f <sub>MCK</sub> + 66	ns
			$2.4 \text{ V} \le \text{EV}_{DD} \le 2.7 \text{ V}$		2/fмcк+ 113	Ns

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp $\downarrow$ " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

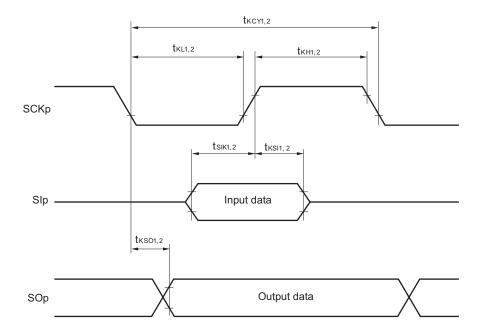
# Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM number (g = 1)
  - 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

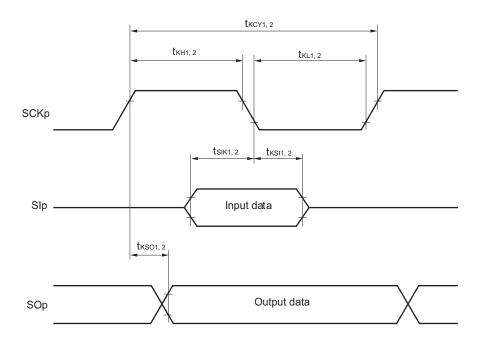
#### Simplified SPI (CSI) mode connection diagram (during communication at same potential)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remarks 1.** p: CSI number (p = 00, 01)

2. m: Unit number, n: Channel number (mn = 00, 01)

# (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (1/2) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \leq \text{EV}_{DD} = \text{V}_{DD} \leq 5.5 \text{ V}, \text{Vss} = \text{EVss} = 0 \text{ V})$

Parameter	Symbol		Conditio	ns	HS (high-spee	ed main) Mode	Unit
					MIN.	MAX.	
Transfer rate		Reception	$4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V},$			fmck/12 Note 1	bps
		2.7 V ≤ V <sub>b</sub> ≤ 4.0 V		Theoretical value of the maximum transfer rate fmck = fclk Note 2		2.0	Mbps
						fmck/12 Note 1	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate fmck = fclk Note 2		2.0	Mbps
		2.4 V ≤ EV <sub>DD</sub> < 3.3 V,			fмск/12 Note 1	bps	
			$1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate f <sub>MCK</sub> = f <sub>CLK</sub> Note 2		2.0	Mbps

- Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.
  - 2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 24 MHz (2.7 V  $\leq$  VDD  $\leq$  5.5 V)

16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (Vpd tolerance (32- to 52-pin products)/EVpd tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For Vih and Vil, see the DC characteristics with TTL input buffer selected.

- Remarks 1. V<sub>b</sub>[V]: Communication line voltage
  - **2.** q: UART number (q = 0), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)

## (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) ( $T_A = -40$ to +105°C, 2.4 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

(2/2)

Parameter	Symbol		Condit	ions	HS (high-spee	ed main) Mode	Unit
					MIN.	MAX.	
Transfer rate		Transmission	$4.0~V \le EV_{DD} \le 5.5~V,$			Note 1	bps
			$2.7~V \leq V_b \leq 4.0~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}$ , $R_b = 1.4 \text{ k}\Omega$ , $V_b = 2.7 \text{ V}$		2.0 Note 2	Mbps
			2.7 V ≤ EV <sub>DD</sub> < 4.0 V,	00 - 30 pr , 100 - 1.4 kgz, vb - 2.7 v		Note 3	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate		1.2 Note 4	Mbps
				$C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega, V_b = 2.3 \text{ V}$			
			$2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V},$			Note 5	bps
			$1.6~V \le V_b \le 2.0~V$	Theoretical value of the maximum transfer rate		0.43 Note 6	Mbps
				$C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$			

**Notes 1.** The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when  $4.0~V \le EV_{DD} \le 5.5~V$  and  $2.7~V \le V_{b} \le 4.0~V$ 

$$\label{eq:maximum transfer rate} \begin{aligned} & \frac{1}{\{-C_b \times R_b \times \text{ln } (1-\frac{2.2}{V_b})\} \times 3} \end{aligned} \text{[bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{2.2}{V_b})}\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **2.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.
- 3. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V  $\leq$  EV<sub>DD</sub> < 4.0 V and 2.3 V  $\leq$  V<sub>b</sub>  $\leq$  2.7 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \text{ln } (1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **4.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.

**5.** The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V  $\leq$  EV<sub>DD</sub> < 3.3 V and 1.6 V  $\leq$  V<sub>b</sub>  $\leq$  2.0 V

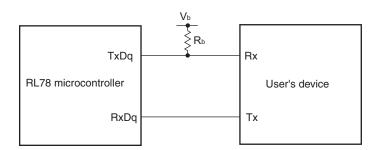
$$\label{eq:maximum transfer rate} \text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \text{ln } (1-\frac{1.5}{V_b})\} \times 3} \text{[bps]}$$

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \, [\%]$$

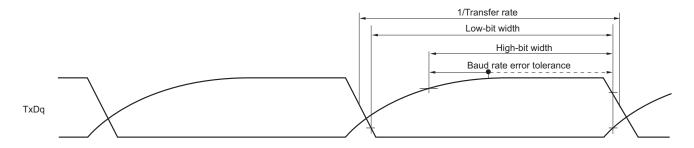
- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- **6.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 5 above to calculate the maximum transfer rate under conditions of the customer.

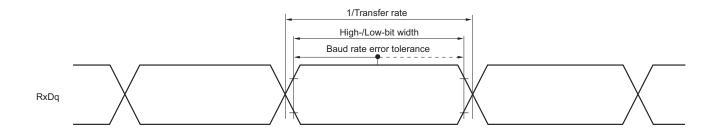
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (Vpb tolerance (32- to 52-pin products)/EVpb tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For Vih and Vil, see the DC characteristics with TTL input buffer selected.

**UART** mode connection diagram (during communication at different potential)



#### UART mode bit width (during communication at different potential) (reference)





- Remarks 1.  $R_b[\Omega]$ :Communication line (TxDq) pull-up resistance,  $C_b[F]$ : Communication line (TxDq) load capacitance,  $V_b[V]$ : Communication line voltage
  - **2.** q: UART number (q = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	HS (high-speed	l main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time	t <sub>KCY1</sub>	tkcy1 ≥ 4/fclk	$4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \;$	600		ns
			$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
			$2.7 \; \text{V} \leq \text{EV}_{\text{DD}} < 4.0 \; \text{V}, \; 2.3 \; \text{V} \leq \text{V}_{\text{b}} \leq 2.7 \; \text{V}, \label{eq:equation_var}$	600		ns
			$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
			$2.4 \text{ V} \le \text{EV}_{DD} \le 3.3 \text{ V}, \ 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	2300		ns
			$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			
SCKp high-level width	t <sub>KH1</sub>	4.0 V ≤ EV <sub>DD</sub>	$\leq 5.5 \; V,  2.7 \; V \leq V_b \leq 4.0 \; V,$	tkcy1/2 - 150		ns
		C <sub>b</sub> = 30 pF, R	$R_b = 1.4 \text{ k}\Omega$			
		2.7 V ≤ EV <sub>DD</sub>	$< 4.0 \ V, \ 2.3 \ V \le V_b \le 2.7 \ V,$	tксү1/2 – 340		ns
		C <sub>b</sub> = 30 pF, R	$R_b = 2.7 \text{ k}\Omega$			
		2.4 V ≤ EV <sub>DD</sub>	< 3.3 V, 1.6 V $\leq$ V <sub>b</sub> $\leq$ 2.0 V,	tксү1/2 – 916		ns
		C <sub>b</sub> = 30 pF, R	$R_b = 5.5 \text{ k}\Omega$			
SCKp low-level width	t <sub>KL1</sub>	$4.0 \text{ V} \leq \text{EV}_{\text{DD}}$	$\leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V,$	tkcy1/2 - 24		ns
		C <sub>b</sub> = 30 pF, R	$R_b = 1.4 \text{ k}\Omega$			
		2.7 V ≤ EV <sub>DD</sub>	$< 4.0 \text{ V}, 2.3 \text{ V} \le V_b \le 2.7 \text{ V},$	tkcy1/2 - 36		ns
		C <sub>b</sub> = 30 pF, R	$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$ 2.4 V $\leq$ EV <sub>DD</sub> $< 3.3 \text{ V}, 1.6 \text{ V} \leq$ V <sub>b</sub> $\leq$ 2.0 V,			
		2.4 V ≤ EV <sub>DD</sub>				ns
		C <sub>b</sub> = 30 pF, R	$R_b = 5.5 \text{ k}\Omega$			

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32- to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

# (5) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/2)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

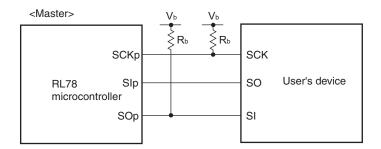
Parameter	Symbol	Conditions	HS (high-spe	ed main) Mode	Unit
			MIN.	MAX.	
SIp setup time	tsik1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$	162		ns
(to SCKp↑) Note 1		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, \ 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	354		ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	958		ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			
SIp hold time	<b>t</b> KSI1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, \ 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$	38		ns
(from SCKp↑) Note 1		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, \ 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	38		ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	38		ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			
Delay time from SCKp↓ to	tkso1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, \ 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$		200	ns
Op output Note 1		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, \ 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$		390	ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \le \text{EV}_{DD} \le 3.3 \text{ V}, \ 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$		966	ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
SIp setup time	tsık1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, \ 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$	88		ns
(to SCKp↓) Note		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	88		ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \le \text{EV}_{DD} \le 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	220		ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			
SIp hold time	t <sub>KSI1</sub>	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$	38		ns
(from SCKp↓) Note 2		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, \ 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$	38		ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \le \text{EV}_{DD} \le 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$	38		ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			
Delay time from SCKp↑ to	tkso1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$		50	ns
SOp output Note 2		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$		50	ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$		50	ns
		$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			

(Notes, Caution and Remarks are listed on the page after the next page.)

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
  - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

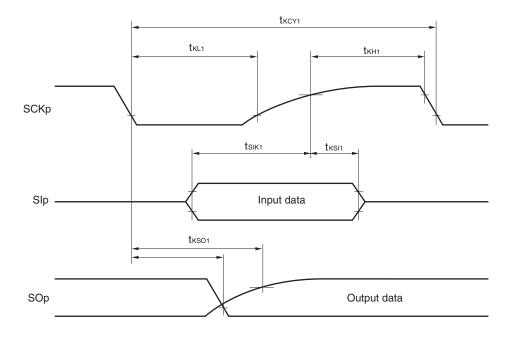
Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32- to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

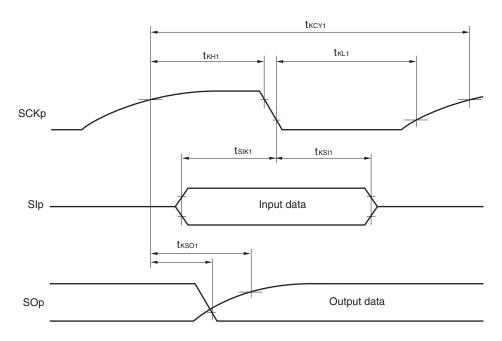


- **Remarks 1.**  $R_b[\Omega]$ :Communication line (SCKp, SOp) pull-up resistance,
  - $C_b[F]: Communication \ line \ (SCKp, SOp) \ load \ capacitance, \ V_b[V]: Communication \ line \ voltage$
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency
    (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

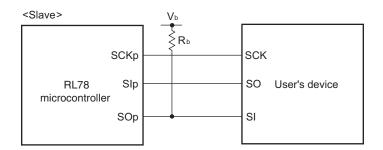
Parameter	Symbol	(	Conditions	HS (high-spee	ed main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time Note 1	tkcy2	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	24/fмск		ns
		$2.7 \ V \leq V_b \leq 4.0 \ V$	$8 \text{ MHz} < f_{\text{MCK}} \le 20 \text{ MHz}$	20/fмск		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	16/fмск		ns
			fмcк ≤ 4 MHz	12/fмск		ns
		$2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V},$	20 MHz < fмcк ≤ 24 MHz	32/fмск		ns
		$2.3 \ V \leq V_b \leq 2.7 \ V$	16 MHz < fмcк ≤ 20 MHz	28/fмск		ns
			8 MHz < fмcк ≤ 16 MHz	24/fмск		ns
			4 MHz < fmck ≤ 8 MHz	16/fмск		ns
			fмcк ≤ 4 MHz	12/fмск		ns
		$2.4 \text{ V} \le \text{EV}_{DD} \le 3.3 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	72/fмск		ns
		$1.6 \ V \leq V_b \leq 2.0 \ V$	16 MHz < f <sub>MCK</sub> ≤ 20 MHz	64/fмск		ns
			$8 \text{ MHz} < f_{\text{MCK}} \le 16 \text{ MHz}$	<b>52/f</b> мск		ns
			4 MHz < $f_{MCK} \le 8$ MHz	32/fмск		ns
			fmck ≤ 4 MHz	20/fмск		ns
SCKp high-/low-level width	t <sub>KH2</sub> ,	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$	V,	tkcy2/2 - 24		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$	V,	tkcy2/2 - 36		ns
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$	V,	tkcy2/2 - 100		ns
SIp setup time (to SCKp↑) Note2	tsik2	$4.0 \text{ V} \le \text{EV}_{DD} < 5.5$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$	V,	1/fмск + 40		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$	V,	1/fмск + 40		ns
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$	V,	1/fмск + 60		ns
Slp hold time (from SCKp↑) Note 3	tksi2	$4.0 \text{ V} \le \text{EV}_{DD} < 5.5$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$	V,	1/fмск + 62		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$	V,	1/fмск + 62		ns
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$	V,	1/fмск + 62		ns
Delay time from SCKp↓ to SOp output Note 4	tkso2	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5$ $C_b = 30 \text{ pF}, R_b = 1.4$	$V, 2.7 V \le V_b \le 4.0 V,$ $4 k\Omega$		2/fмск + 240	ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0$ $C_b = 30 \text{ pF}, R_b = 2.$	$V, 2.3 \ V \le V_b \le 2.7 \ V,$ $7 \ k\Omega$		2/fmck + 428	ns
		$2.4 \text{ V} \le \text{EV}_{DD} < 3.3$ $C_b = 30 \text{ pF}, R_b = 5.9$	$V$ , 1.6 $V \le V_b \le 2.0 V$ 5 $kΩ$		2/fмск + 1146	ns

(Notes, Caution and Remarks are listed on the page after the next page.)

- Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

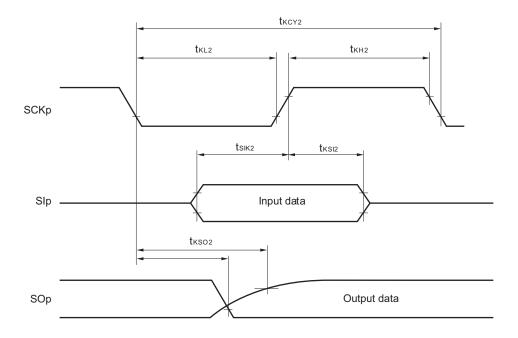
Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance (32- to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

#### Simplified SPI (CSI) mode connection diagram (during communication at different potential)

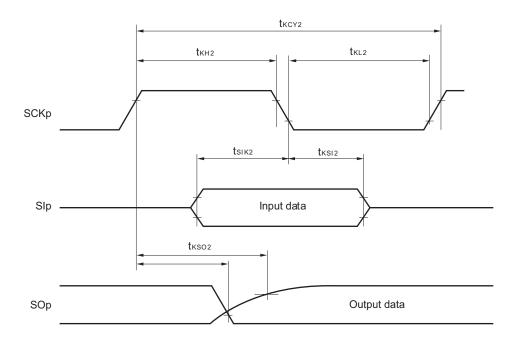


- **Remarks 1.**  $R_b[\Omega]$ :Communication line (SOp) pull-up resistance,
  - Cb[F]: Communication line (SOp) load capacitance, Vb[V]: Communication line voltage
  - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 01), m: Unit number (m = 0),

n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

#### 3.5.2 Serial interface IICA

#### (1) I<sup>2</sup>C standard mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Co	nditions	HS (high-spe	ed main) Mode	Unit
				MIN.	MAX.	
SCLA0 clock frequency	fscL	Standard mode:	$2.7~V \leq EV_{DD} \leq 5.5~V$	0	100	kHz
		fclk ≥ 1 MHz	$2.4~V \leq EV_{DD} \leq 5.5~V$	0	100	kHz
Setup time of restart condition	tsu:sta	$2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	4.7		μS
		$2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	4.7		μS
Hold time <sup>Note 1</sup>	thd:sta	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	4.0		μS
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	4.0		μS
Hold time when SCLA0 = "L"	tLOW	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	4.7		μS
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	$2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$			μS
Hold time when SCLA0 = "H"	thigh	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	4.0		μS
		$2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	4.0		μS
Data setup time (reception)	tsu:dat	$2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	250		ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	250		ns
Data hold time (transmission)Note 2	thd:dat	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	0	3.45	μS
		$2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	0	3.45	μS
Setup time of stop condition	tsu:sto	$2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	4.0		μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.	5 V	4.0		μS
Bus-free time	<b>t</b> BUF	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.$	5 V	4.7		μS
		$2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$	5 V	4.7		μS

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
  - 2. The maximum value (MAX.) of the Deat is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode:  $C_b = 400 \text{ pF}, R_b = 2.7 \text{ k}\Omega$ 

#### (2) I<sup>2</sup>C fast mode

## (Ta = -40 to +105°C, 2.4 V $\leq$ EV<sub>DD</sub> = V<sub>DD</sub> $\leq$ 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol	Co	nditions	HS (high-spee	ed main) Mode	Unit
				MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode:	$2.7~V \leq EV_{DD} \leq 5.5~V$	0	400	kHz
		fc∟κ≥ 3.5 MHz	$2.4~V \leq EV_{DD} \leq 5.5~V$	0	400	
Setup time of restart condition	tsu:sta	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		
Hold time Note 1	thd:sta	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		μs
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		
Hold time when SCLA0 = "L"	tLOW	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	1.3		μS
		$2.4 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$		1.3		
Hold time when SCLA0 = "H"	thigh	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		
Data setup time (reception)	tsu:dat	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	100		ns
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	100		
Data hold time (transmission)Note 2	thd:dat	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0	0.9	μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0	0.9	
Setup time of stop condition	tsu:sto	2.7 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		μs
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	0.6		1
Bus-free time	<b>t</b> BUF	$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$		1.3		μS
		2.4 V ≤ EV <sub>DD</sub> ≤ 5.5	5 V	1.3		

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
  - 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode:  $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$ 

#### 3.6 Analog Characteristics

#### 3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

		Reference Voltage					
	Reference voltage (+) = AVREFP	Reference voltage (+) = V <sub>DD</sub>	Reference voltage (+) = V <sub>BGR</sub>				
Input channel	Reference voltage (-) = AVREFM	Reference voltage (-) = Vss	Reference voltage (-) = AVREFM				
ANIO, ANI1	-	Refer to <b>3.6.1 (3)</b> .	Refer to <b>3.6.1 (4)</b> .				
ANI16 to ANI23	Refer to 3.6.1 (2).						
Internal reference voltage Temperature sensor output voltage	Refer to <b>3.6.1 (1)</b> .		-				

(1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \leq \text{EV}_{DD} = \text{V}_{DD} \leq 5.5 \text{ V}, 2.4 \text{ V} \leq \text{AV}_{REFP} \leq \text{V}_{DD} \leq 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Parameter	Symbol	Condition	ns	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$2.4~V \le AV_{REFP} \le 5.5~V$		1.2	±3.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μS
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	1.8 V ≤ AVREFP ≤ 5.5 V			±0.25	%FSR
Full-scale errorNotes 1, 2	Ers	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.8~V \le AV_{REFP} \le 5.5~V$			±0.25	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}$			±2.5	LSB
Differential linearity error	DLE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3	$1.8~V \le AV_{REFP} \le 5.5~V$			±1.5	LSB
Analog input voltage	Vain	Internal reference voltage (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (high-s	speed main) mode)		V <sub>BGR</sub> Note 4		V
		Temperature sensor output volt (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (high-s		V <sub>TMPS25</sub> Note	4	V	

- **Notes 1.** Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - **3.** When AV<sub>REFP</sub> < V<sub>DD</sub>, the MAX. values are as follows.

Overall error: Add  $\pm 1.0$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Zero-scale error/Full-scale error: Add  $\pm 0.05\%$  FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Integral linearity error/ Differential linearity error: Add  $\pm 0.5$  LSB to the MAX. value when AVREFP = VDD.

4. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.



# (2) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : ANI16 to ANI23

(TA = -40 to +105°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, 2.4 V  $\leq$  AV<sub>REFP</sub>  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V, Reference voltage (+) = AV<sub>REFP</sub>, Reference voltage (-) = AV<sub>REFM</sub> = 0 V)

Parameter	Symbol	Condition	าร	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution  AV <sub>REFP</sub> = EV <sub>DD</sub> = V <sub>DD</sub> Note 3	$2.4~V \leq AV_{REFP} \leq 5.5~V$		1.2	±5.0	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
		$V_{REFP} = EV_{DD} = V_{DD}^{Note 3}$	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	10-bit resolution AV <sub>REFP</sub> = EV <sub>DD</sub> = V <sub>DD</sub> Note 3	$2.4~V \le AV_{REFP} \le 5.5~V$			±0.35	%FSR
Full-scale error <sup>Notes 1, 2</sup>	E <sub>F</sub> s	10-bit resolution AV <sub>REFP</sub> = EV <sub>DD</sub> = V <sub>DD</sub> Note 3	$2.4~V \le AV_{REFP} \le 5.5~V$			±0.35	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution  AV <sub>REFP</sub> = EV <sub>DD</sub> = V <sub>DD</sub> Note 3	$2.4~\text{V} \leq \text{AV}_{\text{REFP}} \leq 5.5~\text{V}$			±3.5	LSB
Differential linearity error	DLE	10-bit resolution  AV <sub>REFP</sub> = EV <sub>DD</sub> = V <sub>DD</sub> Note 3	$2.4~V \leq AV_{REFP} \leq 5.5~V$			±2.0	LSB
Analog input voltage	VAIN	ANI16 to ANI23		0		AVREFP and EVDD	V

#### Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When  $AV_{REFP} < EV_{DD} = V_{DD}$ , the MAX. values are as follows.

Overall error: Add  $\pm 4.0$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Zero-scale error/Full-scale error: Add  $\pm 0.20\%$  FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Integral linearity error/ Differential linearity error: Add  $\pm 2.0$  LSB to the MAX. value when AVREFP = VDD.

(3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>SS</sub> (ADREFM = 0), target pin : ANI0, ANI1, ANI16 to ANI23, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{V}_{DD}, \text{ Reference voltage (-)} = \text{V}_{SS})$ 

Parameter	Symbol	Condition	s	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$		1.2	±7.0	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
			$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μS
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
		10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.375		39	μS
		Target pin: Internal reference	$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μS
		voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Full-scale errorNotes 1, 2	Ers	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±4.0	LSB
Differential linearity error	DLE	10-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Analog input voltage	Vain	ANIO, ANI1		0		V <sub>DD</sub>	V
		ANI16 to ANI23		0		EV <sub>DD</sub>	V
		Internal reference voltage output (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (high-s			V <sub>BGR</sub> Note 3		V
		Temperature sensor output volt (2.4 V $\leq$ V <sub>DD</sub> $\leq$ 5.5 V, HS (high-s	0	\	V		

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : ANI0, ANI16 to ANI23

(TA = -40 to +105°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = EV<sub>SS</sub> = 0 V, Reference voltage (+) = V<sub>BGR</sub> Note 3, Reference voltage (-) = AV<sub>REFM</sub> Note 4 = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Cond	MIN.	TYP.	MAX.	Unit	
Resolution	RES				8		bit
Conversion time	tconv	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μS
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
Integral linearity errorNote 1	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	Vain			0		V <sub>BGR</sub> Note 3	V

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - 3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.
  - **4.** When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add  $\pm 0.35\%$  FSR to the MAX. value when reference voltage (–) = AVREFM.

Integral linearity error: Add ±0.5 LSB to the MAX. value when reference voltage (-) = AVREFM.

Differential linearity error: Add ±0.2 LSB to the MAX. value when reference voltage (–) = AVREFM.

## 3.6.2 Temperature sensor/internal reference voltage characteristics

(TA = -40 to +105°C, 2.4 V  $\leq$  EV<sub>DD</sub> = V<sub>DD</sub>  $\leq$  5.5 V, Vss = EVss = 0 V, HS (high-speed main) mode)

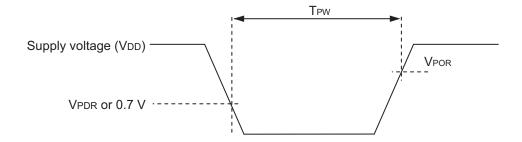
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V <sub>TMPS25</sub>	Setting ADS register = 80H, Ta = +25°C		1.05		٧
Internal reference voltage	V <sub>BGR</sub>	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μs

#### 3.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V <sub>POR</sub>	The power supply voltage is rising.	1.45	1.51	1.57	V
	V <sub>PDR</sub>	The power supply voltage is falling.	1.44	1.50	1.56	V
Minimum pulse width	Tpw		300			μs

Note Minimum time required for a POR reset when V<sub>DD</sub> exceeds below V<sub>PDR</sub>. This is also the minimum time required for a POR reset from when V<sub>DD</sub> exceeds below 0.7 V to when V<sub>DD</sub> exceeds V<sub>POR</sub> while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



#### 3.6.4 LVD circuit characteristics

(Ta = -40 to +105°C, VPDR  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	V <sub>LVD0</sub>	Power supply rise time	3.90	4.06	4.22	٧
voltage			Power supply fall time	3.83	3.98	4.13	٧
		V <sub>LVD1</sub>	Power supply rise time	3.60	3.75	3.90	V
			Power supply fall time	3.53	3.67	3.81	V
		V <sub>LVD2</sub>	Power supply rise time	3.01	3.13	3.25	V
			Power supply fall time	2.94	3.06	3.18	V
		V <sub>LVD3</sub>	Power supply rise time	2.90	3.02	3.14	V
			Power supply fall time	2.85	2.96	3.07	V
		V <sub>LVD4</sub>	Power supply rise time	2.81	2.92	3.03	V
			Power supply fall time	2.75	2.86	2.97	V
		V <sub>LVD5</sub>	Power supply rise time	2.70	2.81	2.92	٧
			Power supply fall time	2.64	2.75	2.86	V
		V <sub>LVD6</sub>	Power supply rise time	2.61	2.71	2.81	٧
			Power supply fall time	2.55	2.65	2.75	٧
		V <sub>LVD7</sub>	Power supply rise time	2.51	2.61	2.71	V
			Power supply fall time	2.45	2.55	2.65	V
Minimum pu	lse width	tLW		300			μS
Detection de	elay time					300	μs

#### LVD Detection Voltage of Interrupt & Reset Mode

(Ta = -40 to +105°C, VPDR  $\leq$  EVDD = VDD  $\leq$  5.5 V, Vss = EVss = 0 V)

Parameter	Symbol		Cond	ditions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	V <sub>LVDD0</sub>	VPOC2,	VPOC1, VPOC0 = 0, 1, 1,	2.64	2.75	2.86	V	
mode	V <sub>LVDD1</sub>		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.81	2.92	3.03	V
				Falling interrupt voltage	2.75	2.86	2.97	٧
	V <sub>LVDD2</sub>		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.90	3.02	3.14	V
				Falling interrupt voltage	2.85	2.96	3.07	V
	V <sub>LVDD3</sub>		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.90	4.06	4.22	V
				Falling interrupt voltage	3.83	3.98	4.13	V

#### 3.6.5 Power supply voltage rising slope characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V<sub>DD</sub> reaches the operating voltage range shown in 3.4 AC Characteristics.

#### 3.7 LCD Characteristics

#### 3.7.1 Resistance division method

#### (1) Static display mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le V_{DD}^{Note} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.0		$V_{DD}$	V

Note Must be 2.4 V or higher.

### (2) 1/2 bias method, 1/4 bias method

(TA = -40 to +105°C, V<sub>L4</sub> (MIN.)  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.7		V <sub>DD</sub>	V

#### (3) 1/3 bias method

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V <sub>L4</sub>		2.5		V <sub>DD</sub>	V

#### 3.7.2 Internal voltage boosting method

#### (1) 1/3 bias method

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Cond	itions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V <sub>L1</sub>	C1 to C4 <sup>Note 1</sup>	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 μF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	V <sub>L2</sub>	C1 to C4 <sup>Note 1</sup> =	0.47 μF	2 V <sub>L1</sub> -0.1	2 VL1	2 V <sub>L1</sub>	٧
Tripler output voltage	V <sub>L4</sub>	C1 to C4 <sup>Note 1</sup> =	0.47 μF	3 V <sub>L1</sub> -0.15	3 V <sub>L1</sub>	3 V <sub>L1</sub>	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait timeNote 3	tvwait2	C1 to C4 <sup>Note 1</sup> =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL4 and GND
- $C1 = C2 = C3 = C4 = 0.47 \mu F \pm 30\%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

#### (2) 1/4 bias method

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Cor	ditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V <sub>L1</sub> Note 4	C1 to C5 <sup>Note 1</sup>	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 μF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	V <sub>L2</sub>	C1 to C5 <sup>Note 1</sup> =	0.47 μF	2 V <sub>L1</sub> – 0.08	2 V <sub>L1</sub>	2 V <sub>L1</sub>	V
Tripler output voltage	V <sub>L3</sub>	C1 to C5 <sup>Note 1</sup> =	0.47 μF	3 V <sub>L1</sub> – 0.12	3 V <sub>L1</sub>	3 V <sub>L1</sub>	V
Quadruply output voltage	V <sub>L4</sub> Note 4	C1 to C5 <sup>Note 1</sup> =	0.47 μF	4 V <sub>L1</sub> – 0.16	4 V <sub>L1</sub>	4 V <sub>L1</sub>	V
Reference voltage setup time Note 2	tvwait1		·	5			ms
Voltage boost wait timeNote 3	tvwait2	C1 to C5 <sup>Note 1</sup> =	0.47 μF	500			ms

**Notes 1.** This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL3 and GND
- C5: A capacitor connected between  $V_{L4}$  and GND
- $C1 = C2 = C3 = C4 = C5 = 0.47 \mu F \pm 30\%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- 4. V<sub>L4</sub> must be 5.5 V or lower.

## 3.7.3 Capacitor split method

#### 1/3 bias method

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V <sub>L4</sub> voltage	V <sub>L4</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 2</sup>		$V_{DD}$		<b>V</b>
V <sub>L2</sub> voltage	V <sub>L2</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 2</sup>	2/3 V <sub>L4</sub> - 0.1	2/3 V <sub>L4</sub>	2/3 V <sub>L4</sub> + 0.1	V
V <sub>L1</sub> voltage	V <sub>L1</sub>	C1 to C4 = 0.47 $\mu$ F <sup>Note 2</sup>	1/3 V <sub>L4</sub> - 0.1	1/3 V <sub>L4</sub>	1/3 V <sub>L4</sub> + 0.1	٧
Capacitor split wait timeNote 1	tvwait		100			ms

Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).

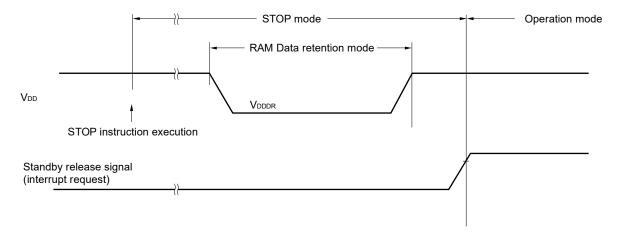
- 2. This is a capacitor that is connected between voltage pins used to drive the LCD.
  - C1: A capacitor connected between CAPH and CAPL
  - C2: A capacitor connected between VL1 and GND
  - C3: A capacitor connected between VL2 and GND
  - C4: A capacitor connected between VL4 and GND
  - $C1 = C2 = C3 = C4 = 0.47 \mu F \pm 30\%$

#### 3.8 RAM Data Retention Characteristics

#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 <sup>Note</sup>		5.5	V

**Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



#### 3.9 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	$1.8~V \leq V_{DD} \leq 5.5~V$	1		24	MHz
Number of code flash rewrites Notes 1, 2, 3	Cerwr	Retained for 20 years  T <sub>A</sub> = 85°C <sup>Note 4</sup>	1,000			Times
Number of data flash rewrites		Retained for 1 year  T <sub>A</sub> = 25°C <sup>Note 4</sup>		1,000,000		
		Retained for 5 years  T <sub>A</sub> = 85°C <sup>Note 4</sup>	100,000			
		Retained for 20 years  T <sub>A</sub> = 85°C <sup>Note 4</sup>	10,000			

**Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite.

The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- 3. This characteristic indicates the flash memory characteristic and based on Renesas Electronics reliability test.
- **4.** This temperature is the average value at which data are retained.

## 3.10 Dedicated Flash Memory Programmer Communication (UART)

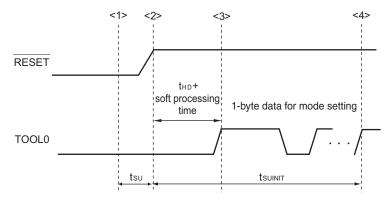
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115,200		1,000,000	bps

## 3.11 Timing Specifications for Switching Flash Memory Programming Modes

#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset must be released before the external reset is released.	10			μS
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	thd	POR and LVD reset must be released before the external reset is released.	1			ms



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.

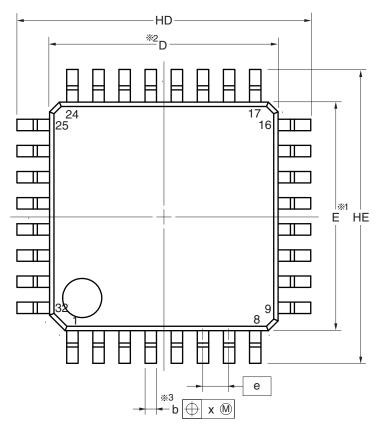
tsu: Time to release the external reset after the TOOL0 pin is set to the low level

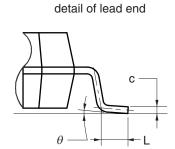
thd: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

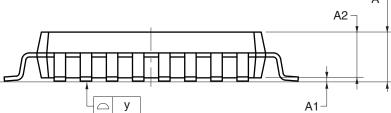
## 4. PACKAGE DRAWINGS

## 4.1 32-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP32-7x7-0.80	PLQP0032GB-A	P32GA-80-GBT-1	0.2







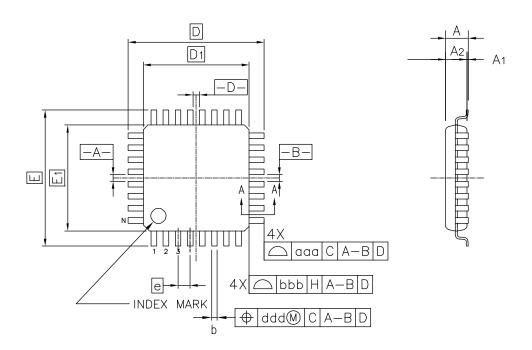
(UNIT:mm)

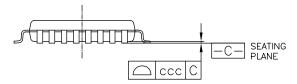
	(UNIT:mm)
ITEM	DIMENSIONS
D	7.00±0.10
Е	7.00±0.10
HD	9.00±0.20
HE	9.00±0.20
Α	1.70 MAX.
A1	0.10±0.10
A2	1.40
b	$0.37 {\pm} 0.05$
С	0.145±0.055
L	0.50±0.20
θ	0° to 8°
е	0.80
х	0.20
٧	0.10

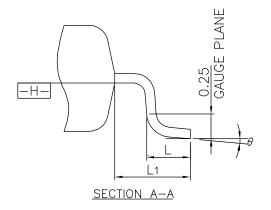
#### NOTE

- 1.Dimensions "%1" and "%2" do not include mold flash.
- 2.Dimension "%3" does not include trim offset.

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LQFP32-7x7-0.80	PLQP0032GE-A	0.18



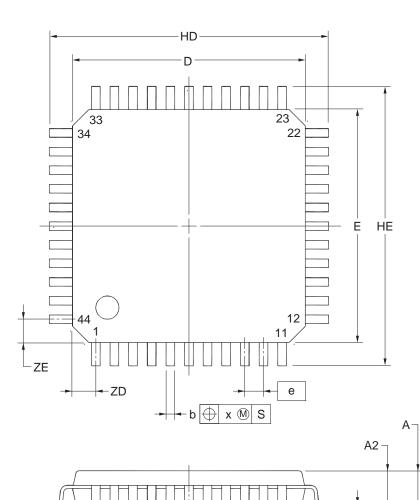




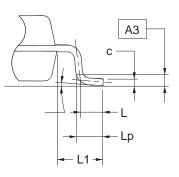
Reference	Dimensi	on in Mill	limeters
Symbol	Min.	Nom.	Max.
Α	_	_	1.60
A <sub>1</sub>	0.05	_	0.15
A <sub>2</sub>	1.35	1.40	1.45
D	_	9.00	_
D <sub>1</sub>	_	7.00	_
Е	_	9.00	_
E <sub>1</sub>	_	7.00	_
N	_	32	_
е	_	0.80	_
b	0.30	0.37	0.45
С	0.09	_	0.20
θ	0,	3.5°	7°
L	0.45	0.60	0.75
L <sub>1</sub>	_	1.00	_
aaa	_	_	0.20
bbb	_	_	0.20
ссс	_	_	0.10
ddd	_	_	0.20

## 4.2 44-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP44-10x10-0.80	PLQP0044GC-A	P44GB-80-UES-2	0.36



detail of lead end



(UNIT:mm)

ITEM	DIMENSIONS
D	10.00±0.20
Е	10.00±0.20
HD	12.00±0.20
HE	12.00±0.20
Α	1.60 MAX.
A1	0.10±0.05
A2	1.40±0.05
A3	0.25
b	$0.37^{+0.08}_{-0.07}$
С	$0.145^{+0.055}_{-0.045}$
L	0.50
Lp	0.60±0.15
L1	1.00±0.20
	3°+5°
е	0.80
Х	0.20
У	0.10
ZD	1.00

1.00

## NOTE

Each lead centerline is located within 0.20 mm of its true position at maximum material condition.

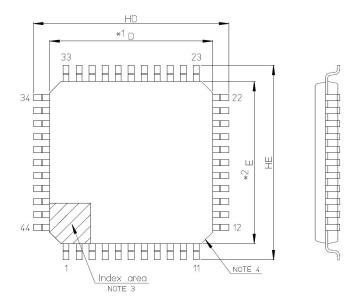
y S

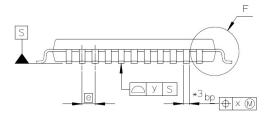
©2012 Renesas Electronics Corporation. All rights reserved.

ZE

S

JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
P-LQFP44-10×10-0.80	P-LQFP44-10×10-0.80 PLQP0044GC-D		0.36g





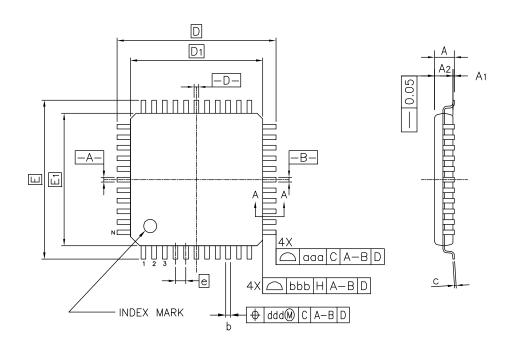


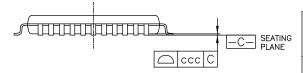
- DIMENSIONS "\*1" AND "\*2" DO NOT INCLUDE MOLD FLASH.
  DIMENSION "\*3" DOES NOT INCLUDE TRIM OFFSET.
  PIN 1 YISUAL INDEX FEATURE MAY VARY, BUT MUST BE
  LOCATED WITHIN THE HATCHED AREA.
  CHAMFERS AT CORNERS ARE OPTIONAL, SIZE MAY VARY.

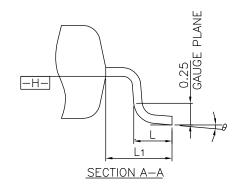
A A A A A A A A A A A A A A A A A A A		0.25
	-	Lp L1
	Detail F	

Reference	Dimension in Millimeters		
Symbol	Min	Nom	Max
D	9.8	10.0	10.2
Е	9.8	10.0	10.2
A2		1.4	
HD	11.8	12.0	12.2
HE	11.8	12.0	12.2
А	<del></del>	[ <del></del> ]	1.6
A1	0.05		0.15
bp	0.22	0.37	0.45
С	0.09		0.20
θ	0 "	3.5	8 "
0		0.80	
×		1	0.20
У		-	0.10
Lp	0.45	0.6	0.75
L1		1.0	

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LQFP044-10x10-0.80	PLQP0044GE-A	0.34



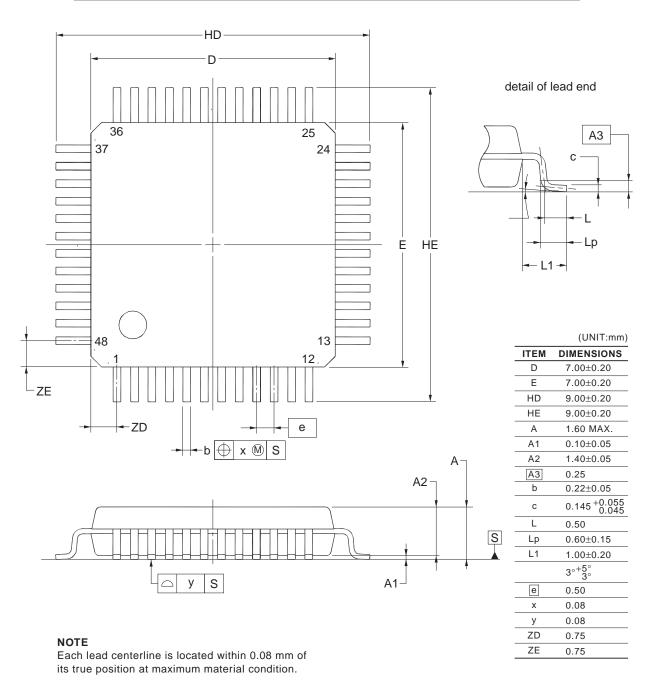




Reference	Dimension in Millimeters			
Symbol	Min.	Nom.	Max.	
А	_	_	1.60	
A <sub>1</sub>	0.05	-	0.15	
A <sub>2</sub>	1.35	1.40	1.45	
D	_	12.00	_	
D <sub>1</sub>	_	10.00	_	
E	_	12.00	_	
E <sub>1</sub>	_	10.00	_	
N	_	44	_	
е	_	0.80	_	
b	0.30	0.37	0.45	
С	0.09	_	0.20	
θ	0,	3.5°	7°	
L	0.45	0.60	0.75	
L <sub>1</sub>	_	1.00	_	
aaa	_	_	0.20	
bbb	_	_	0.20	
ССС	_	_	0.10	
ddd	_	_	0.20	

## 4.3 48-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP48-7x7-0.50	PLQP0048KF-A	P48GA-50-8EU-1	0.16



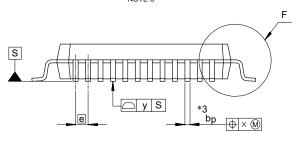
©2012 Renesas Electronics Corporation. All rights reserved.

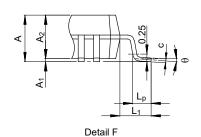
Feb 01, 2023

JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-LFQFP48-7x7-0.50	PLQP0048KB-B	_	0.2

 $H_{\mathsf{D}}$ \*1\_D 25 37 💷 **⊐** 24 Ш 뿐 ш ړې 13 48 💷 NOTE 4 NOTE) NOTE 3

Unit: mm





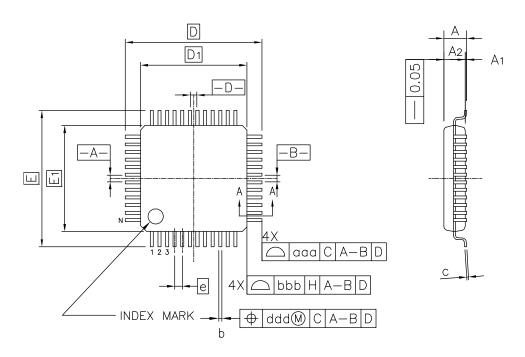
1.	DIMENSIONS "*1" AND "*2" DO NOT INCLUDE MOLD FLASH.
2	DIMENSION "*3" DOES NOT INCLUDE TRIM OFFSET

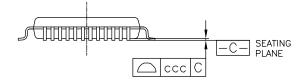
- DIMENSION "\*3" DOES NOT INCLUDE TRIM OFFSET.
   PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE LOCATED WITHIN THE HATCHED AREA.
   CHAMFERS AT CORNERS ARE OPTIONAL, SIZE MAY VARY.

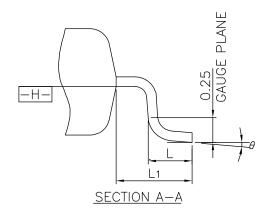
Reference Symbol	Dimensions in millimeters			
	Min	Nom	Max	
D	6.9	7.0	7.1	
Е	6.9	7.0	7.1	
$A_2$	_	1.4	_	
$H_D$	8.8	9.0	9.2	
HE	8.8	9.0	9.2	
Α	_	1	1.7	
A <sub>1</sub>	0.05		0.15	
bp	0.17	0.20	0.27	
С	0.09	l	0.20	
θ	0°	3.5°	8°	
е	_	0.5	_	
х	_	1	0.08	
у	_	1	0.08	
Lp	0.45	0.6	0.75	
L <sub>1</sub>	_	1.0		

© 2015 Renesas Electronics Corporation. All rights reserved.

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP48-7x7-0.50	PLQP0048KL-A	0.18



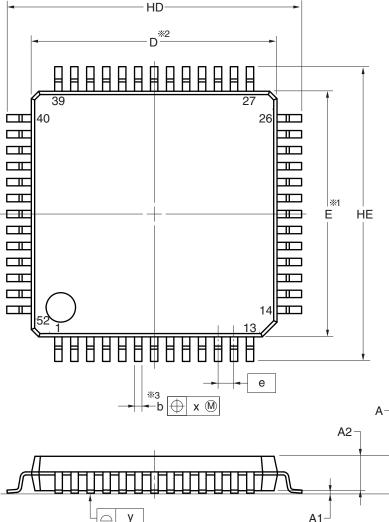




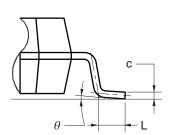
Reference	Dimension in Millimeters			
Symbol	Min.	Nom.	Max.	
А	_	_	1.60	
A <sub>1</sub>	0.05	_	0.15	
A <sub>2</sub>	1.35	1.40	1.45	
D	_	9.00	_	
D <sub>1</sub>	_	7.00	_	
E	_	9.00	_	
E <sub>1</sub>	_	7.00	_	
N	_	48	_	
е	_	0.50	_	
b	0.17	0.22	0.27	
С	0.09	_	0.20	
θ	0°	3.5°	7°	
L	0.45	0.60	0.75	
L <sub>1</sub>	-	1.00	-	
aaa	_	_	0.20	
bbb	_	_	0.20	
ccc	_	_	0.08	
ddd	_	_	0.08	

## 4.4 52-pin Package

	JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
F	P-LQFP52-10x10-0.65	PLQP0052JA-A	P52GB-65-GBS-1	0.3



detail of lead end



У A1

(UNIT:mm)

	(UNII:mm
ITEM	DIMENSIONS
D	10.00±0.10
Е	10.00±0.10
HD	12.00±0.20
HE	12.00±0.20
Α	1.70 MAX.
A1	0.10±0.05
A2	1.40
b	$0.32 {\pm} 0.05$
С	0.145±0.055
L	0.50±0.15
θ	0° to 8°
е	0.65
х	0.13
у	0.10

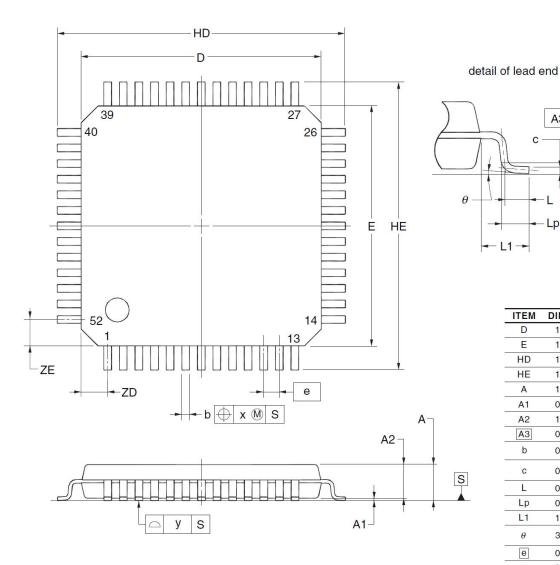
NOTE1. Dimensions "%1" and "%2" do not include mold flash.

2.Dimension "%3" does not include trim offset.

© 2012 Renesas Electronics Corporation. All rights reserved.

**A3** 

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP52-10x10-0.65	PLQP0052JD-B	P52GB-65-UET-2	0.36



(UNIT:mm)

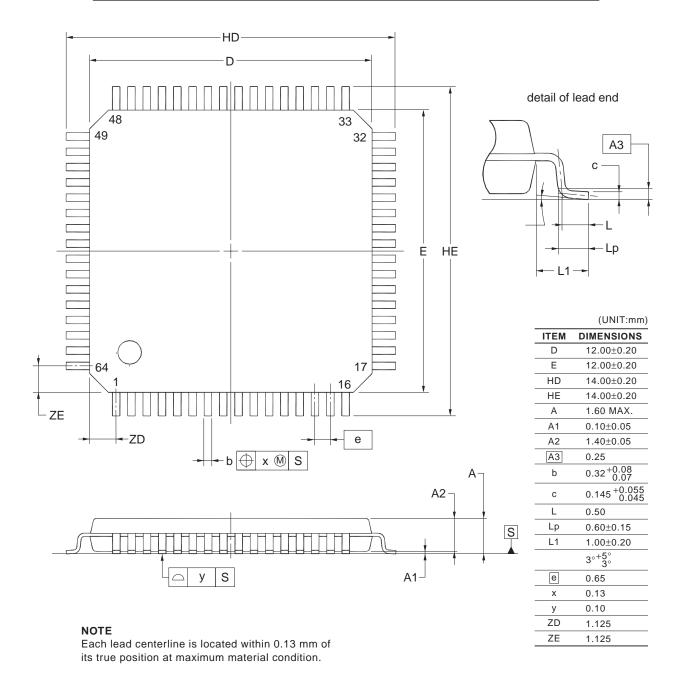
	(UNIT:IIIII)
ITEM	DIMENSIONS
D	10.00±0.20
E	10.00±0.20
HD	12.00±0.20
HE	12.00±0.20
Α	1.60 MAX.
A1	0.10±0.05
A2	1.40±0.05
<b>A</b> 3	0.25
b	$0.32^{+0.08}_{-0.07}$
С	$0.145^{+0.055}_{-0.045}$
L	0.50
Lp	0.60±0.15
L1	1.00±0.20
θ	3°+5°
е	0.65
X	0.13
у	0.10
ZD	1.10
ZE	1.10

### NOTE

Each lead centerline is located within 0.13 mm of its true position at maximum material condition.

## 4.5 64-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP64-12x12-0.65	PLQP0064JA-A	P64GK-65-UET-2	0.51

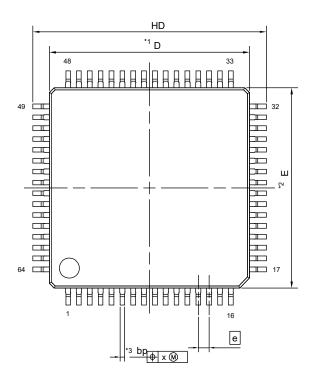


© 2012 Renesas Electronics Corporation. All rights reserved.

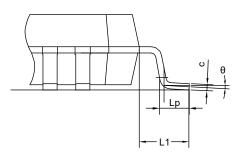
Feb 01, 2023

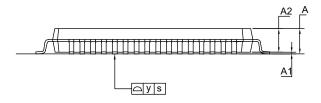
<R>

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LQFP64-12x12-0.65	PLQP0064JB-A	0.50





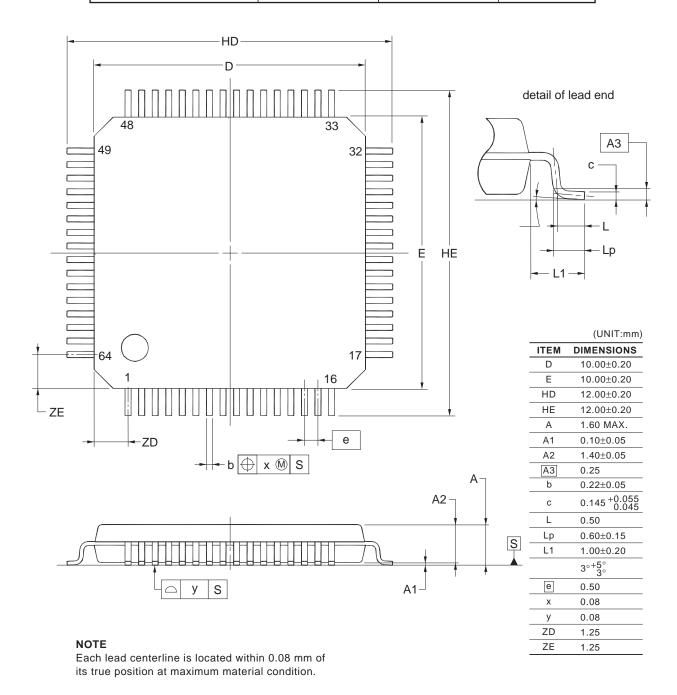




NOTE
1.DIMENSIONS "\*1" AND "\*2"DO NOT INCLUDE MOLD FLASH.
2.DIMENSION "\*3" DOES NOT INCLUDE TRIM OFFSET.

Reference	Dimen	sion in Milli	meters
Symbol	Min.	Nom.	Max.
E	11.90	12.00	12.10
D	11.90	12.00	12.10
$A_2$	-	1.40	-
$H_D$	13.80	14.00	14.20
H <sub>E</sub>	13.80	14.00	14.20
Α	_	_	1.70
$A_1$	0.05	_	0.15
Lp	0.45	0.60	0.75
L1	_	1.00	-
b <sub>p</sub>	0.27	0.32	0.37
С	0.09	_	0.20
Ф	_	0.65	-
θ	0.00	3.50	8.00
Х		_	0.08
у	_	_	0.08

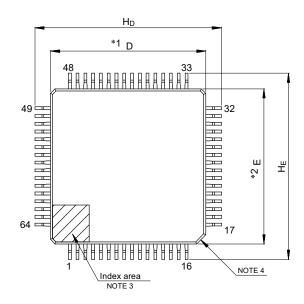
JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP64-10x10-0.50	PLQP0064KF-A	P64GB-50-UEU-2	0.35

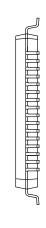


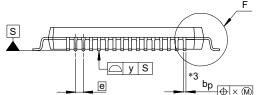
©2012 Renesas Electronics Corporation. All rights reserved.

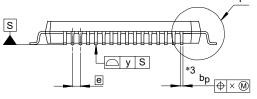
JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-LFQFP64-10x10-0.50	PLQP0064KB-C	_	0.3

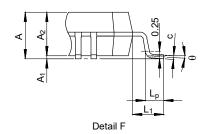
Unit: mm











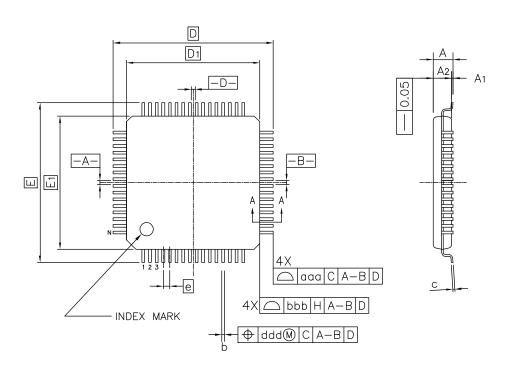
#### NOTE)

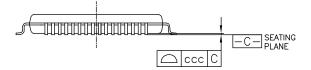
- 1. DIMENSIONS "\*1" AND "\*2" DO NOT INCLUDE MOLD FLASH.
  2. DIMENSION "\*3" DOES NOT INCLUDE TRIM OFFSET.
  3. PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE LOCATED WITHIN THE HATCHED AREA.
  4. CHAMFERS AT CORNERS ARE OPTIONAL, SIZE MAY VARY.

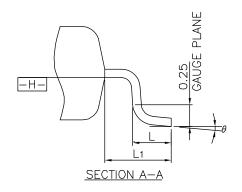
Reference	Dimens	ions in mi	llimeters
Symbol	Min	Nom	Max
D	9.9	10.0	10.1
E	9.9	10.0	10.1
$A_2$		1.4	_
$H_D$	11.8	12.0	12.2
HE	11.8	12.0	12.2
Α		-	1.7
A <sub>1</sub>	0.05		0.15
bp	0.15	0.20	0.27
С	0.09		0.20
θ	0°	3.5°	8°
е		0.5	_
х	_	I	0.08
у	_	_	0.08
Lp	0.45	0.6	0.75
L <sub>1</sub>		1.0	_

© 2015 Renesas Electronics Corporation. All rights reserved.

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP064-10x10-0.50	PLQP0064KL-A	0.36



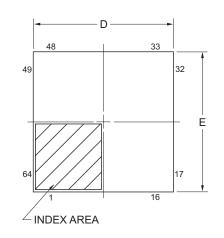




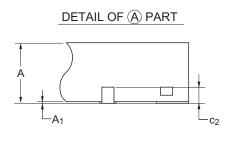
Reference	Dimension in Millimeters		
Symbol	Min.	Nom.	Max.
А	_	_	1.60
A <sub>1</sub>	0.05	_	0.15
A <sub>2</sub>	1.35	1.40	1.45
D	_	12.00	_
D <sub>1</sub>	_	10.00	_
Е	_	12.00	_
E <sub>1</sub>	_	10.00	_
N	_	64	_
е	_	0.50	_
b	0.17	0.22	0.27
С	0.09	_	0.20
θ	0,	3.5°	7°
L	0.45	0.60	0.75
L <sub>1</sub>	_	1.00	_
aaa	_	_	0.20
bbb		_	0.20
ссс	_	_	0.08
ddd	_	_	0.08

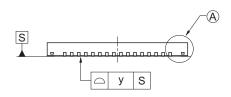
JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-HWQFN64-8x8-0.40	PWQN0064LA-A	P64K8-40-9B5-4	0.16

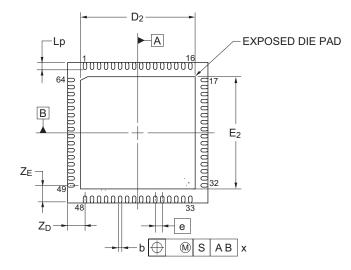
Unit: mm







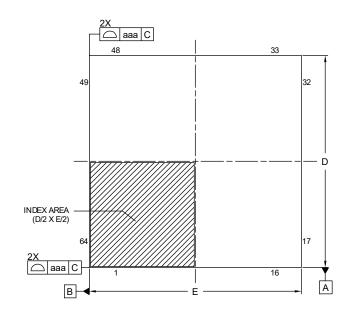


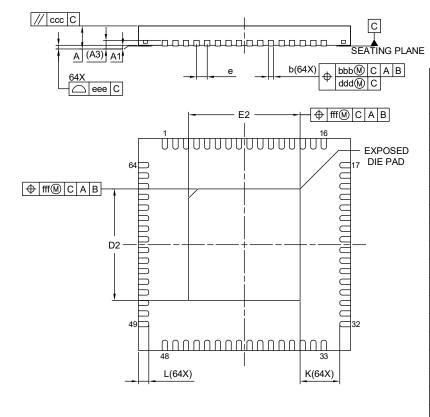


Reference	Dimensi	ons in mi	llimeters
Symbol	Min	Nom	Max
D	7.95	8.00	8.05
E	7.95	8.00	8.05
Α	_	_	0.80
A <sub>1</sub>	0.00	_	_
b	0.17	0.20	0.23
е	_	0.40	_
Lp	0.30	0.40	0.50
х	_	_	0.05
У	_	_	0.05
$Z_{D}$	_	1.00	_
ZE	_	1.00	_
C <sub>2</sub>	0.15	0.20	0.25
D <sub>2</sub>	_	6.50	_
E <sub>2</sub>		6.50	

© 2015 Renesas Electronics Corporation. All rights reserved.

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-HWQFN064-8x8-0.40	PWQN0064LB-A	0.18





Reference Symbol	Dimension in Millimeters		
	Min.	Nom.	Max.
А	_	_	0.80
<b>A</b> <sub>1</sub>	0.00	0.02	0.05
<b>A</b> <sub>3</sub>	0.203 REF.		
b	0.15	0.20	0.25
D	8.00 BSC		
E	8.00 BSC		
е	0.40 BSC		
L	0.35	0.40	0.45
K	0.20	_	_
D <sub>2</sub>	4.15	4.20	4.25
E <sub>2</sub>	4.15	4.20	4.25
aaa	0.10		
bbb	0.07		
ccc	0.10		
ddd	0.05		
eee	0.08		
fff	0.10		

# RL78/L12 Datasheet

		Description		
Rev.	Date	Page	Summary	
0.01	Feb 20, 2012	-	First Edition issued	
0.02	Sep 26, 2012	7, 8	Modification of caution 2 in 1.3.5 64-pin products	
		15	Modification of I/O port in 1.6 Outline of Functions	
		-	Modification of 2. ELECTRICAL SPECIFICATIONS (TARGET)	
		-	Update of package drawings in 3. PACKAGE DRAWINGS	
1.00	Jan 31, 2013	11 to 15	Modification of 1.5 Block Diagram	
		16	Modification of Note 2 in 1.6 Outline of Functions	
		17	Modification of 1.6 Outline of Functions	
		-	Deletion of target in 2. ELECTRICAL SPECIFICATIONS	
		18	Addition of caution 2 to 2. ELECTRICAL SPECIFICATIONS	
		19	Addition of description, note 3, and remark 2 to 2.1 Absolute Maximum Ratings	
		20	Modification of description and addition of note to 2.1 Absolute Maximum Ratings	
		22, 23	Modification of 2.2 Oscillator Characteristics	
		30	Modification of notes 1 to 4 in 2.3.2 Supply current characteristics	
		32	Modification of notes 1, 3 to 6, 8 in 2.3.2 Supply current characteristics	
		34	Modification of notes 7, 9, 11, and addition of notes 8, 12 to 2.3.2 Supply current	
			characteristics	
		36	Addition of description to 2.4 AC Characteristics	
		38, 40 to	Modification of 2.5.1 Serial array unit	
		42, 44 to		
		46, 48 to		
		52, 54, 55		
		57, 58	Modification of 2.5.2 Serial interface IICA	
		62	Modification of 2.6.2 Temperature sensor/internal reference voltage characteristics	
		64		
		64	Addition of note and caution in 2.6.5 Supply voltage rise time	
		69	Modification of 2.8 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics	
		69	Modification of conditions in 2.9 Timing Specs for Switching Flash Memory Programming Modes	
		70	Modification of 2.10 Timing Specifications for Switching Flash Memory	
			Programming Modes	
2.00	Jan 10, 2014	1	Modification of 1.1 Features	
		3	Modification of Figure 1-1	
		4	Modification of part number, note, and caution	
		5 to 10	Deletion of COMEXP pin in 1.3.1 to 1.3.5.	
		11	Modification of description in 1.4 Pin Identification	
		12 to 16	Deletion of COMEXP pin in 1.5.1 to 1.5.5	
		17	Modification of table and note 2 in 1.6 Outline of Functions	
		20 21	Modification of description in Absolute Maximum Ratings (T <sub>A</sub> = 25°C) (1/3)  Modification of description and note 2 in Absolute Maximum Ratings (T <sub>A</sub> = 25°C)	
		23	(2/3)  Modification of table, note, caution, and remark in 2.2.1 X1, XT1 oscillator characteristics	
		23	Modification of table in 2.2.2 On-chip oscillator characteristics	
		24	Modification of table in 2.2.2 On-crip oscillator characteristics  Modification of table, notes 2 and 3 in 2.3.1 Pin characteristics (1/5)	
		25	Modification of notes 1 and 3 in 2.3.1 Pin characteristics (2/5)	
		30	Modification of notes 1 and 4 in 2.3.2 Supply current characteristics (1/3)	
		31, 32	Modification of table, notes 1, 5, and 6 in 2.3.2 Supply current characteristics (2/3)	
		33, 34	Modification of table, notes 1, 3, 4, and 5 to 10 in 2.3.2 Supply current characteristics (3/3)	

		Description	
Rev.	Date	Page	Summary
2.00	Jan 10, 2014	35	Modification of table in 2.4 AC Characteristics
		36	Addition of Minimum Instruction Execution Time during Main System Clock Operation
		37	Modification of AC Timing Test Points and External System Clock Timing
		39	Modification of AC Timing Test Points
		39	Modification of description, notes 1 and 2 in (1) During communication at same potential (UART mode)
		41, 42	Modification of description, remark 2 in (2) During communication at same potential (CSI mode)
		42, 43	Modification of description in (3) During communication at same potential (CSI mode)
		45	Modification of description, notes 1 and 3, and remark 3 in (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (1/2)
		46, 48	Modification of description, and remark 3 in (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)
		49, 50	Modification of table, and note 1, caution, and remark 3 in (5) Communication at different potential (2.5 V, 3 V) (CSI mode)
		51	Modification of table and note in (6) Communication at different potential (1.8 V,
		52	2.5 V, 3 V) (1/3)  Modification of table and notes 1 to 3 in (6) Communication at different potential
			(1.8 V, 2.5 V, 3 V) (2/3)
		53, 54	Modification of table, note 3, and remark 3 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (3/3)
		56	Modification of table in (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (1/2)
		57	Modification of table in (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (2/2)
		59, 60	Addition of (1) I <sup>2</sup> C standard mode
		61	Addition of (2) I <sup>2</sup> C fast mode
		62	Addition of (3) I <sup>2</sup> C fast mode plus
		63	Addition of table in 2.6.1 A/D converter characteristics
		63, 64	Modification of description and notes 3 to 5 in 2.6.1 (1)
		65	Modification of description, notes 3 and 4 in 2.6.1 (2)
		66	Modification of description, notes 3 and 4 in 2.6.1 (3)
		67	Modification of description, notes 3 and 4 in 2.6.1 (4)
		67	Modification of the table in 2.6.2 Temperature sensor/internal reference voltage characteristics
		68	Modification of the table and note in 2.6.3 POR circuit characteristics
		70	Modification of the table of LVD Detection Voltage of Interrupt & Reset Mode
		70	Modification from VDD rise slope to Power supply voltage rising slope in 2.6.5 Supply voltage rise time
		75	Modification of description in 2.10 Dedicated Flash Memory Programmer Communication (UART)
		76	Modification of the figure in 2.11 Timing Specifications for Switching Flash Memory Programming Modes
		77 to 126	Addition of products for industrial applications (G: T <sub>A</sub> = -40 to +105°C)
		127 to 133	Addition of product names for industrial applications (G: T <sub>A</sub> = -40 to +105°C)
2.10	Sep 30, 2016	5	Modification of pin configuration in 1.3.1 32-pin products
		6	Modification of pin configuration in 1.3.2 44-pin products
		7	Modification of pin configuration in 1.3.3 48-pin products
		8	Modification of pin configuration in 1.3.4 52-pin products
		9, 10	Modification of pin configuration in 1.3.5 64-pin products
		17	Modification of description of main system clock in 1.6 Outline of Functions
		74	Modification of title of 2.8 RAM Data Retention Characteristics, Note, and figure
		74	Modification of table of 2.9 Flash Memory Programming Characteristics
		123	Modification of title of 3.8 RAM Data Retention Characteristics, Note, and figure
		123	Modification of table of 3.9 Flash Memory Programming Characteristics and addition of Note 4
		131	Modification of 4.5 64-pin Products

		Description	
Rev.	Date	Page	Summary
2.11	Feb 14, 2020	3	Addition of packaging specifications in Figure 1-1 Part Number, Memory Size, and Package of RL78/L12
		4, 5	Addition of ordering part numbers and RENESAS codes in Table 1-1 List of Ordering Part Numbers
		6 to 11	Additions of the package size and pin pitch in 1.3 Pin Configuration (Top View)
		126, 127,	Modification of the titles of the subchapters and deletion of product names in
		129,	Chapter 4
		131 to 133,	
		135	
		128	Addition of figure in 4.2 44-pin Package
		130	Addition of figure in 4.3 48-pin Package
0.40	D 00 0000	134	Addition of figure in 4.5 64-pin Package
2.12	Dec 22, 2020	3	Modification of Figure 1-1 Part Number, Memory Size, and Package of RL78/L12
		4	Modification of description in Table 1-1 List of Ordering Part Numbers
2.20	Dec 22, 2024	135	Addition of figure in 4.5 64-pin Package
2.20	Dec 22, 2021	67	Modification of description in 2.6.3 POR circuit characteristics
2.21	Sep 30, 2022	117 All	Modification of description in 3.6.3 POR circuit characteristics  The module name for CSI was changed to Simplified SPI(CSI)
2.21	Sep 30, 2022	All	"wait" for IIC was modified to "clock stretch"
		4, 5	Modification of description in Table 1-1. (1/2) to (2/2)
		127	Addition of package drawing in 4.1 32-pin Package
		130	Addition of package drawing in 4.1 42 pin Package
		133	Addition of package drawing in 4.3 48-pin Package
		135	Addition of package drawing in 4.4 52-pin Package
		137, 140	Addition of package drawing in 4.5 64-pin Package
2.21	Feb 01, 2023	5	Addition of title in Table 1-1. List of Ordering Part Numbers
	·	6	Modification of 32-pin plastic LQFP (7 × 7 mm, 0.8 mm pitch)
		6, 7	Addition of Table 1-2. Alternate function of 32-pin products
		8	Modification of 44-pin plastic LQFP (10 × 10 mm, 0.8 mm pitch)
		8 to 10	Addition of Table 1-3. Alternate function of 44-pin products
		11	Modification of 48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)
		11 to 13	Addition of Table 1-4. Alternate function of 48-pin products
		14	Modification of 52-pin plastic LQFP (10 × 10 mm, 0.65 mm pitch)
		14 to 16	Addition of Table 1-5. Alternate function of 52-pin products
		17	Modification of 64-pin plastic HWQFN (8 × 8 mm, 0.4 mm pitch)
		17	Deletion of Cautions and Remarks in 64-pin plastic HWQFN (8 × 8 mm, 0.4 mm pitch)
		18	Modification of 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch), 64-pin plastic LQFP (12 × 12 mm, 0.65 mm pitch)
		19 to 21	Addition of Table 1-6. Alternate function of 64-pin products
		22	Modification of description in 1.4 Pin Identification
		23	Modification of block diagram in 1.5.1 32-pin products
		24	Modification of block diagram in 1.5.2 44-pin products
		25	Modification of block diagram in 1.5.3 48-pin products
		26	Modification of block diagram in 1.5.4 52-pin products
		27	Modification of block diagram in 1.5.5 64-pin products
		41	Modification of Notes 1 and 4 in 2.3.2 Supply current characteristics
		42	Modification of table in 2.3.2 Supply current characteristics
		43	Modification of Notes 1 and 5 and delete Notes 6 in 2.3.2 Supply current characteristics
		71 to 73	Modification of Notes 2 in 2.5.2 Serial interface IICA
		99	Modification of Notes 1 and 4 in 3.3.2 Supply current characteristics
		100	Modification of table in 3.3.2 Supply current characteristics
		101	Modification of Notes 1 and 5 and delete Notes 6 in 3.3.2 Supply current characteristics
		147	Replacement of package drawing in 4.5 64-pin Package
		147	Theplacement of package drawling in 4.3 04-pin Fackage

The mark "<R>" shows major revised points. The revised points can be easily searched by copying an "<R>" in the PDF file and specifying it in the "Find what:" field.

All trademarks and registered trademarks are the property of their respective owners.

SuperFlash is a registered trademark of Silicon Storage Technology, Inc. in several countries including the United States and Japan.

Caution: This product uses SuperFlash® technology licensed from Silicon Storage Technology, Inc.

# General Precautions in the Handling of Microprocessing Unit and Microcontroller Unit Products

The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

- 1. Precaution against Electrostatic Discharge (ESD)
  - A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.
- 2. Processing at power-on
  - The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power reaches the level at which resetting is specified.
- 3. Input of signal during power-off state
  - Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.
- 4. Handling of unused pins
  - Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.
- 5. Clock signals
  - After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.
- 6. Voltage application waveform at input pin
  - Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between  $V_{IL}$  (Max.) and  $V_{IH}$  (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between  $V_{IL}$  (Max.) and  $V_{IH}$  (Min.).
- 7. Prohibition of access to reserved addresses
  - Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.
- 8. Differences between products
  - Before changing from one product to another, for example to a product with a different part number, confirm that the change will not lead to problems. The characteristics of a microprocessing unit or microcontroller unit products in the same group but having a different part number might differ in terms of internal memory capacity, layout pattern, and other factors, which can affect the ranges of electrical characteristics, such as characteristic values, operating margins, immunity to noise, and amount of radiated noise. When changing to a product with a different part number, implement a system-evaluation test for the given product.

### **Notice**

- 1. Descriptions of circuits, software and other related information in this document are provided only to illustrate the operation of semiconductor products and application examples. You are fully responsible for the incorporation or any other use of the circuits, software, and information in the design of your product or system. Renesas Electronics disclaims any and all liability for any losses and damages incurred by you or third parties arising from the use of these circuits, software, or information.
- Renesas Electronics hereby expressly disclaims any warranties against and liability for infringement or any other claims involving patents, copyrights, or other intellectual property rights of third parties, by or arising from the use of Renesas Electronics products or technical information described in this document, including but not limited to, the product data, drawings, charts, programs, algorithms, and application examples.
- No license, express, implied or otherwise, is granted hereby under any patents, copyrights or other intellectual property rights of Renesas Electronics or others.
- 4. You shall be responsible for determining what licenses are required from any third parties, and obtaining such licenses for the lawful import, export, manufacture, sales, utilization, distribution or other disposal of any products incorporating Renesas Electronics products, if required.
- 5. You shall not alter, modify, copy, or reverse engineer any Renesas Electronics product, whether in whole or in part. Renesas Electronics disclaims any and all liability for any losses or damages incurred by you or third parties arising from such alteration, modification, copying or reverse engineering.
- 6. Renesas Electronics products are classified according to the following two quality grades: "Standard" and "High Quality". The intended applications for each Renesas Electronics product depends on the product's quality grade, as indicated below.
  - "Standard": Computers; office equipment; communications equipment; test and measurement equipment; audio and visual equipment; home electronic appliances; machine tools; personal electronic equipment; industrial robots; etc.
  - "High Quality": Transportation equipment (automobiles, trains, ships, etc.); traffic control (traffic lights); large-scale communication equipment; key financial terminal systems; safety control equipment; etc.

Unless expressly designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not intended or authorized for use in products or systems that may pose a direct threat to human life or bodily injury (artificial life support devices or systems; surgical implantations; etc.), or may cause serious property damage (space system; undersea repeaters; nuclear power control systems; aircraft control systems; key plant systems; military equipment; etc.). Renesas Electronics disclaims any and all liability for any damages or losses incurred by you or any third parties arising from the use of any Renesas Electronics product that is inconsistent with any Renesas Electronics data sheet, user's manual or other Renesas Electronics document.

- 7. No semiconductor product is absolutely secure. Notwithstanding any security measures or features that may be implemented in Renesas Electronics hardware or software products, Renesas Electronics shall have absolutely no liability arising out of any vulnerability or security breach, including but not limited to any unauthorized access to or use of a Renesas Electronics product or a system that uses a Renesas Electronics product. RENESAS ELECTRONICS DOES NOT WARRANT OR GUARANTEE THAT RENESAS ELECTRONICS PRODUCTS, OR ANY SYSTEMS CREATED USING RENESAS ELECTRONICS PRODUCTS WILL BE INVULNERABLE OR FREE FROM CORRUPTION, ATTACK, VIRUSES, INTERFERENCE, HACKING, DATA LOSS OR THEFT, OR OTHER SECURITY INTRUSION ("Vulnerability Issues"). RENESAS ELECTRONICS DISCLAIMS ANY AND ALL RESPONSIBILITY OR LIABILITY ARISING FROM OR RELATED TO ANY VULNERABILITY ISSUES. FURTHERMORE, TO THE EXTENT PERMITTED BY APPLICABLE LAW, RENESAS ELECTRONICS DISCLAIMS ANY AND ALL WARRANTIES, EXPRESS OR IMPLIED, WITH RESPECT TO THIS DOCUMENT AND ANY RELATED OR ACCOMPANYING SOFTWARE OR HARDWARE, INCLUDING BUT NOT LIMITED TO THE IMPLIED WARRANTIES OF MERCHANTABILITY, OR FITNESS FOR A PARTICULAR PURPOSE.
- 8. When using Renesas Electronics products, refer to the latest product information (data sheets, user's manuals, application notes, "General Notes for Handling and Using Semiconductor Devices" in the reliability handbook, etc.), and ensure that usage conditions are within the ranges specified by Renesas Electronics with respect to maximum ratings, operating power supply voltage range, heat dissipation characteristics, installation, etc. Renesas Electronics disclaims any and all liability for any malfunctions, failure or accident arising out of the use of Renesas Electronics products outside of such specified ranges.
- 9. Although Renesas Electronics endeavors to improve the quality and reliability of Renesas Electronics products, semiconductor products have specific characteristics, such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Unless designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not subject to radiation resistance design. You are responsible for implementing safety measures to guard against the possibility of bodily injury, injury or damage caused by fire, and/or danger to the public in the event of a failure or malfunction of Renesas Electronics products, such as safety design for hardware and software, including but not limited to redundancy, fire control and malfunction prevention, appropriate treatment for aging degradation or any other appropriate measures. Because the evaluation of microcomputer software alone is very difficult and impractical, you are responsible for evaluating the safety of the final products or systems manufactured by you.
- 10. Please contact a Renesas Electronics sales office for details as to environmental matters such as the environmental compatibility of each Renesas Electronics product. You are responsible for carefully and sufficiently investigating applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive, and using Renesas Electronics products in compliance with all these applicable laws and regulations. Renesas Electronics disclaims any and all liability for damages or losses occurring as a result of your noncompliance with applicable laws and regulations.
- 11. Renesas Electronics products and technologies shall not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable domestic or foreign laws or regulations. You shall comply with any applicable export control laws and regulations promulgated and administered by the governments of any countries asserting jurisdiction over the parties or transactions.
- 12. It is the responsibility of the buyer or distributor of Renesas Electronics products, or any other party who distributes, disposes of, or otherwise sells or transfers the product to a third party, to notify such third party in advance of the contents and conditions set forth in this document.
- 13. This document shall not be reprinted, reproduced or duplicated in any form, in whole or in part, without prior written consent of Renesas Electronics.
- 14. Please contact a Renesas Electronics sales office if you have any questions regarding the information contained in this document or Renesas Electronics products.
- (Note1) "Renesas Electronics" as used in this document means Renesas Electronics Corporation and also includes its directly or indirectly controlled subsidiaries.
- (Note2) "Renesas Electronics product(s)" means any product developed or manufactured by or for Renesas Electronics.

(Rev.5.0-1 October 2020)

### **Corporate Headquarters**

TOYOSU FORESIA, 3-2-24 Toyosu, Koto-ku, Tokyo 135-0061, Japan www.renesas.com

## **Trademarks**

Renesas and the Renesas logo are trademarks of Renesas Electronics Corporation. All trademarks and registered trademarks are the property of their respective owners.

### **Contact Information**

For further information on a product, technology, the most up-to-date version of a document, or your nearest sales office, please visit: <a href="https://www.renesas.com/contact/">www.renesas.com/contact/</a>